

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRI-g encoded:
				5 *
				6 * E659 VSRP - VECTOR SHIFT AND ROUND DECIMAL
				7 * E65B VPSOP - VECTOR PERFORM SIGN OPERATION DECIMAL
				8 *
				9 * James Wekel June 2024
				10 *****
				11
				12 *****
				13 *
				14 * basic instruction tests
				15 *
				16 *****
				17 * This program tests proper functioning of the z/arch E6 VRI-g vector
				18 * shift and round decimal, and perform sign operation decimal
				19 * instructions. Exceptions are not tested.
				20 *
				21 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				22 * obvious coding errors. None of the tests are thorough. They are
				23 * NOT designed to test all aspects of any of the instructions.
				24 *
				25 *****
				26 *
				27 * *Testcase zvector-e6-16-VSRP-VPSOP: VECTOR E6 VRI-g instructions
				28 * *
				29 * * Zvector E6 tests for VRI-g encoded instruction:
				30 * *
				31 * * E659 VSRP - VECTOR SHIFT AND ROUND DECIMAL
				32 * * E65B VPSOP - VECTOR PERFORM SIGN OPERATION DECIMAL
				33 * *
				34 * * # -----
				35 * * # This tests only the basic function of the instruction.
				36 * * # Exceptions are NOT tested.
				37 * * # -----
				38 * *
				39 * main size 2
				40 * numcpu 1
				41 * sysclear
				42 * archlvl z/Arch
				43 *
				44 * diag8cmd enable # (needed for messages to Hercules console)
				45 * loadcore "\$(testpath)/zvector-e6-16-VSRP-VPSOP.core" 0x0
				46 * diag8cmd disable # (reset back to default)
				47 *
				48 * *Done
				49 *
				50 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				52 *****
				53 * FCHECK Macro - Is a Facility Bit set?
				54 *
				55 * If the facility bit is NOT set, an message is issued and
				56 * the test is skipped.
				57 *
				58 * Fcheck uses R0, R1 and R2
				59 *
				60 * eg. FCHECK 134, 'vector-packed-decimal'
				61 *****
				62 MACRO
				63 FCHECK &BITNO, &NOTSETMSG
				64 . * &BITNO : facility bit number to check
				65 . * &NOTSETMSG : 'facility name'
				66 LCLA &FBBYTE Facility bit in Byte
				67 LCLA &FBBIT Facility bit within Byte
				68
				69 LCLA &L(8)
				70 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				71
				72 &FBBYTE SETA &BITNO/8
				73 &FBBIT SETA &L((&BITNO- (&FBBYTE*8))+1)
				74 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				75
				76 B X&SYSNDX
				77 * Fcheck data area
				78 * skip messgae
				79 SKT&SYSNDX DC C' Skipping tests: '
				80 DC C&NOTSETMSG
				81 DC C' facility (bit &BITNO) is not installed.'
				82 SKL&SYSNDX EQU *- SKT&SYSNDX
				83 * facility bits
				84 DS FD gap
				85 FB&SYSNDX DS 4FD
				86 DS FD gap
				87 *
				88 X&SYSNDX EQU *
				89 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				90 STFLE FB&SYSNDX get facility bits
				91
				92 XGR R0, R0
				93 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				94 N R0, =F' &FBBIT' is bit set?
				95 BNZ XC&SYSNDX
				96 *
				97 * facility bit not set, issue message and exit
				98 *
				99 LA R0, SKL&SYSNDX message length
				100 LA R1, SKT&SYSNDX message address
				101 BAL R2, MSG
				102
				103 B E0J
				104 XC&SYSNDX EQU *
				105 MEND

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						237	*****
						238	* cc was not as expected
						239	*****
00000328	E310	0001	0082	00000328	00000001	240	CCMSG EQU *
0000032E	E310	5009	0076		00000001	241	XG R1, R1
00000334	5410	838C			00000009	242	LB R1, M5 M5 has CS bit
00000338	4780	810C			0000058C	243	N R1, =F' 1' get CS (CC set) bit
					0000030C	244	BZ TESTREST ignore if not set
						245	*
						246	* extract CC extracted PSW
						247	*
0000033C	5810	8EF4			000010F4	248	L R1, CCPSW
00000340	8810	000C			0000000C	249	SRL R1, 12
00000344	5410	8390			00000590	250	N R1, =XL4' 3'
00000348	4210	8EFC			000010FC	251	STC R1, CCFOUND save cc
						252	*
						253	* FILL IN MESSAGE
						254	*
0000034C	4820	5004			00000004	255	LH R2, TNUM get test number and convert
00000350	4E20	8EE2			000010E2	256	CVD R2, DECNUM
00000354	D211	8ECC	8EB6	000010CC	000010B6	257	MVC PRT3, EDIT
0000035A	DE11	8ECC	8EE2	000010CC	000010E2	258	ED PRT3, DECNUM
00000360	D202	8E71	8ED9	00001071	000010D9	259	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						260	
00000366	D207	8E8E	5010	0000108E	00000010	261	MVC CCPRTNAME, OPNAME fill in message with instruction
						262	
0000036C	B982	0022				263	XGR R2, R2 get CC as U8
00000370	4320	500A			0000000A	264	IC R2, CC
00000374	4E20	8EE2			000010E2	265	CVD R2, DECNUM and convert
00000378	D211	8ECC	8EB6	000010CC	000010B6	266	MVC PRT3, EDIT
0000037E	DE11	8ECC	8EE2	000010CC	000010E2	267	ED PRT3, DECNUM
00000384	D200	8EA4	8EDB	000010A4	000010DB	268	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						269	
0000038A	B982	0022				270	XGR R2, R2 get CCFOUND as U8
0000038E	4320	8EFC			000010FC	271	IC R2, CCFOUND
00000392	4E20	8EE2			000010E2	272	CVD R2, DECNUM and convert
00000396	D211	8ECC	8EB6	000010CC	000010B6	273	MVC PRT3, EDIT
0000039C	DE11	8ECC	8EE2	000010CC	000010E2	274	ED PRT3, DECNUM
000003A2	D200	8EB4	8EDB	000010B4	000010DB	275	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						276	
000003A8	4100	0055			00000055	277	LA R0, CCPRTLNG message length
000003AC	4110	8E61			00001061	278	LA R1, CCPRTLNE messagfe address
000003B0	45F0	825C			0000045C	279	BAL R15, RPTERROR
						280	
000003B4	47F0	823E			0000043E	281	B FAILCONT

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						283	*****
						284	* result not as expected:
						285	* issue message with test number, instruction under test
						286	* and instruction m3
						287	*****
				000003B8	00000001	288	FAILMSG EQU *
000003B8	4820	5004			00000004	289	LH R2, TNUM get test number and convert
000003BC	4E20	8EE2			000010E2	290	CVD R2, DECNUM
000003C0	D211	8ECC	8EB6	000010CC	000010B6	291	MVC PRT3, EDIT
000003C6	DE11	8ECC	8EE2	000010CC	000010E2	292	ED PRT3, DECNUM
000003CC	D202	8E18	8ED9	00001018	000010D9	293	MVC PRTNUM(3), PRT3+13 fill in message with test #
						294	
000003D2	D207	8E33	5010	00001033	00000010	295	MVC PRTNAME, OPNAME fill in message with instruction
						296	
000003D8	B982	0022				297	XGR R2, R2 get i3 as U8
000003DC	4320	5007			00000007	298	IC R2, I3
000003E0	4E20	8EE2			000010E2	299	CVD R2, DECNUM and convert
000003E4	D211	8ECC	8EB6	000010CC	000010B6	300	MVC PRT3, EDIT
000003EA	DE11	8ECC	8EE2	000010CC	000010E2	301	ED PRT3, DECNUM
000003F0	D202	8E44	8ED9	00001044	000010D9	302	MVC PRTI3(3), PRT3+13 fill in message with i3 field
						303	
000003F6	B982	0022				304	XGR R2, R2 get i4 as U8
000003FA	4320	5008			00000008	305	IC R2, I4
000003FE	4E20	8EE2			000010E2	306	CVD R2, DECNUM and convert
00000402	D211	8ECC	8EB6	000010CC	000010B6	307	MVC PRT3, EDIT
00000408	DE11	8ECC	8EE2	000010CC	000010E2	308	ED PRT3, DECNUM
0000040E	D202	8E51	8ED9	00001051	000010D9	309	MVC PRTI4(3), PRT3+13 fill in message with i4 field
						310	
00000414	B982	0022				311	XGR R2, R2 get m5 as U8
00000418	4320	5009			00000009	312	IC R2, M5 and convert
0000041C	4E20	8EE2			000010E2	313	CVD R2, DECNUM
00000420	D211	8ECC	8EB6	000010CC	000010B6	314	MVC PRT3, EDIT
00000426	DE11	8ECC	8EE2	000010CC	000010E2	315	ED PRT3, DECNUM
0000042C	D201	8E5E	8EDA	0000105E	000010DA	316	MVC PRTM5(2), PRT3+14 fill in message with m5 field
						317	
00000432	4100	0059			00000059	318	LA R0, PRTLNG message length
00000436	4110	8E08			00001008	319	LA R1, PRTLINE messagfe address
0000043A	45F0	825C			0000045C	320	BAL R15, RPTERROR
						322	*****
						323	* continue after a failed test
						324	*****
				0000043E	00000001	325	FAILCONT EQU *
0000043E	5800	838C			0000058C	326	L R0, =F' 1' set GLOBAL failed test indicator
00000442	5000	8E00			00001000	327	ST R0, FAILED
						328	
00000446	41C0	C004			00000004	329	LA R12, 4(0, R12) next test address
0000044A	47F0	80DC			000002DC	330	B NEXTE6
						332	*****
						333	* end of testing; set ending psw
						334	*****
				0000044E	00000001	335	ENDTEST EQU *
0000044E	5810	8E00			00001000	336	L R1, FAILED did a test fail?

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				442 *=====
				443 *
				444 * NOTE: start data on an address that is easy to display
				445 * within Hercules
				446 *
				447 *=====
00000598		00000598	00001000	448
00001000	00000000			449 ORG ZVE6TST+X' 1000'
00001004	00000000			450 FAILED DC F' 0' some test failed?
				451 TESTING DC F' 0' current test number
				453 *****
				454 * TEST failed : result messgae
				455 *****
				456 *
				457 * failed message and associated editting
				458 *
00001008	40404040	40404040		459 PRTLIN DC C' Test # '
00001018	A7A7A7			460 PRTNUM DC C' xxx'
0000101B	40868189	93858440		461 DC C' failed for instruction '
00001033	A7A7A7A7	A7A7A7A7		462 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3	884089F3		463 DC C' with i3=
00001044	A7A7A7			464 PRTI3 DC C' xxx'
00001047	6B			465 DC C' ,'
00001048	40A689A3	884089F4		466 DC C' with i4=
00001051	A7A7A7			467 PRTI4 DC C' xxx'
00001054	6B			468 DC C' ,'
00001055	40A689A3	884094F5		469 DC C' with m5=
0000105E	A7A7			470 PRTM5 DC C' xx'
00001060	4B			471 DC C' .'
		00000059	00000001	472 PRTLNG EQU *- PRTLIN
				474 *****
				475 * TEST failed : CC message
				476 *****
				477 *
				478 * failed message and associated editting
				479 *
00001061	40404040	40404040		480 CCPRTLIN DC C' Test # '
00001071	A7A7A7			481 CCPRTNUM DC C' xxx'
00001074	40A69996	95874083		482 DC c' wrong cc for instruction '
0000108E	A7A7A7A7	A7A7A7A7		483 CCPRTNAME DC CL8' xxxxxxxx'
00001096	4085A797	8583A385		484 DC C' expected: cc=
000010A4	A7			485 CCPRTEXP DC C' x'
000010A5	6B			486 DC C' ,'
000010A6	40998583	8589A585		487 DC C' received: cc=
000010B4	A7			488 CCPRTGOT DC C' x'
000010B5	4B			489 DC C' .'
		00000055	00000001	490 CCPRTLNG EQU *- CCPRTLIN

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				545 *****	
				546 * Macros to help build test tables	
				547 *-----	
				548 * VRI_G Macro to help build test tables	
				549 *****	
				550 MACRO	
				551 VRI_G &INST, &I3, &I4, &M5, &CC	
				552 . *	&INST - VRI-g instruction under test
				553 . *	&i3 - i3 field
				554 . *	&i4 - i4 field
				555 . *	&m5 - m5 field
				556 . *	&CC - expected CC
				557 . *	
				558 LCLA &XCC(4) &CC has mask values for FAILED condition codes	
				559 &XCC(1) SETA 7 CC != 0	
				560 &XCC(2) SETA 11 CC != 1	
				561 &XCC(3) SETA 13 CC != 2	
				562 &XCC(4) SETA 14 CC != 3	
				563 . *	
				564 GBLA &TNUM	
				565 &TNUM SETA &TNUM+1	
				566	
				567 DS OFD	
				568 USING *, R5	base for test data and test routine
				569	
				570 T&TNUM DC A(X&TNUM)	address of test routine
				571 DC H' &TNUM	test number
				572 DC X' 00'	
				573 DC HL1' &I3'	i3
				574 DC HL1' &I4'	i4
				575 DC HL1' &M5'	m5
				576 DC HL1' &CC'	cc
				577 DC HL1' &XCC(&CC+1)'	cc failed mask
				578 V2_&TNUM DC A(RE&TNUM+16)	address of v2: 16-byte packed decimal
				579 DC CL8' &INST'	instruction name
				580 DC A(16)	result length
				581 REA&TNUM DC A(RE&TNUM)	result address
				582 . *	
				583 *	INSTRUCTION UNDER TEST ROUTINE
				584	
				585 X&TNUM DS OF	
				586 LGF R2, V2_&TNUM	get v2
				587 VL V2, 0(R2)	
				588	
				589 &INST V1, V2, &I3, &I4, &M5	test instruction
				590	
				591 VST V1, V10OUTPUT	save result
				592 EPSW R2, R0	extract psw
				593 ST R2, CCPSW	to save CC
				594 BR R11	return
				595	
				596 RE&TNUM DC OF	
				597 DROP R5	
				598	
				599 MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
-----	-------------	-------	-------	------

601 *****

```
602 * PTTABLE Macro to generate table of pointers to individual tests
```

603 *****8*****1*****

604

605 MACRO

606 PTTABLE

607 **GBLA** **&TNUM**

608 LCLA & CUR

609 &CUR SETA 1

610 . *

611 TTABLE DS OF

612 . LOOP ANOP

613 . *

614	DC	A(T&CUR)	address of test
-----	----	----------	-----------------

615 . *

616 &CUR SETA &CUR+1

```
617      AIF      (&CUR LE &TNUM). LOOP
```

618 *

619	DC	A(0)	END OF TABLE
-----	----	------	--------------

620 DC A(0)

621 . *

622 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				624 *****
				625 * E6 VRI_G tests
				626 *****
				627
00001170		00000000	00003A6F	628 ZVE6TST CSECT ,
				629 DS 0F
				631 PRINT DATA
				632 *
				633 * E659 VSRP - VECTOR SHIFT AND ROUND DECIMAL
				634 * E65B VPSOP - VECTOR PERFORM SIGN OPERATION DECIMAL
				635 *
				636 * VRI_G instr,i3,i4,m5,cc
				637 * followed by
				638 * v1 - 16 byte expected result
				639 * v2 - 16 byte zoned decimal (operand)
				640
				641 * -----
				642 * VSRP - VECTOR SHIFT AND ROUND DECIMAL REGISTER
				643 * -----
				644 * VSRP with some I3, I4 and M5's
				645 * I3 tests
				646 * i4=129 (iom=1, rdc=1)
				647 * i4=132 (iom=1, rdc=4)
				648 * i4=135 (iom=1, rdc=7)
				649 * i4=142 (iom=1, rdc=14)
				650 * i4=159 (iom=1, rdc=31)
				651 * I4
				652 * i4= 0 (drd=0, shamt=0) shi ft left
				653 * i4= 1 (drd=0, shamt=1) shi ft left
				654 * i4= 4 (drd=0, shamt=4) shi ft left
				655 * i4= 7 (drd=0, shamt=7) shi ft left
				656 * i4= 14 (drd=0, shamt=14) shi ft left
				657 * i4= 30 (drd=0, shamt=30) shi ft left
				658 * i4= 31 (drd=0, shamt=31) shi ft left
				659
				660 * i4=96 (drd=0, shamt=- 32) shi ft right
				661 * i4=114 (drd=0, shamt=- 14) shi ft right
				662 * i4=121 (drd=0, shamt=- 7) shi ft right
				663 * i4=124 (drd=0, shamt=- 4) shi ft right
				664 * i4=127 (drd=0, shamt=- 1) shi ft right
				665
				666 * i4=129 (drd=1, shamt=1) shi ft left
				667 * i4=132 (drd=1, shamt=4) shi ft left
				668 * i4=135 (drd=1, shamt=7) shi ft left
				669 * i4=142 (drd=1, shamt=14) shi ft left
				670 * i4=159 (drd=1, shamt=31) shi ft left
				671
				672 * i4=224 (drd=1, shamt=- 32) shi ft right
				673 * i4=225 (drd=1, shamt=- 31) shi ft right
				674 * i4=242 (drd=1, shamt=- 14) shi ft right
				675 * i4=249 (drd=1, shamt=- 7) shi ft right
				676 * i4=252 (drd=1, shamt=- 4) shi ft right
				677 * i4=255 (drd=1, shamt=- 1) shi ft right
				678

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				679 *		
				680 *	m5 tests (note: cs is always 1)	
				681 *	m5=1 (p2=0, p1=0, cs=1)	
				682 *	m5=3 (p2=0, p1=1, cs=1)	
				683 *	m5=9 (p2=1, p1=0, cs=1)	
				684 *	m5=11 (p2=1, p1=1, cs=1)	
				685		
				686	VRI_G VSRP, 159, 0, 1, 2	shamt=0
00001170				687+	DS	OFD
00001170		00001170		688+	USING	*, R5
00001170	00001190			689+T1	DC	A(X1)
00001174	0001			690+	DC	H' 1'
00001176	00			691+	DC	X' 00'
00001177	9F			692+	DC	HL1' 159'
00001178	00			693+	DC	HL1' 0'
00001179	01			694+	DC	HL1' 1'
0000117A	02			695+	DC	HL1' 2'
0000117B	0D			696+	DC	HL1' 13'
0000117C	000011C4			697+V2_1	DC	A(RE1+16)
00001180	E5E2D9D7 40404040			698+	DC	CL8' VSRP'
00001188	00000010			699+	DC	A(16)
0000118C	000011B4			700+REA1	DC	A(RE1)
				701+*		INSTRUCTION UNDER TEST ROUTINE
00001190				702+X1	DS	OF
00001190	E320 500C 0014		0000117C	703+	LGF	R2, V2_1
00001196	E722 0000 0006		00000000	704+	VL	V2, 0(R2)
0000119C	E612 0019 F059			705+	VSRP	V1, V2, 159, 0, 1
000011A2	E710 8F10 000E		00001110	706+	VST	V1, V10UTPUT
000011A8	B98D 0020			707+	EPSW	R2, R0
000011AC	5020 8EF4		000010F4	708+	ST	R2, CCPSW
000011B0	07FB			709+	BR	R11
000011B4				710+RE1	DC	OF
000011B4				711+	DROP	R5
000011B4	00000000 00000000			712	DC	XL16' 0000000000000000000000000000022C' V1
000011BC	00000000 0000022C					
000011C4	00000000 00000000			713	DC	XL16' 0000000000000000000000000000022C' V2
000011CC	00000000 0000022C					
				714		
				715	VRI_G VSRP, 159, 1, 1, 2	shamt=1 (left)
000011D8				716+	DS	OFD
000011D8		000011D8		717+	USING	*, R5
000011D8	000011F8			718+T2	DC	A(X2)
000011DC	0002			719+	DC	H' 2'
000011DE	00			720+	DC	X' 00'
000011DF	9F			721+	DC	HL1' 159'
000011E0	01			722+	DC	HL1' 1'
000011E1	01			723+	DC	HL1' 1'
000011E2	02			724+	DC	HL1' 2'
000011E3	0D			725+	DC	HL1' 13'
000011E4	0000122C			726+V2_2	DC	A(RE2+16)
000011E8	E5E2D9D7 40404040			727+	DC	CL8' VSRP'
000011F0	00000010			728+	DC	A(16)
000011F4	0000121C			729+REA2	DC	A(RE2)
				730+*		INSTRUCTION UNDER TEST ROUTINE
000011F8				731+X2	DS	OF
000011F8	E320 500C 0014		000011E4	732+	LGF	R2, V2_2

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000011FE	E722 0000 0006		00000000	733+	VL	V2, 0(R2)	
00001204	E612 0119 F059			734+	VSRP	V1, V2, 159, 1, 1	test instruction
0000120A	E710 8F10 000E		00001110	735+	VST	V1, V10OUTPUT	save result
00001210	B98D 0020			736+	EPSW	R2, R0	exptract psw
00001214	5020 8EF4		000010F4	737+	ST	R2, CCPSW	to save CC
00001218	07FB			738+	BR	R11	return
0000121C				739+RE2	DC	0F	
0000121C				740+	DROP	R5	
0000121C	00000000 00000000			741	DC	XL16' 0000000000000000000000000000220C'	V1
00001224	00000000 0000220C						
0000122C	00000000 00000000			742	DC	XL16' 000000000000000000000000000022C'	V2
00001234	00000000 0000022C						
				743			
				744	VRI_G	VSRP, 159, 7, 1, 2	shamt=7 (left)
00001240				745+	DS	0FD	
00001240		00001240		746+	USING	*, R5	base for test data and test routine
00001240	00001260			747+T3	DC	A(X3)	address of test routine
00001244	0003			748+	DC	H' 3'	test number
00001246	00			749+	DC	X' 00'	
00001247	9F			750+	DC	HL1' 159'	i3
00001248	07			751+	DC	HL1' 7'	i4
00001249	01			752+	DC	HL1' 1'	m5
0000124A	02			753+	DC	HL1' 2'	cc
0000124B	0D			754+	DC	HL1' 13'	cc failed mask
0000124C	00001294			755+V2_3	DC	A(RE3+16)	address of v2: 16-byte packed decimal
00001250	E5E2D9D7 40404040			756+	DC	CL8' VSRP'	instruction name
00001258	00000010			757+	DC	A(16)	result length
0000125C	00001284			758+REA3	DC	A(RE3)	result address
				759+*			INSTRUCTION UNDER TEST ROUTINE
00001260				760+X3	DS	0F	
00001260	E320 500C 0014		0000124C	761+	LGF	R2, V2_3	get v2
00001266	E722 0000 0006		00000000	762+	VL	V2, 0(R2)	
0000126C	E612 0719 F059			763+	VSRP	V1, V2, 159, 7, 1	test instruction
00001272	E710 8F10 000E		00001110	764+	VST	V1, V10OUTPUT	save result
00001278	B98D 0020			765+	EPSW	R2, R0	exptract psw
0000127C	5020 8EF4		000010F4	766+	ST	R2, CCPSW	to save CC
00001280	07FB			767+	BR	R11	return
00001284				768+RE3	DC	0F	
00001284				769+	DROP	R5	
00001284	00000000 00000000			770	DC	XL16' 000000000000000000000000220000000C'	V1
0000128C	00000022 0000000C						
00001294	00000000 00000000			771	DC	XL16' 000000000000000000000000000022C'	V2
0000129C	00000000 0000022C						
				772			
				773	VRI_G	VSRP, 159, 30, 1, 3	shamt=30 (left) (overflow)
000012A8				774+	DS	0FD	
000012A8		000012A8		775+	USING	*, R5	base for test data and test routine
000012A8	000012C8			776+T4	DC	A(X4)	address of test routine
000012AC	0004			777+	DC	H' 4'	test number
000012AE	00			778+	DC	X' 00'	
000012AF	9F			779+	DC	HL1' 159'	i3
000012B0	1E			780+	DC	HL1' 30'	i4
000012B1	01			781+	DC	HL1' 1'	m5
000012B2	03			782+	DC	HL1' 3'	cc
000012B3	0E			783+	DC	HL1' 14'	cc failed mask
000012B4	000012FC			784+V2_4	DC	A(RE4+16)	address of v2: 16-byte packed decimal

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000012B8	E5E2D9D7 40404040			785+	DC	CL8' VSRP'	instruction name
000012C0	00000010			786+	DC	A(16)	result length
000012C4	000012EC			787+REA4	DC	A(RE4)	result address
				788+*			INSTRUCTION UNDER TEST ROUTINE
000012C8				789+X4	DS	0F	
000012C8	E320 500C 0014		000012B4	790+	LGF	R2, V2_4	get v2
000012CE	E722 0000 0006		00000000	791+	VL	V2, 0(R2)	
000012D4	E612 1E19 F059			792+	VSRP	V1, V2, 159, 30, 1	test instruction
000012DA	E710 8F10 000E		00001110	793+	VST	V1, V10UTPUT	save result
000012E0	B98D 0020			794+	EPSW	R2, R0	exptract psw
000012E4	5020 8EF4		000010F4	795+	ST	R2, CCPSW	to save CC
000012E8	07FB			796+	BR	R11	return
000012EC				797+RE4	DC	0F	
000012EC				798+	DROP	R5	
000012EC	20000000 00000000			799	DC	XL16' 20000000000000000000000000000000C'	V1
000012F4	00000000 0000000C						
000012FC	00000000 00000000			800	DC	XL16' 0000000000000000000000000000000022C'	V2
00001304	00000000 0000022C						
				801			
				802	VRI_G	VSRP, 159, 31, 1, 3	shamt=31 (left) (overflow)
00001310				803+	DS	0FD	
00001310		00001310		804+	USING	*, R5	base for test data and test routine
00001310	00001330			805+T5	DC	A(X5)	address of test routine
00001314	0005			806+	DC	H' 5'	test number
00001316	00			807+	DC	X' 00'	
00001317	9F			808+	DC	HL1' 159'	i3
00001318	1F			809+	DC	HL1' 31'	i4
00001319	01			810+	DC	HL1' 1'	m5
0000131A	03			811+	DC	HL1' 3'	cc
0000131B	0E			812+	DC	HL1' 14'	cc failed mask
0000131C	00001364			813+V2_5	DC	A(RE5+16)	address of v2: 16-byte packed decimal
00001320	E5E2D9D7 40404040			814+	DC	CL8' VSRP'	instruction name
00001328	00000010			815+	DC	A(16)	result length
0000132C	00001354			816+REA5	DC	A(RE5)	result address
				817+*			INSTRUCTION UNDER TEST ROUTINE
00001330				818+X5	DS	0F	
00001330	E320 500C 0014		0000131C	819+	LGF	R2, V2_5	get v2
00001336	E722 0000 0006		00000000	820+	VL	V2, 0(R2)	
0000133C	E612 1F19 F059			821+	VSRP	V1, V2, 159, 31, 1	test instruction
00001342	E710 8F10 000E		00001110	822+	VST	V1, V10UTPUT	save result
00001348	B98D 0020			823+	EPSW	R2, R0	exptract psw
0000134C	5020 8EF4		000010F4	824+	ST	R2, CCPSW	to save CC
00001350	07FB			825+	BR	R11	return
00001354				826+RE5	DC	0F	
00001354				827+	DROP	R5	
00001354	00000000 00000000			828	DC	XL16' 00000000000000000000000000000000C'	V1
0000135C	00000000 0000000C						
00001364	00000000 00000000			829	DC	XL16' 0000000000000000000000000000000022D'	V2
0000136C	00000000 0000022D						
				830			
				831	VRI_G	VSRP, 159, 127, 1, 2	shamt=-1 (right)
00001378				832+	DS	0FD	
00001378		00001378		833+	USING	*, R5	base for test data and test routine
00001378	00001398			834+T6	DC	A(X6)	address of test routine
0000137C	0006			835+	DC	H' 6'	test number
0000137E	00			836+	DC	X' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000137F	9F			837+	DC	HL1' 159'	i3
00001380	7F			838+	DC	HL1' 127'	i4
00001381	01			839+	DC	HL1' 1'	m5
00001382	02			840+	DC	HL1' 2'	cc
00001383	0D			841+	DC	HL1' 13'	cc failed mask
00001384	000013CC			842+V2_6	DC	A(RE6+16)	address of v2: 16-byte packed decimal
00001388	E5E2D9D7 40404040			843+	DC	CL8' VSRP'	instruction name
00001390	00000010			844+	DC	A(16)	result length
00001394	000013BC			845+REA6	DC	A(RE6)	result address
				846+*			INSTRUCTION UNDER TEST ROUTINE
00001398				847+X6	DS	0F	
00001398	E320 500C 0014		00001384	848+	LGF	R2, V2_6	get v2
0000139E	E722 0000 0006		00000000	849+	VL	V2, 0(R2)	
000013A4	E612 7F19 F059			850+	VSRP	V1, V2, 159, 127, 1	test instruction
000013AA	E710 8F10 000E		00001110	851+	VST	V1, V10UTPUT	save result
000013B0	B98D 0020			852+	EPSW	R2, R0	exptract psw
000013B4	5020 8EF4		000010F4	853+	ST	R2, CCPSW	to save CC
000013B8	07FB			854+	BR	R11	return
000013BC				855+RE6	DC	0F	
000013BC				856+	DROP	R5	
000013BC	00000000 00000000			857	DC	XL16' 0000000000000000000000000000000002C'	V1
000013C4	00000000 0000002C						
000013CC	00000000 00000000			858	DC	XL16' 0000000000000000000000000000000002C'	V2
000013D4	00000000 0000022C						
				859			
				860	VRI_G	VSRP, 159, 255, 1, 2	shamt=-1 (right) drd=1
000013E0				861+	DS	0FD	
000013E0		000013E0		862+	USING	*, R5	base for test data and test routine
000013E0	00001400			863+T7	DC	A(X7)	address of test routine
000013E4	0007			864+	DC	H' 7'	test number
000013E6	00			865+	DC	X' 00'	
000013E7	9F			866+	DC	HL1' 159'	i3
000013E8	FF			867+	DC	HL1' 255'	i4
000013E9	01			868+	DC	HL1' 1'	m5
000013EA	02			869+	DC	HL1' 2'	cc
000013EB	0D			870+	DC	HL1' 13'	cc failed mask
000013EC	00001434			871+V2_7	DC	A(RE7+16)	address of v2: 16-byte packed decimal
000013F0	E5E2D9D7 40404040			872+	DC	CL8' VSRP'	instruction name
000013F8	00000010			873+	DC	A(16)	result length
000013FC	00001424			874+REA7	DC	A(RE7)	result address
				875+*			INSTRUCTION UNDER TEST ROUTINE
00001400				876+X7	DS	0F	
00001400	E320 500C 0014		000013EC	877+	LGF	R2, V2_7	get v2
00001406	E722 0000 0006		00000000	878+	VL	V2, 0(R2)	
0000140C	E612 FF19 F059			879+	VSRP	V1, V2, 159, 255, 1	test instruction
00001412	E710 8F10 000E		00001110	880+	VST	V1, V10UTPUT	save result
00001418	B98D 0020			881+	EPSW	R2, R0	exptract psw
0000141C	5020 8EF4		000010F4	882+	ST	R2, CCPSW	to save CC
00001420	07FB			883+	BR	R11	return
00001424				884+RE7	DC	0F	
00001424				885+	DROP	R5	
00001424	00000000 00000000			886	DC	XL16' 0000000000000000000000000000000003C'	V1
0000142C	00000000 0000003C						
00001434	00000000 00000000			887	DC	XL16' 00000000000000000000000000000000028C'	V2
0000143C	00000000 0000028C						
				888			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				889	VRI_G VSRP, 159, 252, 1, 1	shamt=- 4 (right) drd=1
00001448				890+	DS OFD	
00001448		00001448		891+	USING *, R5	base for test data and test routine
00001448	00001468			892+T8	DC A(X8)	address of test routine
0000144C	0008			893+	DC H' 8'	test number
0000144E	00			894+	DC X' 00'	
0000144F	9F			895+	DC HL1' 159'	i3
00001450	FC			896+	DC HL1' 252'	i4
00001451	01			897+	DC HL1' 1'	m5
00001452	01			898+	DC HL1' 1'	cc
00001453	0B			899+	DC HL1' 11'	cc failed mask
00001454	0000149C			900+V2_8	DC A(RE8+16)	address of v2: 16-byte packed decimal
00001458	E5E2D9D7 40404040			901+	DC CL8' VSRP'	instruction name
00001460	00000010			902+	DC A(16)	result length
00001464	0000148C			903+REA8	DC A(RE8)	result address
				904+*		INSTRUCTION UNDER TEST ROUTINE
00001468				905+X8	DS OF	
00001468	E320 500C 0014		00001454	906+	LGF R2, V2_8	get v2
0000146E	E722 0000 0006		00000000	907+	VL V2, 0(R2)	
00001474	E612 FC19 F059			908+	VSRP V1, V2, 159, 252, 1	test instruction
0000147A	E710 8F10 000E		00001110	909+	VST V1, V10UTPUT	save result
00001480	B98D 0020			910+	EPSW R2, R0	exptract psw
00001484	5020 8EF4		000010F4	911+	ST R2, CCPSW	to save CC
00001488	07FB			912+	BR R11	return
0000148C				913+RE8	DC OF	
0000148C				914+	DROP R5	
0000148C	00000000 00000000			915	DC XL16' 000000000000000000000000000000002D'	V1
00001494	00000000 0000002D					
0000149C	00000000 00000000			916	DC XL16' 0000000000000000000000000000000015028D'	V2
000014A4	00000000 0015028D					
				917		
				918	VRI_G VSRP, 159, 249, 1, 0	shamt=- 7 (right) drd=1
000014B0				919+	DS OFD	
000014B0		000014B0		920+	USING *, R5	base for test data and test routine
000014B0	000014D0			921+T9	DC A(X9)	address of test routine
000014B4	0009			922+	DC H' 9'	test number
000014B6	00			923+	DC X' 00'	
000014B7	9F			924+	DC HL1' 159'	i3
000014B8	F9			925+	DC HL1' 249'	i4
000014B9	01			926+	DC HL1' 1'	m5
000014BA	00			927+	DC HL1' 0'	cc
000014BB	07			928+	DC HL1' 7'	cc failed mask
000014BC	00001504			929+V2_9	DC A(RE9+16)	address of v2: 16-byte packed decimal
000014C0	E5E2D9D7 40404040			930+	DC CL8' VSRP'	instruction name
000014C8	00000010			931+	DC A(16)	result length
000014CC	000014F4			932+REA9	DC A(RE9)	result address
				933+*		INSTRUCTION UNDER TEST ROUTINE
000014D0				934+X9	DS OF	
000014D0	E320 500C 0014		000014BC	935+	LGF R2, V2_9	get v2
000014D6	E722 0000 0006		00000000	936+	VL V2, 0(R2)	
000014DC	E612 F919 F059			937+	VSRP V1, V2, 159, 249, 1	test instruction
000014E2	E710 8F10 000E		00001110	938+	VST V1, V10UTPUT	save result
000014E8	B98D 0020			939+	EPSW R2, R0	exptract psw
000014EC	5020 8EF4		000010F4	940+	ST R2, CCPSW	to save CC
000014F0	07FB			941+	BR R11	return
000014F4				942+RE9	DC OF	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000014F4				943+	DROP	R5	
000014F4	00000000 00000000			944	DC	XL16' 00000000000000000000000000000000C'	V1 (note: C)
000014FC	00000000 0000000C						
00001504	00000000 00000000			945	DC	XL16' 0000000000000000000000000000028D'	V2
0000150C	00000000 0000028D						
				946			
				947	VRI_G	VSRP, 159, 225, 1, 1	shamt=- 31 (right) drd=1
00001518				948+	DS	OFD	
00001518		00001518		949+	USING	*, R5	base for test data and test routine
00001518	00001538			950+T10	DC	A(X10)	address of test routine
0000151C	000A			951+	DC	H' 10'	test number
0000151E	00			952+	DC	X' 00'	
0000151F	9F			953+	DC	HL1' 159'	i3
00001520	E1			954+	DC	HL1' 225'	i4
00001521	01			955+	DC	HL1' 1'	m5
00001522	01			956+	DC	HL1' 1'	cc
00001523	0B			957+	DC	HL1' 11'	cc failed mask
00001524	0000156C			958+V2_10	DC	A(RE10+16)	address of v2: 16-byte packed decimal
00001528	E5E2D9D7 40404040			959+	DC	CL8' VSRP'	instruction name
00001530	00000010			960+	DC	A(16)	result length
00001534	0000155C			961+REA10	DC	A(RE10)	result address
				962+*			INSTRUCTION UNDER TEST ROUTINE
00001538				963+X10	DS	OF	
00001538	E320 500C 0014		00001524	964+	LGF	R2, V2_10	get v2
0000153E	E722 0000 0006		00000000	965+	VL	V2, 0(R2)	
00001544	E612 E119 F059			966+	VSRP	V1, V2, 159, 225, 1	test instruction
0000154A	E710 8F10 000E		00001110	967+	VST	V1, V10UTPUT	save result
00001550	B98D 0020			968+	EPSW	R2, R0	exptract psw
00001554	5020 8EF4		000010F4	969+	ST	R2, CCPSW	to save CC
00001558	07FB			970+	BR	R11	return
0000155C				971+RE10	DC	OF	
0000155C				972+	DROP	R5	
0000155C	00000000 00000000			973	DC	XL16' 0000000000000000000000000000001D'	V1 (note: C)
00001564	00000000 0000001D						
0000156C	99990000 00000000			974	DC	XL16' 9999000000000000000000000000028D'	V2
00001574	00000000 0000028D						
				975			
				976	VRI_G	VSRP, 159, 224, 1, 0	shamt=- 32 (right) drd=1
00001580				977+	DS	OFD	
00001580		00001580		978+	USING	*, R5	base for test data and test routine
00001580	000015A0			979+T11	DC	A(X11)	address of test routine
00001584	000B			980+	DC	H' 11'	test number
00001586	00			981+	DC	X' 00'	
00001587	9F			982+	DC	HL1' 159'	i3
00001588	E0			983+	DC	HL1' 224'	i4
00001589	01			984+	DC	HL1' 1'	m5
0000158A	00			985+	DC	HL1' 0'	cc
0000158B	07			986+	DC	HL1' 7'	cc failed mask
0000158C	000015D4			987+V2_11	DC	A(RE11+16)	address of v2: 16-byte packed decimal
00001590	E5E2D9D7 40404040			988+	DC	CL8' VSRP'	instruction name
00001598	00000010			989+	DC	A(16)	result length
0000159C	000015C4			990+REA11	DC	A(RE11)	result address
				991+*			INSTRUCTION UNDER TEST ROUTINE
000015A0				992+X11	DS	OF	
000015A0	E320 500C 0014		0000158C	993+	LGF	R2, V2_11	get v2
000015A6	E722 0000 0006		00000000	994+	VL	V2, 0(R2)	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000015AC	E612 E019 F059			995+	VSRP	V1, V2, 159, 224, 1	test instruction
000015B2	E710 8F10 000E		00001110	996+	VST	V1, V10UTPUT	save result
000015B8	B98D 0020			997+	EPSW	R2, R0	exptract psw
000015BC	5020 8EF4		000010F4	998+	ST	R2, CCPSW	to save CC
000015C0	07FB			999+	BR	R11	return
000015C4				1000+RE11	DC	0F	
000015C4				1001+	DROP	R5	
000015C4	00000000 00000000			1002	DC	XL16' 00000000000000000000000000000000C'	V1 (note: C)
000015CC	00000000 0000000C						
000015D4	90000000 00000000			1003	DC	XL16' 9000000000000000000000000000000028D'	V2
000015DC	00000000 0000028D						
				1004			
				1005 *	m5 tests (note: cs is always 1)		
				1006 *		m5=1 (p2=0, p1=0, cs=1)	
				1007 *		m5=3 (p2=0, p1=1, cs=1)	
				1008 *		m5=9 (p2=1, p1=0, cs=1)	
				1009 *		m5=11 (p2=1, p1=1, cs=1)	
				1010			
000015E8				1011	VRI_G	VSRP, 159, 255, 3, 2	shamt=-1 (right) drd=1 p1=1
000015E8		000015E8		1012+	DS	0FD	
000015E8	00001608			1013+	USING	*, R5	base for test data and test routine
000015EC	000C			1014+T12	DC	A(X12)	address of test routine
000015EE	00			1015+	DC	H' 12'	test number
000015EF	9F			1016+	DC	X' 00'	
000015F0	FF			1017+	DC	HL1' 159'	i3
000015F1	03			1018+	DC	HL1' 255'	i4
000015F2	02			1019+	DC	HL1' 3'	m5
000015F3	0D			1020+	DC	HL1' 2'	cc
000015F3	0D			1021+	DC	HL1' 13'	cc failed mask
000015F4	0000163C			1022+V2_12	DC	A(RE12+16)	address of v2: 16-byte packed decimal
000015F8	E5E2D9D7 40404040			1023+	DC	CL8' VSRP'	instruction name
00001600	00000010			1024+	DC	A(16)	result length
00001604	0000162C			1025+REA12	DC	A(RE12)	result address
				1026+*			INSTRUCTION UNDER TEST ROUTINE
00001608				1027+X12	DS	0F	
00001608	E320 500C 0014		000015F4	1028+	LGF	R2, V2_12	get v2
0000160E	E722 0000 0006		00000000	1029+	VL	V2, 0(R2)	
00001614	E612 FF39 F059			1030+	VSRP	V1, V2, 159, 255, 3	test instruction
0000161A	E710 8F10 000E		00001110	1031+	VST	V1, V10UTPUT	save result
00001620	B98D 0020			1032+	EPSW	R2, R0	exptract psw
00001624	5020 8EF4		000010F4	1033+	ST	R2, CCPSW	to save CC
00001628	07FB			1034+	BR	R11	return
0000162C				1035+RE12	DC	0F	
0000162C				1036+	DROP	R5	
0000162C	00000000 00000000			1037	DC	XL16' 000000000000000000000000000000003F'	V1
00001634	00000000 0000003F						
0000163C	00000000 00000000			1038	DC	XL16' 0000000000000000000000000000000028D'	V2
00001644	00000000 0000028D						
				1039			
00001650				1040	VRI_G	VSRP, 159, 255, 9, 2	shamt=-1 (right) drd=1 p2=1 p1=0
00001650		00001650		1041+	DS	0FD	
00001650	00001670			1042+	USING	*, R5	base for test data and test routine
00001654	000D			1043+T13	DC	A(X13)	address of test routine
00001656	00			1044+	DC	H' 13'	test number
00001657	9F			1045+	DC	X' 00'	
				1046+	DC	HL1' 159'	i3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000017CC	00000000 00000000			1153	DC	XL16' 0000000000000000000000000000220C'	V1
000017D4	00000000 0000220C						
000017DC	00000000 00000000			1154	DC	XL16' 000000000000000000000000000022D'	V2
000017E4	00000000 0000022D						
				1155			
				1156	VRI_G	VSRP, 159, 7, 11, 2	shamt=7 (left) p2=1 p1=1
000017F0				1157+	DS	OFD	
000017F0		000017F0		1158+	USING	*, R5	base for test data and test routine
000017F0	00001810			1159+T17	DC	A(X17)	address of test routine
000017F4	0011			1160+	DC	H' 17'	test number
000017F6	00			1161+	DC	X' 00'	
000017F7	9F			1162+	DC	HL1' 159'	i3
000017F8	07			1163+	DC	HL1' 7'	i4
000017F9	0B			1164+	DC	HL1' 11'	m5
000017FA	02			1165+	DC	HL1' 2'	cc
000017FB	0D			1166+	DC	HL1' 13'	cc failed mask
000017FC	00001844			1167+V2_17	DC	A(RE17+16)	address of v2: 16-byte packed decimal
00001800	E5E2D9D7 40404040			1168+	DC	CL8' VSRP'	instruction name
00001808	00000010			1169+	DC	A(16)	result length
0000180C	00001834			1170+REA17	DC	A(RE17)	result address
				1171+*			INSTRUCTION UNDER TEST ROUTINE
00001810				1172+X17	DS	OF	
00001810	E320 500C 0014		000017FC	1173+	LGF	R2, V2_17	get v2
00001816	E722 0000 0006		00000000	1174+	VL	V2, 0(R2)	
0000181C	E612 07B9 F059			1175+	VSRP	V1, V2, 159, 7, 11	test instruction
00001822	E710 8F10 000E		00001110	1176+	VST	V1, V10UTPUT	save result
00001828	B98D 0020			1177+	EPSW	R2, R0	exptract psw
0000182C	5020 8EF4		000010F4	1178+	ST	R2, CCPSW	to save CC
00001830	07FB			1179+	BR	R11	return
00001834				1180+RE17	DC	OF	
00001834				1181+	DROP	R5	
00001834	00000000 00000000			1182	DC	XL16' 000000000000000000000000220000000F'	V1
0000183C	00000022 0000000F						
00001844	00000000 00000000			1183	DC	XL16' 000000000000000000000000000022D'	V2
0000184C	00000000 0000022D						
				1184			
				1185	*	-----	
				1186	*	VPSOP - VECTOR PERFORM SIGN OPERATION DECIMAL	
				1187	*	-----	
				1188	*	VPSOP with some I3, I4 and M5's	
				1189	*	I3 tests	
				1190	*	i4=129 (iom=1, rdc=1)	
				1191	*	i4=132 (iom=1, rdc=4)	
				1192	*	i4=135 (iom=1, rdc=7)	
				1193	*	i4=142 (iom=1, rdc=14)	
				1194	*	i4=159 (iom=1, rdc=31)	
				1195	*	I4 : so=00	
				1196	*	i4=128 (nv=1, nz=0, //, so=00, pc=0, sv=0)	
				1197	*	i4=130 (nv=1, nz=0, //, so=00, pc=1, sv=0)	
				1198	*		
				1199	*	i4=192 (nv=1, nz=1, //, so=00, pc=0, sv=0)	
				1200	*	i4=194 (nv=1, nz=1, //, so=00, pc=1, sv=0)	
				1201			
				1202	*	I4 : so=01	
				1203	*	i4=132 (nv=1, nz=0, //, so=01, pc=0, sv=0)	
				1204	*	i4=134 (nv=1, nz=0, //, so=01, pc=1, sv=0)	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000189C	00000000 00000000			1261	DC	XL16' 000000000000000000000000220000000C'	V1	
000018A4	00000022 0000000C							
000018AC	00000000 00000000			1262	DC	XL16' 000000000000000000000000220000000F'	V2	
000018B4	00000022 0000000F							
				1263				
000018C0				1264	VRI_G	VPSOP, 159, 192, 1, 2	nz=1	
000018C0		000018C0		1265+	DS	OFD		
000018C0	000018E0			1266+	USING	*, R5	base for test data and test routine	
000018C4	0013			1267+T19	DC	A(X19)	address of test routine	
000018C6	00			1268+	DC	H' 19'	test number	
000018C7	9F			1269+	DC	X' 00'		
000018C8	C0			1270+	DC	HL1' 159'	i3	
000018C9	01			1271+	DC	HL1' 192'	i4	
000018CA	02			1272+	DC	HL1' 1'	m5	
000018CB	0D			1273+	DC	HL1' 2'	cc	
000018CB	0D			1274+	DC	HL1' 13'	cc failed mask	
000018CC	00001914			1275+V2_19	DC	A(RE19+16)	address of v2: 16-byte packed decimal	
000018D0	E5D7E2D6 D7404040			1276+	DC	CL8' VPSOP'	instruction name	
000018D8	00000010			1277+	DC	A(16)	result length	
000018DC	00001904			1278+REA19	DC	A(RE19)	result address	
				1279+*			INSTRUCTION UNDER TEST ROUTINE	
000018E0				1280+X19	DS	OF		
000018E0	E320 500C 0014		000018CC	1281+	LGF	R2, V2_19	get v2	
000018E6	E722 0000 0006		00000000	1282+	VL	V2, 0(R2)		
000018EC	E612 C019 F05B			1283+	VPSOP	V1, V2, 159, 192, 1	test instruction	
000018F2	E710 8F10 000E		00001110	1284+	VST	V1, V10UTPUT	save result	
000018F8	B98D 0020			1285+	EPSW	R2, R0	exptract psw	
000018FC	5020 8EF4		000010F4	1286+	ST	R2, CCPSW	to save CC	
00001900	07FB			1287+	BR	R11	return	
00001904				1288+RE19	DC	OF		
00001904				1289+	DROP	R5		
00001904	00000000 00000000			1290	DC	XL16' 000000000000000000000000220000000C'	V1	
0000190C	00000022 0000000C							
00001914	00000000 00000000			1291	DC	XL16' 000000000000000000000000220000000F'	V2	
0000191C	00000022 0000000F							
				1292				
				1293	*	V1: nonzero V2: positive PC=' 1' NZ=' â€‘'	V1_sign=F CC=2	
				1294	VRI_G	VPSOP, 159, 130, 1, 2	nz=0	
00001928				1295+	DS	OFD		
00001928		00001928		1296+	USING	*, R5	base for test data and test routine	
00001928	00001948			1297+T20	DC	A(X20)	address of test routine	
0000192C	0014			1298+	DC	H' 20'	test number	
0000192E	00			1299+	DC	X' 00'		
0000192F	9F			1300+	DC	HL1' 159'	i3	
00001930	82			1301+	DC	HL1' 130'	i4	
00001931	01			1302+	DC	HL1' 1'	m5	
00001932	02			1303+	DC	HL1' 2'	cc	
00001933	0D			1304+	DC	HL1' 13'	cc failed mask	
00001934	0000197C			1305+V2_20	DC	A(RE20+16)	address of v2: 16-byte packed decimal	
00001938	E5D7E2D6 D7404040			1306+	DC	CL8' VPSOP'	instruction name	
00001940	00000010			1307+	DC	A(16)	result length	
00001944	0000196C			1308+REA20	DC	A(RE20)	result address	
				1309+*			INSTRUCTION UNDER TEST ROUTINE	
00001948				1310+X20	DS	OF		
00001948	E320 500C 0014		00001934	1311+	LGF	R2, V2_20	get v2	
0000194E	E722 0000 0006		00000000	1312+	VL	V2, 0(R2)		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001954	E612 8219 F05B			1313+	VPSOP	V1, V2, 159, 130, 1	test instruction	
0000195A	E710 8F10 000E		00001110	1314+	VST	V1, V10UTPUT	save result	
00001960	B98D 0020			1315+	EPSW	R2, R0	exptract psw	
00001964	5020 8EF4		000010F4	1316+	ST	R2, CCPSW	to save CC	
00001968	07FB			1317+	BR	R11	return	
0000196C				1318+RE20	DC	0F		
0000196C				1319+	DROP	R5		
0000196C	00000000 00000000			1320	DC	XL16' 000000000000000000000000220000000F'	V1	
00001974	00000022 0000000F							
0000197C	00000000 00000000			1321	DC	XL16' 000000000000000000000000220000000A'	V2	
00001984	00000022 0000000A							
00001990				1322				
00001990		00001990		1323	VRI_G	VPSOP, 159, 194, 1, 2	nz=1	
00001990	000019B0			1324+	DS	0FD		
00001994	0015			1325+	USING	*, R5	base for test data and test routine	
00001996	00			1326+T21	DC	A(X21)	address of test routine	
00001997	9F			1327+	DC	H' 21'	test number	
00001998	C2			1328+	DC	X' 00'		
00001999	01			1329+	DC	HL1' 159'	i3	
0000199A	02			1330+	DC	HL1' 194'	i4	
0000199B	0D			1331+	DC	HL1' 1'	m5	
0000199C	000019E4			1332+	DC	HL1' 2'	cc	
000019A0	E5D7E2D6 D7404040			1333+	DC	HL1' 13'	cc failed mask	
000019A8	00000010			1334+V2_21	DC	A(RE21+16)	address of v2: 16-byte packed decimal	
000019AC	000019D4			1335+	DC	CL8' VPSOP'	instruction name	
				1336+	DC	A(16)	result length	
				1337+REA21	DC	A(RE21)	result address	
				1338+*			INSTRUCTION UNDER TEST ROUTINE	
000019B0				1339+X21	DS	0F		
000019B0	E320 500C 0014		0000199C	1340+	LGF	R2, V2_21	get v2	
000019B6	E722 0000 0006		00000000	1341+	VL	V2, 0(R2)		
000019BC	E612 C219 F05B			1342+	VPSOP	V1, V2, 159, 194, 1	test instruction	
000019C2	E710 8F10 000E		00001110	1343+	VST	V1, V10UTPUT	save result	
000019C8	B98D 0020			1344+	EPSW	R2, R0	exptract psw	
000019CC	5020 8EF4		000010F4	1345+	ST	R2, CCPSW	to save CC	
000019D0	07FB			1346+	BR	R11	return	
000019D4				1347+RE21	DC	0F		
000019D4				1348+	DROP	R5		
000019D4	00000000 00000000			1349	DC	XL16' 000000000000000000000000220000000F'	V1	
000019DC	00000022 0000000F							
000019E4	00000000 00000000			1350	DC	XL16' 000000000000000000000000220000000A'	V2	
000019EC	00000022 0000000A							
				1351				
				1352 * V1: nonzero V2: negative PC=' - ' NZ=' â€‘' V1_sign=D CC=1				
				1353	VRI_G	VPSOP, 159, 128, 1, 1	nz=0 pc=0	
000019F8		000019F8		1354+	DS	0FD		
000019F8	00001A18			1355+	USING	*, R5	base for test data and test routine	
000019FC	0016			1356+T22	DC	A(X22)	address of test routine	
000019FE	00			1357+	DC	H' 22'	test number	
000019FF	9F			1358+	DC	X' 00'		
00001A00	80			1359+	DC	HL1' 159'	i3	
00001A01	01			1360+	DC	HL1' 128'	i4	
00001A02	01			1361+	DC	HL1' 1'	m5	
00001A03	0B			1362+	DC	HL1' 1'	cc	
00001A04	00001A4C			1363+	DC	HL1' 11'	cc failed mask	
				1364+V2_22	DC	A(RE22+16)	address of v2: 16-byte packed decimal	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A08	E5D7E2D6 D7404040			1365+	DC	CL8' VPSOP'	instruction name
00001A10	00000010			1366+	DC	A(16)	result length
00001A14	00001A3C			1367+REA22	DC	A(RE22)	result address
				1368+*			INSTRUCTION UNDER TEST ROUTINE
00001A18				1369+X22	DS	0F	
00001A18	E320 500C 0014		00001A04	1370+	LGF	R2, V2_22	get v2
00001A1E	E722 0000 0006		00000000	1371+	VL	V2, 0(R2)	
00001A24	E612 8019 F05B			1372+	VPSOP	V1, V2, 159, 128, 1	test instruction
00001A2A	E710 8F10 000E		00001110	1373+	VST	V1, V10UTPUT	save result
00001A30	B98D 0020			1374+	EPSW	R2, R0	exptract psw
00001A34	5020 8EF4		000010F4	1375+	ST	R2, CCPSW	to save CC
00001A38	07FB			1376+	BR	R11	return
00001A3C				1377+RE22	DC	0F	
00001A3C				1378+	DROP	R5	
00001A3C	00000000 00000000			1379	DC	XL16' 000000000000000000000000220000000D'	V1
00001A44	00000022 0000000D						
00001A4C	00000000 00000000			1380	DC	XL16' 000000000000000000000000220000000B'	V2
00001A54	00000022 0000000B						
				1381			
				1382	VRI_G	VPSOP, 159, 130, 1, 1	nz=0 pc=1
00001A60				1383+	DS	0FD	
00001A60		00001A60		1384+	USING	*, R5	base for test data and test routine
00001A60	00001A80			1385+T23	DC	A(X23)	address of test routine
00001A64	0017			1386+	DC	H' 23'	test number
00001A66	00			1387+	DC	X' 00'	
00001A67	9F			1388+	DC	HL1' 159'	i3
00001A68	82			1389+	DC	HL1' 130'	i4
00001A69	01			1390+	DC	HL1' 1'	m5
00001A6A	01			1391+	DC	HL1' 1'	cc
00001A6B	0B			1392+	DC	HL1' 11'	cc failed mask
00001A6C	00001AB4			1393+V2_23	DC	A(RE23+16)	address of v2: 16-byte packed decimal
00001A70	E5D7E2D6 D7404040			1394+	DC	CL8' VPSOP'	instruction name
00001A78	00000010			1395+	DC	A(16)	result length
00001A7C	00001AA4			1396+REA23	DC	A(RE23)	result address
				1397+*			INSTRUCTION UNDER TEST ROUTINE
00001A80				1398+X23	DS	0F	
00001A80	E320 500C 0014		00001A6C	1399+	LGF	R2, V2_23	get v2
00001A86	E722 0000 0006		00000000	1400+	VL	V2, 0(R2)	
00001A8C	E612 8219 F05B			1401+	VPSOP	V1, V2, 159, 130, 1	test instruction
00001A92	E710 8F10 000E		00001110	1402+	VST	V1, V10UTPUT	save result
00001A98	B98D 0020			1403+	EPSW	R2, R0	exptract psw
00001A9C	5020 8EF4		000010F4	1404+	ST	R2, CCPSW	to save CC
00001AA0	07FB			1405+	BR	R11	return
00001AA4				1406+RE23	DC	0F	
00001AA4				1407+	DROP	R5	
00001AA4	00000000 00000000			1408	DC	XL16' 000000000000000000000000220000000D'	V1
00001AAC	00000022 0000000D						
00001AB4	00000000 00000000			1409	DC	XL16' 000000000000000000000000220000000B'	V2
00001ABC	00000022 0000000B						
				1410			
				1411	VRI_G	VPSOP, 159, 192, 1, 1	nz=1 pc=0
00001AC8				1412+	DS	0FD	
00001AC8		00001AC8		1413+	USING	*, R5	base for test data and test routine
00001AC8	00001AE8			1414+T24	DC	A(X24)	address of test routine
00001ACC	0018			1415+	DC	H' 24'	test number
00001ACE	00			1416+	DC	X' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001ACF	9F			1417+	DC	HL1' 159'	i3
00001AD0	C0			1418+	DC	HL1' 192'	i4
00001AD1	01			1419+	DC	HL1' 1'	m5
00001AD2	01			1420+	DC	HL1' 1'	cc
00001AD3	0B			1421+	DC	HL1' 11'	cc failed mask
00001AD4	00001B1C			1422+V2_24	DC	A(RE24+16)	address of v2: 16-byte packed decimal
00001AD8	E5D7E2D6 D7404040			1423+	DC	CL8' VPSOP'	instruction name
00001AE0	00000010			1424+	DC	A(16)	result length
00001AE4	00001B0C			1425+REA24	DC	A(RE24)	result address
				1426+*			INSTRUCTION UNDER TEST ROUTINE
00001AE8				1427+X24	DS	0F	
00001AE8	E320 500C 0014		00001AD4	1428+	LGF	R2, V2_24	get v2
00001AEE	E722 0000 0006		00000000	1429+	VL	V2, 0(R2)	
00001AF4	E612 C019 F05B			1430+	VPSOP	V1, V2, 159, 192, 1	test instruction
00001AFA	E710 8F10 000E		00001110	1431+	VST	V1, V10UTPUT	save result
00001B00	B98D 0020			1432+	EPSW	R2, R0	exptract psw
00001B04	5020 8EF4		000010F4	1433+	ST	R2, CCPSW	to save CC
00001B08	07FB			1434+	BR	R11	return
00001B0C				1435+RE24	DC	0F	
00001B0C				1436+	DROP	R5	
00001B0C	00000000 00000000			1437	DC	XL16' 000000000000000000000000220000000D'	V1
00001B14	00000022 0000000D						
00001B1C	00000000 00000000			1438	DC	XL16' 000000000000000000000000220000000B'	V2
00001B24	00000022 0000000B						
				1439			
				1440	VRI_G	VPSOP, 159, 194, 1, 1	nz=1 pc=1
00001B30				1441+	DS	0FD	
00001B30		00001B30		1442+	USING	*, R5	base for test data and test routine
00001B30	00001B50			1443+T25	DC	A(X25)	address of test routine
00001B34	0019			1444+	DC	H' 25'	test number
00001B36	00			1445+	DC	X' 00'	
00001B37	9F			1446+	DC	HL1' 159'	i3
00001B38	C2			1447+	DC	HL1' 194'	i4
00001B39	01			1448+	DC	HL1' 1'	m5
00001B3A	01			1449+	DC	HL1' 1'	cc
00001B3B	0B			1450+	DC	HL1' 11'	cc failed mask
00001B3C	00001B84			1451+V2_25	DC	A(RE25+16)	address of v2: 16-byte packed decimal
00001B40	E5D7E2D6 D7404040			1452+	DC	CL8' VPSOP'	instruction name
00001B48	00000010			1453+	DC	A(16)	result length
00001B4C	00001B74			1454+REA25	DC	A(RE25)	result address
				1455+*			INSTRUCTION UNDER TEST ROUTINE
00001B50				1456+X25	DS	0F	
00001B50	E320 500C 0014		00001B3C	1457+	LGF	R2, V2_25	get v2
00001B56	E722 0000 0006		00000000	1458+	VL	V2, 0(R2)	
00001B5C	E612 C219 F05B			1459+	VPSOP	V1, V2, 159, 194, 1	test instruction
00001B62	E710 8F10 000E		00001110	1460+	VST	V1, V10UTPUT	save result
00001B68	B98D 0020			1461+	EPSW	R2, R0	exptract psw
00001B6C	5020 8EF4		000010F4	1462+	ST	R2, CCPSW	to save CC
00001B70	07FB			1463+	BR	R11	return
00001B74				1464+RE25	DC	0F	
00001B74				1465+	DROP	R5	
00001B74	00000000 00000000			1466	DC	XL16' 000000000000000000000000220000000D'	V1
00001B7C	00000022 0000000D						
00001B84	00000000 00000000			1467	DC	XL16' 000000000000000000000000220000000B'	V2
00001B8C	00000022 0000000B						
				1468			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
				1469 *	V1: nonzero V2: invalid	PC=' - '	NZ=' â€‘'	V1_sign=V2 CC=2
				1470	VRI_G VPSOP, 159, 128, 1, 2		nz=0 pc=0	
00001B98				1471+	DS	OFD		
00001B98		00001B98		1472+	USING	*, R5		base for test data and test routine
00001B98	00001BB8			1473+T26	DC	A(X26)		address of test routine
00001B9C	001A			1474+	DC	H' 26'		test number
00001B9E	00			1475+	DC	X' 00'		
00001B9F	9F			1476+	DC	HL1' 159'		i3
00001BA0	80			1477+	DC	HL1' 128'		i4
00001BA1	01			1478+	DC	HL1' 1'		m5
00001BA2	02			1479+	DC	HL1' 2'		cc
00001BA3	0D			1480+	DC	HL1' 13'		cc failed mask
00001BA4	00001BEC			1481+V2_26	DC	A(RE26+16)		address of v2: 16-byte packed decimal
00001BA8	E5D7E2D6 D7404040			1482+	DC	CL8' VPSOP'		instruction name
00001BB0	00000010			1483+	DC	A(16)		result length
00001BB4	00001BDC			1484+REA26	DC	A(RE26)		result address
				1485+*				INSTRUCTION UNDER TEST ROUTINE
00001BB8				1486+X26	DS	OF		
00001BB8	E320 500C 0014		00001BA4	1487+	LGF	R2, V2_26		get v2
00001BBE	E722 0000 0006		00000000	1488+	VL	V2, 0(R2)		
00001BC4	E612 8019 F05B			1489+	VPSOP	V1, V2, 159, 128, 1		test instruction
00001BCA	E710 8F10 000E		00001110	1490+	VST	V1, V10UTPUT		save result
00001BD0	B98D 0020			1491+	EPSW	R2, R0		exptract psw
00001BD4	5020 8EF4		000010F4	1492+	ST	R2, CCPSW		to save CC
00001BD8	07FB			1493+	BR	R11		return
00001BDC				1494+RE26	DC	OF		
00001BDC				1495+	DROP	R5		
00001BDC	00000000 00000000			1496	DC	XL16' 0000000000000000000000002200000009'		V1
00001BE4	00000022 00000009							
00001BEC	00000000 00000000			1497	DC	XL16' 0000000000000000000000002200000009'		V2
00001BF4	00000022 00000009							
				1498				
				1499	VRI_G VPSOP, 159, 130, 1, 2		nz=0 pc=1	
00001C00				1500+	DS	OFD		
00001C00		00001C00		1501+	USING	*, R5		base for test data and test routine
00001C00	00001C20			1502+T27	DC	A(X27)		address of test routine
00001C04	001B			1503+	DC	H' 27'		test number
00001C06	00			1504+	DC	X' 00'		
00001C07	9F			1505+	DC	HL1' 159'		i3
00001C08	82			1506+	DC	HL1' 130'		i4
00001C09	01			1507+	DC	HL1' 1'		m5
00001C0A	02			1508+	DC	HL1' 2'		cc
00001C0B	0D			1509+	DC	HL1' 13'		cc failed mask
00001C0C	00001C54			1510+V2_27	DC	A(RE27+16)		address of v2: 16-byte packed decimal
00001C10	E5D7E2D6 D7404040			1511+	DC	CL8' VPSOP'		instruction name
00001C18	00000010			1512+	DC	A(16)		result length
00001C1C	00001C44			1513+REA27	DC	A(RE27)		result address
				1514+*				INSTRUCTION UNDER TEST ROUTINE
00001C20				1515+X27	DS	OF		
00001C20	E320 500C 0014		00001C0C	1516+	LGF	R2, V2_27		get v2
00001C26	E722 0000 0006		00000000	1517+	VL	V2, 0(R2)		
00001C2C	E612 8219 F05B			1518+	VPSOP	V1, V2, 159, 130, 1		test instruction
00001C32	E710 8F10 000E		00001110	1519+	VST	V1, V10UTPUT		save result
00001C38	B98D 0020			1520+	EPSW	R2, R0		exptract psw
00001C3C	5020 8EF4		000010F4	1521+	ST	R2, CCPSW		to save CC
00001C40	07FB			1522+	BR	R11		return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C44				1523+RE27	DC	0F	
00001C44				1524+	DROP	R5	
00001C44	00000000 00000000			1525	DC	XL16' 0000000000000000000000002200000009'	V1
00001C4C	00000022 00000009						
00001C54	00000000 00000000			1526	DC	XL16' 0000000000000000000000002200000009'	V2
00001C5C	00000022 00000009						
				1527			
				1528	VRI_G	VPSOP, 159, 192, 1, 2	nz=1 pc=0
00001C68				1529+	DS	0FD	
00001C68		00001C68		1530+	USING	*, R5	base for test data and test routine
00001C68	00001C88			1531+T28	DC	A(X28)	address of test routine
00001C6C	001C			1532+	DC	H' 28'	test number
00001C6E	00			1533+	DC	X' 00'	
00001C6F	9F			1534+	DC	HL1' 159'	i3
00001C70	C0			1535+	DC	HL1' 192'	i4
00001C71	01			1536+	DC	HL1' 1'	m5
00001C72	02			1537+	DC	HL1' 2'	cc
00001C73	0D			1538+	DC	HL1' 13'	cc failed mask
00001C74	00001CBC			1539+V2_28	DC	A(RE28+16)	address of v2: 16-byte packed decimal
00001C78	E5D7E2D6 D7404040			1540+	DC	CL8' VPSOP'	instruction name
00001C80	00000010			1541+	DC	A(16)	result length
00001C84	00001CAC			1542+REA28	DC	A(RE28)	result address
				1543+*			INSTRUCTION UNDER TEST ROUTINE
00001C88				1544+X28	DS	0F	
00001C88	E320 500C 0014		00001C74	1545+	LGF	R2, V2_28	get v2
00001C8E	E722 0000 0006		00000000	1546+	VL	V2, 0(R2)	
00001C94	E612 C019 F05B			1547+	VPSOP	V1, V2, 159, 192, 1	test instruction
00001C9A	E710 8F10 000E		00001110	1548+	VST	V1, V10UTPUT	save result
00001CA0	B98D 0020			1549+	EPSW	R2, R0	exptract psw
00001CA4	5020 8EF4		000010F4	1550+	ST	R2, CCPSW	to save CC
00001CA8	07FB			1551+	BR	R11	return
00001CAC				1552+RE28	DC	0F	
00001CAC				1553+	DROP	R5	
00001CAC	00000000 00000000			1554	DC	XL16' 0000000000000000000000002200000009'	V1
00001CB4	00000022 00000009						
00001CBC	00000000 00000000			1555	DC	XL16' 0000000000000000000000002200000009'	V2
00001CC4	00000022 00000009						
				1556			
				1557	VRI_G	VPSOP, 159, 194, 1, 2	nz=1 pc=1
00001CD0				1558+	DS	0FD	
00001CD0		00001CD0		1559+	USING	*, R5	base for test data and test routine
00001CD0	00001CF0			1560+T29	DC	A(X29)	address of test routine
00001CD4	001D			1561+	DC	H' 29'	test number
00001CD6	00			1562+	DC	X' 00'	
00001CD7	9F			1563+	DC	HL1' 159'	i3
00001CD8	C2			1564+	DC	HL1' 194'	i4
00001CD9	01			1565+	DC	HL1' 1'	m5
00001CDA	02			1566+	DC	HL1' 2'	cc
00001CDB	0D			1567+	DC	HL1' 13'	cc failed mask
00001CDC	00001D24			1568+V2_29	DC	A(RE29+16)	address of v2: 16-byte packed decimal
00001CE0	E5D7E2D6 D7404040			1569+	DC	CL8' VPSOP'	instruction name
00001CE8	00000010			1570+	DC	A(16)	result length
00001CEC	00001D14			1571+REA29	DC	A(RE29)	result address
				1572+*			INSTRUCTION UNDER TEST ROUTINE
00001CF0				1573+X29	DS	0F	
00001CF0	E320 500C 0014		00001CDC	1574+	LGF	R2, V2_29	get v2

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001CF6	E722 0000 0006		00000000	1575+	VL	V2, 0(R2)		
00001CFC	E612 C219 F05B			1576+	VPSOP	V1, V2, 159, 194, 1	test instruction	
00001D02	E710 8F10 000E		00001110	1577+	VST	V1, V10UTPUT	save result	
00001D08	B98D 0020			1578+	EPSW	R2, R0	exptract psw	
00001D0C	5020 8EF4		000010F4	1579+	ST	R2, CCPSW	to save CC	
00001D10	07FB			1580+	BR	R11	return	
00001D14				1581+RE29	DC	0F		
00001D14				1582+	DROP	R5		
00001D14	00000000 00000000			1583	DC	XL16' 00000000000000000000000002200000009'	V1	
00001D1C	00000022 00000009							
00001D24	00000000 00000000			1584	DC	XL16' 00000000000000000000000002200000009'	V2	
00001D2C	00000022 00000009							
				1585				
				1586 *	V1: zero V2: positive PC=' 0' NZ=' â€‘' V1_sign=C CC=0			
				1587	VRI_G	VPSOP, 159, 128, 1, 0	nz=0 pc=0	
00001D38				1588+	DS	0FD		
00001D38		00001D38		1589+	USING	*, R5	base for test data and test routine	
00001D38	00001D58			1590+T30	DC	A(X30)	address of test routine	
00001D3C	001E			1591+	DC	H' 30'	test number	
00001D3E	00			1592+	DC	X' 00'		
00001D3F	9F			1593+	DC	HL1' 159'	i3	
00001D40	80			1594+	DC	HL1' 128'	i4	
00001D41	01			1595+	DC	HL1' 1'	m5	
00001D42	00			1596+	DC	HL1' 0'	cc	
00001D43	07			1597+	DC	HL1' 7'	cc failed mask	
00001D44	00001D8C			1598+V2_30	DC	A(RE30+16)	address of v2: 16-byte packed decimal	
00001D48	E5D7E2D6 D7404040			1599+	DC	CL8' VPSOP'	instruction name	
00001D50	00000010			1600+	DC	A(16)	result length	
00001D54	00001D7C			1601+REA30	DC	A(RE30)	result address	
				1602+*			INSTRUCTION UNDER TEST ROUTINE	
00001D58				1603+X30	DS	0F		
00001D58	E320 500C 0014		00001D44	1604+	LGF	R2, V2_30	get v2	
00001D5E	E722 0000 0006		00000000	1605+	VL	V2, 0(R2)		
00001D64	E612 8019 F05B			1606+	VPSOP	V1, V2, 159, 128, 1	test instruction	
00001D6A	E710 8F10 000E		00001110	1607+	VST	V1, V10UTPUT	save result	
00001D70	B98D 0020			1608+	EPSW	R2, R0	exptract psw	
00001D74	5020 8EF4		000010F4	1609+	ST	R2, CCPSW	to save CC	
00001D78	07FB			1610+	BR	R11	return	
00001D7C				1611+RE30	DC	0F		
00001D7C				1612+	DROP	R5		
00001D7C	00000000 00000000			1613	DC	XL16' 0000000000000000000000000000000C'	V1	
00001D84	00000000 0000000C							
00001D8C	00000000 00000000			1614	DC	XL16' 0000000000000000000000000000000F'	V2	
00001D94	00000000 0000000F							
				1615				
				1616	VRI_G	VPSOP, 159, 192, 1, 0	nz=1 pc=0	
00001DA0				1617+	DS	0FD		
00001DA0		00001DA0		1618+	USING	*, R5	base for test data and test routine	
00001DA0	00001DC0			1619+T31	DC	A(X31)	address of test routine	
00001DA4	001F			1620+	DC	H' 31'	test number	
00001DA6	00			1621+	DC	X' 00'		
00001DA7	9F			1622+	DC	HL1' 159'	i3	
00001DA8	C0			1623+	DC	HL1' 192'	i4	
00001DA9	01			1624+	DC	HL1' 1'	m5	
00001DAA	00			1625+	DC	HL1' 0'	cc	
00001DAB	07			1626+	DC	HL1' 7'	cc failed mask	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001DAC	00001DF4			1627+V2_31	DC	A(RE31+16)	address of v2: 16-byte packed decimal
00001DB0	E5D7E2D6 D7404040			1628+	DC	CL8' VPSOP'	instruction name
00001DB8	00000010			1629+	DC	A(16)	result length
00001DBC	00001DE4			1630+REA31	DC	A(RE31)	result address
				1631+*			INSTRUCTION UNDER TEST ROUTINE
00001DC0				1632+X31	DS	0F	
00001DC0	E320 500C 0014		00001DAC	1633+	LGF	R2, V2_31	get v2
00001DC6	E722 0000 0006		00000000	1634+	VL	V2, 0(R2)	
00001DCC	E612 C019 F05B			1635+	VPSOP	V1, V2, 159, 192, 1	test instruction
00001DD2	E710 8F10 000E		00001110	1636+	VST	V1, V10UTPUT	save result
00001DD8	B98D 0020			1637+	EPSW	R2, R0	exptract psw
00001DDC	5020 8EF4		000010F4	1638+	ST	R2, CCPSW	to save CC
00001DE0	07FB			1639+	BR	R11	return
00001DE4				1640+RE31	DC	0F	
00001DE4				1641+	DROP	R5	
00001DE4	00000000 00000000			1642	DC	XL16' 00000000000000000000000000000000C'	V1
00001DEC	00000000 0000000C						
00001DF4	00000000 00000000			1643	DC	XL16' 00000000000000000000000000000000F'	V2
00001DFC	00000000 0000000F						
				1644			
				1645 * V1: zero V2: positive PC=' 1' NZ=' â€‘' V1_sign=F CC=0			
				1646	VRI_G	VPSOP, 159, 130, 1, 0	nz=0 pc=1
00001E08				1647+	DS	0FD	
00001E08		00001E08		1648+	USING	*, R5	base for test data and test routine
00001E08	00001E28			1649+T32	DC	A(X32)	address of test routine
00001E0C	0020			1650+	DC	H' 32'	test number
00001E0E	00			1651+	DC	X' 00'	
00001E0F	9F			1652+	DC	HL1' 159'	i3
00001E10	82			1653+	DC	HL1' 130'	i4
00001E11	01			1654+	DC	HL1' 1'	m5
00001E12	00			1655+	DC	HL1' 0'	cc
00001E13	07			1656+	DC	HL1' 7'	cc failed mask
00001E14	00001E5C			1657+V2_32	DC	A(RE32+16)	address of v2: 16-byte packed decimal
00001E18	E5D7E2D6 D7404040			1658+	DC	CL8' VPSOP'	instruction name
00001E20	00000010			1659+	DC	A(16)	result length
00001E24	00001E4C			1660+REA32	DC	A(RE32)	result address
				1661+*			INSTRUCTION UNDER TEST ROUTINE
00001E28				1662+X32	DS	0F	
00001E28	E320 500C 0014		00001E14	1663+	LGF	R2, V2_32	get v2
00001E2E	E722 0000 0006		00000000	1664+	VL	V2, 0(R2)	
00001E34	E612 8219 F05B			1665+	VPSOP	V1, V2, 159, 130, 1	test instruction
00001E3A	E710 8F10 000E		00001110	1666+	VST	V1, V10UTPUT	save result
00001E40	B98D 0020			1667+	EPSW	R2, R0	exptract psw
00001E44	5020 8EF4		000010F4	1668+	ST	R2, CCPSW	to save CC
00001E48	07FB			1669+	BR	R11	return
00001E4C				1670+RE32	DC	0F	
00001E4C				1671+	DROP	R5	
00001E4C	00000000 00000000			1672	DC	XL16' 00000000000000000000000000000000F'	V1
00001E54	00000000 0000000F						
00001E5C	00000000 00000000			1673	DC	XL16' 00000000000000000000000000000000C'	V2
00001E64	00000000 0000000C						
				1674			
				1675	VRI_G	VPSOP, 159, 194, 1, 0	nz=1 pc=1
00001E70				1676+	DS	0FD	
00001E70		00001E70		1677+	USING	*, R5	base for test data and test routine
00001E70	00001E90			1678+T33	DC	A(X33)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001E74	0021			1679+	DC	H' 33'	test number
00001E76	00			1680+	DC	X' 00'	
00001E77	9F			1681+	DC	HL1' 159'	i3
00001E78	C2			1682+	DC	HL1' 194'	i4
00001E79	01			1683+	DC	HL1' 1'	m5
00001E7A	00			1684+	DC	HL1' 0'	cc
00001E7B	07			1685+	DC	HL1' 7'	cc failed mask
00001E7C	00001EC4			1686+V2_33	DC	A(RE33+16)	address of v2: 16-byte packed decimal
00001E80	E5D7E2D6 D7404040			1687+	DC	CL8' VPSOP'	instruction name
00001E88	00000010			1688+	DC	A(16)	result length
00001E8C	00001EB4			1689+REA33	DC	A(RE33)	result address
				1690+*			INSTRUCTION UNDER TEST ROUTINE
00001E90				1691+X33	DS	0F	
00001E90	E320 500C 0014		00001E7C	1692+	LGF	R2, V2_33	get v2
00001E96	E722 0000 0006		00000000	1693+	VL	V2, 0(R2)	
00001E9C	E612 C219 F05B			1694+	VPSOP	V1, V2, 159, 194, 1	test instruction
00001EA2	E710 8F10 000E		00001110	1695+	VST	V1, V10UTPUT	save result
00001EA8	B98D 0020			1696+	EPSW	R2, R0	exptract psw
00001EAC	5020 8EF4		000010F4	1697+	ST	R2, CCPSW	to save CC
00001EB0	07FB			1698+	BR	R11	return
00001EB4				1699+RE33	DC	0F	
00001EB4				1700+	DROP	R5	
00001EB4	00000000 00000000			1701	DC	XL16' 00000000000000000000000000000000F'	V1
00001EBC	00000000 0000000F						
00001EC4	00000000 00000000			1702	DC	XL16' 00000000000000000000000000000000C'	V2
00001ECC	00000000 0000000C						
				1703			
				1704 * V1: zero V2: negative PC=' 0' NZ=' 0' V1_sign=C CC=0			
				1705 VRI_G VPSOP, 159, 128, 1, 0 nz=0 pc=0			
00001ED8				1706+	DS	0FD	
00001ED8		00001ED8		1707+	USING	*, R5	base for test data and test routine
00001ED8	00001EF8			1708+T34	DC	A(X34)	address of test routine
00001EDC	0022			1709+	DC	H' 34'	test number
00001EDE	00			1710+	DC	X' 00'	
00001EDF	9F			1711+	DC	HL1' 159'	i3
00001EE0	80			1712+	DC	HL1' 128'	i4
00001EE1	01			1713+	DC	HL1' 1'	m5
00001EE2	00			1714+	DC	HL1' 0'	cc
00001EE3	07			1715+	DC	HL1' 7'	cc failed mask
00001EE4	00001F2C			1716+V2_34	DC	A(RE34+16)	address of v2: 16-byte packed decimal
00001EE8	E5D7E2D6 D7404040			1717+	DC	CL8' VPSOP'	instruction name
00001EF0	00000010			1718+	DC	A(16)	result length
00001EF4	00001F1C			1719+REA34	DC	A(RE34)	result address
				1720+*			INSTRUCTION UNDER TEST ROUTINE
00001EF8				1721+X34	DS	0F	
00001EF8	E320 500C 0014		00001EE4	1722+	LGF	R2, V2_34	get v2
00001EFE	E722 0000 0006		00000000	1723+	VL	V2, 0(R2)	
00001F04	E612 8019 F05B			1724+	VPSOP	V1, V2, 159, 128, 1	test instruction
00001F0A	E710 8F10 000E		00001110	1725+	VST	V1, V10UTPUT	save result
00001F10	B98D 0020			1726+	EPSW	R2, R0	exptract psw
00001F14	5020 8EF4		000010F4	1727+	ST	R2, CCPSW	to save CC
00001F18	07FB			1728+	BR	R11	return
00001F1C				1729+RE34	DC	0F	
00001F1C				1730+	DROP	R5	
00001F1C	00000000 00000000			1731	DC	XL16' 00000000000000000000000000000000C'	V1
00001F24	00000000 0000000C						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001F2C	00000000 00000000			1732	DC	XL16' 0000000000000000000000000000000D'	V2
00001F34	00000000 0000000D						
				1733			
				1734	* V1: zero V2: negative PC=' 1' NZ=' 0' V1_sign=F CC=0		
				1735	VRI_G VPSOP, 159, 130, 1, 0 nz=0 pc=1		
00001F40				1736+	DS	0FD	
00001F40		00001F40		1737+	USING	*, R5	base for test data and test routine
00001F40	00001F60			1738+T35	DC	A(X35)	address of test routine
00001F44	0023			1739+	DC	H' 35'	test number
00001F46	00			1740+	DC	X' 00'	
00001F47	9F			1741+	DC	HL1' 159'	i3
00001F48	82			1742+	DC	HL1' 130'	i4
00001F49	01			1743+	DC	HL1' 1'	m5
00001F4A	00			1744+	DC	HL1' 0'	cc
00001F4B	07			1745+	DC	HL1' 7'	cc failed mask
00001F4C	00001F94			1746+V2_35	DC	A(RE35+16)	address of v2: 16-byte packed decimal
00001F50	E5D7E2D6 D7404040			1747+	DC	CL8' VPSOP'	instruction name
00001F58	00000010			1748+	DC	A(16)	result length
00001F5C	00001F84			1749+REA35	DC	A(RE35)	result address
				1750+*			INSTRUCTION UNDER TEST ROUTINE
00001F60				1751+X35	DS	0F	
00001F60	E320 500C 0014		00001F4C	1752+	LGF	R2, V2_35	get v2
00001F66	E722 0000 0006		00000000	1753+	VL	V2, 0(R2)	
00001F6C	E612 8219 F05B			1754+	VPSOP	V1, V2, 159, 130, 1	test instruction
00001F72	E710 8F10 000E		00001110	1755+	VST	V1, V10UTPUT	save result
00001F78	B98D 0020			1756+	EPSW	R2, R0	exptract psw
00001F7C	5020 8EF4		000010F4	1757+	ST	R2, CCPSW	to save CC
00001F80	07FB			1758+	BR	R11	return
00001F84				1759+RE35	DC	0F	
00001F84				1760+	DROP	R5	
00001F84	00000000 00000000			1761	DC	XL16' 000000000000000000000000000000F'	V1
00001F8C	00000000 0000000F						
00001F94	00000000 00000000			1762	DC	XL16' 000000000000000000000000000000D'	V2
00001F9C	00000000 0000000D						
				1763			
				1764	* V1: zero V2: negative PC=' - ' NZ=' 1' V1_sign=D CC=0		
				1765	VRI_G VPSOP, 159, 192, 1, 0 nz=1 pc=0		
00001FA8				1766+	DS	0FD	
00001FA8		00001FA8		1767+	USING	*, R5	base for test data and test routine
00001FA8	00001FC8			1768+T36	DC	A(X36)	address of test routine
00001FAC	0024			1769+	DC	H' 36'	test number
00001FAE	00			1770+	DC	X' 00'	
00001FAF	9F			1771+	DC	HL1' 159'	i3
00001FB0	C0			1772+	DC	HL1' 192'	i4
00001FB1	01			1773+	DC	HL1' 1'	m5
00001FB2	00			1774+	DC	HL1' 0'	cc
00001FB3	07			1775+	DC	HL1' 7'	cc failed mask
00001FB4	00001FFC			1776+V2_36	DC	A(RE36+16)	address of v2: 16-byte packed decimal
00001FB8	E5D7E2D6 D7404040			1777+	DC	CL8' VPSOP'	instruction name
00001FC0	00000010			1778+	DC	A(16)	result length
00001FC4	00001FEC			1779+REA36	DC	A(RE36)	result address
				1780+*			INSTRUCTION UNDER TEST ROUTINE
00001FC8				1781+X36	DS	0F	
00001FC8	E320 500C 0014		00001FB4	1782+	LGF	R2, V2_36	get v2
00001FCE	E722 0000 0006		00000000	1783+	VL	V2, 0(R2)	
00001FD4	E612 C019 F05B			1784+	VPSOP	V1, V2, 159, 192, 1	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001FDA	E710 8F10 000E		00001110	1785+	VST	V1, V10OUTPUT	save result	
00001FE0	B98D 0020			1786+	EPSW	R2, R0	exptract psw	
00001FE4	5020 8EF4		000010F4	1787+	ST	R2, CCPSW	to save CC	
00001FE8	07FB			1788+	BR	R11	return	
00001FEC				1789+RE36	DC	0F		
00001FEC				1790+	DROP	R5		
00001FEC	00000000 00000000			1791	DC	XL16' 0000000000000000000000000000000D'	V1	
00001FF4	00000000 0000000D							
00001FFC	00000000 00000000			1792	DC	XL16' 0000000000000000000000000000000B'	V2	
00002004	00000000 0000000B							
				1793				
				1794	VRI_G	VPSOP, 159, 194, 1, 0	nz=1 pc=1	
00002010				1795+	DS	0FD		
00002010		00002010		1796+	USING	*, R5	base for test data and test routine	
00002010	00002030			1797+T37	DC	A(X37)	address of test routine	
00002014	0025			1798+	DC	H' 37'	test number	
00002016	00			1799+	DC	X' 00'		
00002017	9F			1800+	DC	HL1' 159'	i3	
00002018	C2			1801+	DC	HL1' 194'	i4	
00002019	01			1802+	DC	HL1' 1'	m5	
0000201A	00			1803+	DC	HL1' 0'	cc	
0000201B	07			1804+	DC	HL1' 7'	cc failed mask	
0000201C	00002064			1805+V2_37	DC	A(RE37+16)	address of v2: 16-byte packed decimal	
00002020	E5D7E2D6 D7404040			1806+	DC	CL8' VPSOP'	instruction name	
00002028	00000010			1807+	DC	A(16)	result length	
0000202C	00002054			1808+REA37	DC	A(RE37)	result address	
				1809+*			INSTRUCTION UNDER TEST ROUTINE	
00002030				1810+X37	DS	0F		
00002030	E320 500C 0014		0000201C	1811+	LGF	R2, V2_37	get v2	
00002036	E722 0000 0006		00000000	1812+	VL	V2, 0(R2)		
0000203C	E612 C219 F05B			1813+	VPSOP	V1, V2, 159, 194, 1	test instruction	
00002042	E710 8F10 000E		00001110	1814+	VST	V1, V10OUTPUT	save result	
00002048	B98D 0020			1815+	EPSW	R2, R0	exptract psw	
0000204C	5020 8EF4		000010F4	1816+	ST	R2, CCPSW	to save CC	
00002050	07FB			1817+	BR	R11	return	
00002054				1818+RE37	DC	0F		
00002054				1819+	DROP	R5		
00002054	00000000 00000000			1820	DC	XL16' 0000000000000000000000000000000D'	V1	
0000205C	00000000 0000000D							
00002064	00000000 00000000			1821	DC	XL16' 0000000000000000000000000000000B'	V2	
0000206C	00000000 0000000B							
				1822				
				1823 * V1: zero V2: invalid PC=' - ' NZ=' â€‘' V1_sign=V2 CC=0				
				1824	VRI_G	VPSOP, 159, 128, 1, 0	nz=0 pc=0	
00002078				1825+	DS	0FD		
00002078		00002078		1826+	USING	*, R5	base for test data and test routine	
00002078	00002098			1827+T38	DC	A(X38)	address of test routine	
0000207C	0026			1828+	DC	H' 38'	test number	
0000207E	00			1829+	DC	X' 00'		
0000207F	9F			1830+	DC	HL1' 159'	i3	
00002080	80			1831+	DC	HL1' 128'	i4	
00002081	01			1832+	DC	HL1' 1'	m5	
00002082	00			1833+	DC	HL1' 0'	cc	
00002083	07			1834+	DC	HL1' 7'	cc failed mask	
00002084	000020CC			1835+V2_38	DC	A(RE38+16)	address of v2: 16-byte packed decimal	
00002088	E5D7E2D6 D7404040			1836+	DC	CL8' VPSOP'	instruction name	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002090	00000010			1837+	DC	A(16)	result length
00002094	000020BC			1838+REA38	DC	A(RE38)	result address
				1839+*			INSTRUCTION UNDER TEST ROUTINE
00002098				1840+X38	DS	0F	
00002098	E320 500C 0014		00002084	1841+	LGF	R2, V2_38	get v2
0000209E	E722 0000 0006		00000000	1842+	VL	V2, 0(R2)	
000020A4	E612 8019 F05B			1843+	VPSOP	V1, V2, 159, 128, 1	test instruction
000020AA	E710 8F10 000E		00001110	1844+	VST	V1, V10UTPUT	save result
000020B0	B98D 0020			1845+	EPSW	R2, R0	exptract psw
000020B4	5020 8EF4		000010F4	1846+	ST	R2, CCPSW	to save CC
000020B8	07FB			1847+	BR	R11	return
000020BC				1848+RE38	DC	0F	
000020BC				1849+	DROP	R5	
000020BC	00000000 00000000			1850	DC	XL16' 00000000000000000000000000000009'	V1
000020C4	00000000 00000009						
000020CC	00000000 00000000			1851	DC	XL16' 00000000000000000000000000000009'	V2
000020D4	00000000 00000009						
				1852			
				1853	VRI_G	VPSOP, 159, 130, 1, 0	nz=0 pc=1
000020E0				1854+	DS	0FD	
000020E0		000020E0		1855+	USING	*, R5	base for test data and test routine
000020E0	00002100			1856+T39	DC	A(X39)	address of test routine
000020E4	0027			1857+	DC	H' 39'	test number
000020E6	00			1858+	DC	X' 00'	
000020E7	9F			1859+	DC	HL1' 159'	i3
000020E8	82			1860+	DC	HL1' 130'	i4
000020E9	01			1861+	DC	HL1' 1'	m5
000020EA	00			1862+	DC	HL1' 0'	cc
000020EB	07			1863+	DC	HL1' 7'	cc failed mask
000020EC	00002134			1864+V2_39	DC	A(RE39+16)	address of v2: 16-byte packed decimal
000020F0	E5D7E2D6 D7404040			1865+	DC	CL8' VPSOP'	instruction name
000020F8	00000010			1866+	DC	A(16)	result length
000020FC	00002124			1867+REA39	DC	A(RE39)	result address
				1868+*			INSTRUCTION UNDER TEST ROUTINE
00002100				1869+X39	DS	0F	
00002100	E320 500C 0014		000020EC	1870+	LGF	R2, V2_39	get v2
00002106	E722 0000 0006		00000000	1871+	VL	V2, 0(R2)	
0000210C	E612 8219 F05B			1872+	VPSOP	V1, V2, 159, 130, 1	test instruction
00002112	E710 8F10 000E		00001110	1873+	VST	V1, V10UTPUT	save result
00002118	B98D 0020			1874+	EPSW	R2, R0	exptract psw
0000211C	5020 8EF4		000010F4	1875+	ST	R2, CCPSW	to save CC
00002120	07FB			1876+	BR	R11	return
00002124				1877+RE39	DC	0F	
00002124				1878+	DROP	R5	
00002124	00000000 00000000			1879	DC	XL16' 00000000000000000000000000000009'	V1
0000212C	00000000 00000009						
00002134	00000000 00000000			1880	DC	XL16' 00000000000000000000000000000009'	V2
0000213C	00000000 00000009						
				1881			
				1882	VRI_G	VPSOP, 159, 192, 1, 0	nz=1 pc=0
00002148				1883+	DS	0FD	
00002148		00002148		1884+	USING	*, R5	base for test data and test routine
00002148	00002168			1885+T40	DC	A(X40)	address of test routine
0000214C	0028			1886+	DC	H' 40'	test number
0000214E	00			1887+	DC	X' 00'	
0000214F	9F			1888+	DC	HL1' 159'	i3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002150	C0			1889+	DC	HL1' 192'	i4
00002151	01			1890+	DC	HL1' 1'	m5
00002152	00			1891+	DC	HL1' 0'	cc
00002153	07			1892+	DC	HL1' 7'	cc failed mask
00002154	0000219C			1893+V2_40	DC	A(RE40+16)	address of v2: 16-byte packed decimal
00002158	E5D7E2D6 D7404040			1894+	DC	CL8' VPSOP'	instruction name
00002160	00000010			1895+	DC	A(16)	result length
00002164	0000218C			1896+REA40	DC	A(RE40)	result address
				1897+*			INSTRUCTION UNDER TEST ROUTINE
00002168				1898+X40	DS	0F	
00002168	E320 500C 0014		00002154	1899+	LGF	R2, V2_40	get v2
0000216E	E722 0000 0006		00000000	1900+	VL	V2, 0(R2)	
00002174	E612 C019 F05B			1901+	VPSOP	V1, V2, 159, 192, 1	test instruction
0000217A	E710 8F10 000E		00001110	1902+	VST	V1, V10UTPUT	save result
00002180	B98D 0020			1903+	EPSW	R2, R0	exptract psw
00002184	5020 8EF4		000010F4	1904+	ST	R2, CCPSW	to save CC
00002188	07FB			1905+	BR	R11	return
0000218C				1906+RE40	DC	0F	
0000218C				1907+	DROP	R5	
0000218C	00000000 00000000			1908	DC	XL16' 00000000000000000000000000000009'	V1
00002194	00000000 00000009						
0000219C	00000000 00000000			1909	DC	XL16' 00000000000000000000000000000009'	V2
000021A4	00000000 00000009						
				1910			
000021B0				1911	VRI_G	VPSOP, 159, 194, 1, 0	nz=1 pc=1
000021B0		000021B0		1912+	DS	0FD	
000021B0	000021D0			1913+	USING	*, R5	base for test data and test routine
000021B4	0029			1914+T41	DC	A(X41)	address of test routine
000021B6	00			1915+	DC	H' 41'	test number
000021B7	9F			1916+	DC	X' 00'	
000021B8	C2			1917+	DC	HL1' 159'	i3
000021B9	01			1918+	DC	HL1' 194'	i4
000021BA	00			1919+	DC	HL1' 1'	m5
000021BB	07			1920+	DC	HL1' 0'	cc
000021BB	07			1921+	DC	HL1' 7'	cc failed mask
000021BC	00002204			1922+V2_41	DC	A(RE41+16)	address of v2: 16-byte packed decimal
000021C0	E5D7E2D6 D7404040			1923+	DC	CL8' VPSOP'	instruction name
000021C8	00000010			1924+	DC	A(16)	result length
000021CC	000021F4			1925+REA41	DC	A(RE41)	result address
				1926+*			INSTRUCTION UNDER TEST ROUTINE
000021D0				1927+X41	DS	0F	
000021D0	E320 500C 0014		000021BC	1928+	LGF	R2, V2_41	get v2
000021D6	E722 0000 0006		00000000	1929+	VL	V2, 0(R2)	
000021DC	E612 C219 F05B			1930+	VPSOP	V1, V2, 159, 194, 1	test instruction
000021E2	E710 8F10 000E		00001110	1931+	VST	V1, V10UTPUT	save result
000021E8	B98D 0020			1932+	EPSW	R2, R0	exptract psw
000021EC	5020 8EF4		000010F4	1933+	ST	R2, CCPSW	to save CC
000021F0	07FB			1934+	BR	R11	return
000021F4				1935+RE41	DC	0F	
000021F4				1936+	DROP	R5	
000021F4	00000000 00000000			1937	DC	XL16' 00000000000000000000000000000009'	V1
000021FC	00000000 00000009						
00002204	00000000 00000000			1938	DC	XL16' 00000000000000000000000000000009'	V2
0000220C	00000000 00000009						
				1939			
				1940 *			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				1941 * SC=01 (complement): nv=1 to avoid data exceptions
				1942 *-----
				1943
				1944 * V1: nonzero V2: positive PC='-' NZ='â€™' V1_sign=D CC=1
				1945 VRI_G VPSOP, 159, 132, 1, 1 nz=0 pc=0
00002218				1946+ DS OFD
00002218		00002218		1947+ USING *, R5 base for test data and test routine
00002218	00002238			1948+T42 DC A(X42) address of test routine
0000221C	002A			1949+ DC H' 42' test number
0000221E	00			1950+ DC X' 00'
0000221F	9F			1951+ DC HL1' 159' i3
00002220	84			1952+ DC HL1' 132' i4
00002221	01			1953+ DC HL1' 1' m5
00002222	01			1954+ DC HL1' 1' cc
00002223	0B			1955+ DC HL1' 11' cc failed mask
00002224	0000226C			1956+V2_42 DC A(RE42+16) address of v2: 16-byte packed decimal
00002228	E5D7E2D6 D7404040			1957+ DC CL8' VPSOP' instruction name
00002230	00000010			1958+ DC A(16) result length
00002234	0000225C			1959+REA42 DC A(RE42) result address
				1960+* INSTRUCTION UNDER TEST ROUTINE
00002238				1961+X42 DS OF
00002238	E320 500C 0014		00002224	1962+ LGF R2, V2_42 get v2
0000223E	E722 0000 0006		00000000	1963+ VL V2, 0(R2)
00002244	E612 8419 F05B			1964+ VPSOP V1, V2, 159, 132, 1 test instruction
0000224A	E710 8F10 000E		00001110	1965+ VST V1, V10UTPUT save result
00002250	B98D 0020			1966+ EPSW R2, R0 exptrect psw
00002254	5020 8EF4		000010F4	1967+ ST R2, CCPSW to save CC
00002258	07FB			1968+ BR R11 return
0000225C				1969+RE42 DC OF
0000225C				1970+ DROP R5
0000225C	00000000 00000000			1971 DC XL16' 000000000000000000000000220000000D' V1
00002264	00000022 0000000D			
0000226C	00000000 00000000			1972 DC XL16' 000000000000000000000000220000000C' V2
00002274	00000022 0000000C			
				1973
				1974 VRI_G VPSOP, 159, 134, 1, 1 nz=0 pc=1
00002280				1975+ DS OFD
00002280		00002280		1976+ USING *, R5 base for test data and test routine
00002280	000022A0			1977+T43 DC A(X43) address of test routine
00002284	002B			1978+ DC H' 43' test number
00002286	00			1979+ DC X' 00'
00002287	9F			1980+ DC HL1' 159' i3
00002288	86			1981+ DC HL1' 134' i4
00002289	01			1982+ DC HL1' 1' m5
0000228A	01			1983+ DC HL1' 1' cc
0000228B	0B			1984+ DC HL1' 11' cc failed mask
0000228C	000022D4			1985+V2_43 DC A(RE43+16) address of v2: 16-byte packed decimal
00002290	E5D7E2D6 D7404040			1986+ DC CL8' VPSOP' instruction name
00002298	00000010			1987+ DC A(16) result length
0000229C	000022C4			1988+REA43 DC A(RE43) result address
				1989+* INSTRUCTION UNDER TEST ROUTINE
000022A0				1990+X43 DS OF
000022A0	E320 500C 0014		0000228C	1991+ LGF R2, V2_43 get v2
000022A6	E722 0000 0006		00000000	1992+ VL V2, 0(R2)
000022AC	E612 8619 F05B			1993+ VPSOP V1, V2, 159, 134, 1 test instruction
000022B2	E710 8F10 000E		00001110	1994+ VST V1, V10UTPUT save result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000022B8	B98D 0020			1995+	EPSW	R2, R0	extract psw
000022BC	5020 8EF4		000010F4	1996+	ST	R2, CCPSW	to save CC
000022C0	07FB			1997+	BR	R11	return
000022C4				1998+RE43	DC	0F	
000022C4				1999+	DROP	R5	
000022C4	00000000 00000000			2000	DC	XL16' 000000000000000000000000220000000D'	V1
000022CC	00000022 0000000D						
000022D4	00000000 00000000			2001	DC	XL16' 000000000000000000000000220000000A'	V2
000022DC	00000022 0000000A						
				2002			
				2003	VRI_G	VPSOP, 159, 196, 1, 1	nz=1 pc=0
000022E8				2004+	DS	0FD	
000022E8		000022E8		2005+	USING	*, R5	base for test data and test routine
000022E8	00002308			2006+T44	DC	A(X44)	address of test routine
000022EC	002C			2007+	DC	H' 44'	test number
000022EE	00			2008+	DC	X' 00'	
000022EF	9F			2009+	DC	HL1' 159'	i3
000022F0	C4			2010+	DC	HL1' 196'	i4
000022F1	01			2011+	DC	HL1' 1'	m5
000022F2	01			2012+	DC	HL1' 1'	cc
000022F3	0B			2013+	DC	HL1' 11'	cc failed mask
000022F4	0000233C			2014+V2_44	DC	A(RE44+16)	address of v2: 16-byte packed decimal
000022F8	E5D7E2D6 D7404040			2015+	DC	CL8' VPSOP'	instruction name
00002300	00000010			2016+	DC	A(16)	result length
00002304	0000232C			2017+REA44	DC	A(RE44)	result address
				2018+*			INSTRUCTION UNDER TEST ROUTINE
00002308				2019+X44	DS	0F	
00002308	E320 500C 0014		000022F4	2020+	LGF	R2, V2_44	get v2
0000230E	E722 0000 0006		00000000	2021+	VL	V2, 0(R2)	
00002314	E612 C419 F05B			2022+	VPSOP	V1, V2, 159, 196, 1	test instruction
0000231A	E710 8F10 000E		00001110	2023+	VST	V1, V10UTPUT	save result
00002320	B98D 0020			2024+	EPSW	R2, R0	extract psw
00002324	5020 8EF4		000010F4	2025+	ST	R2, CCPSW	to save CC
00002328	07FB			2026+	BR	R11	return
0000232C				2027+RE44	DC	0F	
0000232C				2028+	DROP	R5	
0000232C	00000000 00000000			2029	DC	XL16' 000000000000000000000000220000000D'	V1
00002334	00000022 0000000D						
0000233C	00000000 00000000			2030	DC	XL16' 000000000000000000000000220000000F'	V2
00002344	00000022 0000000F						
				2031			
				2032	VRI_G	VPSOP, 159, 198, 1, 1	nz=1 pc=1
00002350				2033+	DS	0FD	
00002350		00002350		2034+	USING	*, R5	base for test data and test routine
00002350	00002370			2035+T45	DC	A(X45)	address of test routine
00002354	002D			2036+	DC	H' 45'	test number
00002356	00			2037+	DC	X' 00'	
00002357	9F			2038+	DC	HL1' 159'	i3
00002358	C6			2039+	DC	HL1' 198'	i4
00002359	01			2040+	DC	HL1' 1'	m5
0000235A	01			2041+	DC	HL1' 1'	cc
0000235B	0B			2042+	DC	HL1' 11'	cc failed mask
0000235C	000023A4			2043+V2_45	DC	A(RE45+16)	address of v2: 16-byte packed decimal
00002360	E5D7E2D6 D7404040			2044+	DC	CL8' VPSOP'	instruction name
00002368	00000010			2045+	DC	A(16)	result length
0000236C	00002394			2046+REA45	DC	A(RE45)	result address

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
					2047+*	INSTRUCTION UNDER TEST ROUTINE	
00002370				2048+X45	DS	0F	
00002370	E320 500C 0014		0000235C	2049+	LGF	R2, V2_45	get v2
00002376	E722 0000 0006		00000000	2050+	VL	V2, 0(R2)	
0000237C	E612 C619 F05B			2051+	VPSOP	V1, V2, 159, 198, 1	test instruction
00002382	E710 8F10 000E		00001110	2052+	VST	V1, V10UTPUT	save result
00002388	B98D 0020			2053+	EPSW	R2, R0	exptract psw
0000238C	5020 8EF4		000010F4	2054+	ST	R2, CCPSW	to save CC
00002390	07FB			2055+	BR	R11	return
00002394				2056+RE45	DC	0F	
00002394				2057+	DROP	R5	
00002394	00000000 00000000			2058	DC	XL16' 000000000000000000000000220000000D'	V1
0000239C	00000022 0000000D						
000023A4	00000000 00000000			2059	DC	XL16' 000000000000000000000000220000000E'	V2
000023AC	00000022 0000000E						
					2060		
					2061 *	V1: nonzero V2: negative PC=' 0' NZ=' â€‘' V1_sign=C CC=2	
					2062	VRI_G VPSOP, 159, 132, 1, 2	nz=0 pc=0
000023B8				2063+	DS	0FD	
000023B8		000023B8		2064+	USING	*, R5	base for test data and test routine
000023B8	000023D8			2065+T46	DC	A(X46)	address of test routine
000023BC	002E			2066+	DC	H' 46'	test number
000023BE	00			2067+	DC	X' 00'	
000023BF	9F			2068+	DC	HL1' 159'	i3
000023C0	84			2069+	DC	HL1' 132'	i4
000023C1	01			2070+	DC	HL1' 1'	m5
000023C2	02			2071+	DC	HL1' 2'	cc
000023C3	0D			2072+	DC	HL1' 13'	cc failed mask
000023C4	0000240C			2073+V2_46	DC	A(RE46+16)	address of v2: 16-byte packed decimal
000023C8	E5D7E2D6 D7404040			2074+	DC	CL8' VPSOP'	instruction name
000023D0	00000010			2075+	DC	A(16)	result length
000023D4	000023FC			2076+REA46	DC	A(RE46)	result address
					2077+*	INSTRUCTION UNDER TEST ROUTINE	
000023D8				2078+X46	DS	0F	
000023D8	E320 500C 0014		000023C4	2079+	LGF	R2, V2_46	get v2
000023DE	E722 0000 0006		00000000	2080+	VL	V2, 0(R2)	
000023E4	E612 8419 F05B			2081+	VPSOP	V1, V2, 159, 132, 1	test instruction
000023EA	E710 8F10 000E		00001110	2082+	VST	V1, V10UTPUT	save result
000023F0	B98D 0020			2083+	EPSW	R2, R0	exptract psw
000023F4	5020 8EF4		000010F4	2084+	ST	R2, CCPSW	to save CC
000023F8	07FB			2085+	BR	R11	return
000023FC				2086+RE46	DC	0F	
000023FC				2087+	DROP	R5	
000023FC	00000000 00000000			2088	DC	XL16' 000000000000000000000000220000000C'	V1
00002404	00000022 0000000C						
0000240C	00000000 00000000			2089	DC	XL16' 000000000000000000000000220000000D'	V2
00002414	00000022 0000000D						
					2090		
					2091	VRI_G VPSOP, 159, 196, 1, 2	nz=1 pc=0
00002420				2092+	DS	0FD	
00002420		00002420		2093+	USING	*, R5	base for test data and test routine
00002420	00002440			2094+T47	DC	A(X47)	address of test routine
00002424	002F			2095+	DC	H' 47'	test number
00002426	00			2096+	DC	X' 00'	
00002427	9F			2097+	DC	HL1' 159'	i3
00002428	C4			2098+	DC	HL1' 196'	i4

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002429	01			2099+	DC	HL1' 1'	m5
0000242A	02			2100+	DC	HL1' 2'	cc
0000242B	0D			2101+	DC	HL1' 13'	cc failed mask
0000242C	00002474			2102+V2_47	DC	A(RE47+16)	address of v2: 16-byte packed decimal
00002430	E5D7E2D6 D7404040			2103+	DC	CL8' VPSOP'	instruction name
00002438	00000010			2104+	DC	A(16)	result length
0000243C	00002464			2105+REA47	DC	A(RE47)	result address
				2106+*			INSTRUCTION UNDER TEST ROUTINE
00002440				2107+X47	DS	0F	
00002440	E320 500C 0014		0000242C	2108+	LGF	R2, V2_47	get v2
00002446	E722 0000 0006		00000000	2109+	VL	V2, 0(R2)	
0000244C	E612 C419 F05B			2110+	VPSOP	V1, V2, 159, 196, 1	test instruction
00002452	E710 8F10 000E		00001110	2111+	VST	V1, V10UTPUT	save result
00002458	B98D 0020			2112+	EPSW	R2, R0	exptract psw
0000245C	5020 8EF4		000010F4	2113+	ST	R2, CCPSW	to save CC
00002460	07FB			2114+	BR	R11	return
00002464				2115+RE47	DC	0F	
00002464				2116+	DROP	R5	
00002464	00000000 00000000			2117	DC	XL16' 000000000000000000000000220000000C'	V1
0000246C	00000022 0000000C						
00002474	00000000 00000000			2118	DC	XL16' 000000000000000000000000220000000D'	V2
0000247C	00000022 0000000D						
				2119			
				2120 *		V1: nonzero V2: negative PC=' 1' NZ=' â€‘' V1_sign=F CC=2	
				2121	VRI_G	VPSOP, 159, 134, 1, 2	nz=0 pc=1
00002488				2122+	DS	0FD	
00002488		00002488		2123+	USING	*, R5	base for test data and test routine
00002488	000024A8			2124+T48	DC	A(X48)	address of test routine
0000248C	0030			2125+	DC	H' 48'	test number
0000248E	00			2126+	DC	X' 00'	
0000248F	9F			2127+	DC	HL1' 159'	i3
00002490	86			2128+	DC	HL1' 134'	i4
00002491	01			2129+	DC	HL1' 1'	m5
00002492	02			2130+	DC	HL1' 2'	cc
00002493	0D			2131+	DC	HL1' 13'	cc failed mask
00002494	000024DC			2132+V2_48	DC	A(RE48+16)	address of v2: 16-byte packed decimal
00002498	E5D7E2D6 D7404040			2133+	DC	CL8' VPSOP'	instruction name
000024A0	00000010			2134+	DC	A(16)	result length
000024A4	000024CC			2135+REA48	DC	A(RE48)	result address
				2136+*			INSTRUCTION UNDER TEST ROUTINE
000024A8				2137+X48	DS	0F	
000024A8	E320 500C 0014		00002494	2138+	LGF	R2, V2_48	get v2
000024AE	E722 0000 0006		00000000	2139+	VL	V2, 0(R2)	
000024B4	E612 8619 F05B			2140+	VPSOP	V1, V2, 159, 134, 1	test instruction
000024BA	E710 8F10 000E		00001110	2141+	VST	V1, V10UTPUT	save result
000024C0	B98D 0020			2142+	EPSW	R2, R0	exptract psw
000024C4	5020 8EF4		000010F4	2143+	ST	R2, CCPSW	to save CC
000024C8	07FB			2144+	BR	R11	return
000024CC				2145+RE48	DC	0F	
000024CC				2146+	DROP	R5	
000024CC	00000000 00000000			2147	DC	XL16' 000000000000000000000000220000000F'	V1
000024D4	00000022 0000000F						
000024DC	00000000 00000000			2148	DC	XL16' 000000000000000000000000220000000D'	V2
000024E4	00000022 0000000D						
				2149			
				2150	VRI_G	VPSOP, 159, 198, 1, 2	nz=1 pc=1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000024F0				2151+	DS	OFD	
000024F0		000024F0		2152+	USING	*,R5	base for test data and test routine
000024F0	00002510			2153+T49	DC	A(X49)	address of test routine
000024F4	0031			2154+	DC	H' 49'	test number
000024F6	00			2155+	DC	X' 00'	
000024F7	9F			2156+	DC	HL1' 159'	i3
000024F8	C6			2157+	DC	HL1' 198'	i4
000024F9	01			2158+	DC	HL1' 1'	m5
000024FA	02			2159+	DC	HL1' 2'	cc
000024FB	0D			2160+	DC	HL1' 13'	cc failed mask
000024FC	00002544			2161+V2_49	DC	A(RE49+16)	address of v2: 16-byte packed decimal
00002500	E5D7E2D6 D7404040			2162+	DC	CL8' VPSOP'	instruction name
00002508	00000010			2163+	DC	A(16)	result length
0000250C	00002534			2164+REA49	DC	A(RE49)	result address
				2165+*			INSTRUCTION UNDER TEST ROUTINE
00002510				2166+X49	DS	OF	
00002510	E320 500C 0014		000024FC	2167+	LGF	R2, V2_49	get v2
00002516	E722 0000 0006		00000000	2168+	VL	V2, 0(R2)	
0000251C	E612 C619 F05B			2169+	VPSOP	V1, V2, 159, 198, 1	test instruction
00002522	E710 8F10 000E		00001110	2170+	VST	V1, V10UTPUT	save result
00002528	B98D 0020			2171+	EPSW	R2, R0	exptract psw
0000252C	5020 8EF4		000010F4	2172+	ST	R2, CCPSW	to save CC
00002530	07FB			2173+	BR	R11	return
00002534				2174+RE49	DC	OF	
00002534				2175+	DROP	R5	
00002534	00000000 00000000			2176	DC	XL16' 000000000000000000000000220000000F'	V1
0000253C	00000022 0000000F						
00002544	00000000 00000000			2177	DC	XL16' 000000000000000000000000220000000D'	V2
0000254C	00000022 0000000D						
				2178			
				2179	*	V1:----- V2:invalid PC='-' NZ='â€‘'	V1_sign=- CC=-
				2180	*	???? test without exceptions?	
				2181			
				2182			
				2183	*	V1: zero V2: positive PC='0' NZ='0'	V1_sign=C CC=0
				2184		VRI_G VPSOP, 159, 132, 1, 0	nz=0 pc=0
00002558				2185+	DS	OFD	
00002558		00002558		2186+	USING	*,R5	base for test data and test routine
00002558	00002578			2187+T50	DC	A(X50)	address of test routine
0000255C	0032			2188+	DC	H' 50'	test number
0000255E	00			2189+	DC	X' 00'	
0000255F	9F			2190+	DC	HL1' 159'	i3
00002560	84			2191+	DC	HL1' 132'	i4
00002561	01			2192+	DC	HL1' 1'	m5
00002562	00			2193+	DC	HL1' 0'	cc
00002563	07			2194+	DC	HL1' 7'	cc failed mask
00002564	000025AC			2195+V2_50	DC	A(RE50+16)	address of v2: 16-byte packed decimal
00002568	E5D7E2D6 D7404040			2196+	DC	CL8' VPSOP'	instruction name
00002570	00000010			2197+	DC	A(16)	result length
00002574	0000259C			2198+REA50	DC	A(RE50)	result address
				2199+*			INSTRUCTION UNDER TEST ROUTINE
00002578				2200+X50	DS	OF	
00002578	E320 500C 0014		00002564	2201+	LGF	R2, V2_50	get v2
0000257E	E722 0000 0006		00000000	2202+	VL	V2, 0(R2)	
00002584	E612 8419 F05B			2203+	VPSOP	V1, V2, 159, 132, 1	test instruction
0000258A	E710 8F10 000E		00001110	2204+	VST	V1, V10UTPUT	save result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002590	B98D 0020			2205+	EPSW	R2, R0	extract psw
00002594	5020 8EF4		000010F4	2206+	ST	R2, CCPSW	to save CC
00002598	07FB			2207+	BR	R11	return
0000259C				2208+RE50	DC	0F	
0000259C				2209+	DROP	R5	
0000259C	00000000 00000000			2210	DC	XL16' 00000000000000000000000000000000C'	V1
000025A4	00000000 0000000C						
000025AC	00000000 00000000			2211	DC	XL16' 00000000000000000000000000000000A'	V2
000025B4	00000000 0000000A						
				2212			
				2213 *	V1: zero	V2: positive	PC=' 1' NZ=' 0' V1_sign=F CC=0
				2214	VRI_G	VPSOP, 159, 134, 1, 0	nz=0 pc=1
000025C0				2215+	DS	0FD	
000025C0		000025C0		2216+	USING	*, R5	base for test data and test routine
000025C0	000025E0			2217+T51	DC	A(X51)	address of test routine
000025C4	0033			2218+	DC	H' 51'	test number
000025C6	00			2219+	DC	X' 00'	
000025C7	9F			2220+	DC	HL1' 159'	i3
000025C8	86			2221+	DC	HL1' 134'	i4
000025C9	01			2222+	DC	HL1' 1'	m5
000025CA	00			2223+	DC	HL1' 0'	cc
000025CB	07			2224+	DC	HL1' 7'	cc failed mask
000025CC	00002614			2225+V2_51	DC	A(RE51+16)	address of v2: 16-byte packed decimal
000025D0	E5D7E2D6 D7404040			2226+	DC	CL8' VPSOP'	instruction name
000025D8	00000010			2227+	DC	A(16)	result length
000025DC	00002604			2228+REA51	DC	A(RE51)	result address
				2229+*			INSTRUCTION UNDER TEST ROUTINE
000025E0				2230+X51	DS	0F	
000025E0	E320 500C 0014		000025CC	2231+	LGF	R2, V2_51	get v2
000025E6	E722 0000 0006		00000000	2232+	VL	V2, 0(R2)	
000025EC	E612 8619 F05B			2233+	VPSOP	V1, V2, 159, 134, 1	test instruction
000025F2	E710 8F10 000E		00001110	2234+	VST	V1, V10UTPUT	save result
000025F8	B98D 0020			2235+	EPSW	R2, R0	extract psw
000025FC	5020 8EF4		000010F4	2236+	ST	R2, CCPSW	to save CC
00002600	07FB			2237+	BR	R11	return
00002604				2238+RE51	DC	0F	
00002604				2239+	DROP	R5	
00002604	00000000 00000000			2240	DC	XL16' 00000000000000000000000000000000F'	V1
0000260C	00000000 0000000F						
00002614	00000000 00000000			2241	DC	XL16' 00000000000000000000000000000000A'	V2
0000261C	00000000 0000000A						
				2242			
				2243 *	V1: zero	V2: positive	PC=' - ' NZ=' 1' V1_sign=D CC=0
				2244	VRI_G	VPSOP, 159, 196, 1, 0	nz=1 pc=0
00002628				2245+	DS	0FD	
00002628		00002628		2246+	USING	*, R5	base for test data and test routine
00002628	00002648			2247+T52	DC	A(X52)	address of test routine
0000262C	0034			2248+	DC	H' 52'	test number
0000262E	00			2249+	DC	X' 00'	
0000262F	9F			2250+	DC	HL1' 159'	i3
00002630	C4			2251+	DC	HL1' 196'	i4
00002631	01			2252+	DC	HL1' 1'	m5
00002632	00			2253+	DC	HL1' 0'	cc
00002633	07			2254+	DC	HL1' 7'	cc failed mask
00002634	0000267C			2255+V2_52	DC	A(RE52+16)	address of v2: 16-byte packed decimal
00002638	E5D7E2D6 D7404040			2256+	DC	CL8' VPSOP'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002640	00000010			2257+	DC	A(16)	result length
00002644	0000266C			2258+REA52	DC	A(RE52)	result address
				2259+*			INSTRUCTION UNDER TEST ROUTINE
00002648				2260+X52	DS	0F	
00002648	E320 500C 0014		00002634	2261+	LGF	R2, V2_52	get v2
0000264E	E722 0000 0006		00000000	2262+	VL	V2, 0(R2)	
00002654	E612 C419 F05B			2263+	VPSOP	V1, V2, 159, 196, 1	test instruction
0000265A	E710 8F10 000E		00001110	2264+	VST	V1, V10UTPUT	save result
00002660	B98D 0020			2265+	EPSW	R2, R0	exptract psw
00002664	5020 8EF4		000010F4	2266+	ST	R2, CCPSW	to save CC
00002668	07FB			2267+	BR	R11	return
0000266C				2268+RE52	DC	0F	
0000266C				2269+	DROP	R5	
0000266C	00000000 00000000			2270	DC	XL16' 00000000000000000000000000000000D'	V1
00002674	00000000 0000000D						
0000267C	00000000 00000000			2271	DC	XL16' 00000000000000000000000000000000A'	V2
00002684	00000000 0000000A						
				2272			
				2273	VRI_G	VPSOP, 159, 198, 1, 0	nz=1 pc=1
00002690				2274+	DS	0FD	
00002690		00002690		2275+	USING	*, R5	base for test data and test routine
00002690	000026B0			2276+T53	DC	A(X53)	address of test routine
00002694	0035			2277+	DC	H' 53'	test number
00002696	00			2278+	DC	X' 00'	
00002697	9F			2279+	DC	HL1' 159'	i3
00002698	C6			2280+	DC	HL1' 198'	i4
00002699	01			2281+	DC	HL1' 1'	m5
0000269A	00			2282+	DC	HL1' 0'	cc
0000269B	07			2283+	DC	HL1' 7'	cc failed mask
0000269C	000026E4			2284+V2_53	DC	A(RE53+16)	address of v2: 16-byte packed decimal
000026A0	E5D7E2D6 D7404040			2285+	DC	CL8' VPSOP'	instruction name
000026A8	00000010			2286+	DC	A(16)	result length
000026AC	000026D4			2287+REA53	DC	A(RE53)	result address
				2288+*			INSTRUCTION UNDER TEST ROUTINE
000026B0				2289+X53	DS	0F	
000026B0	E320 500C 0014		0000269C	2290+	LGF	R2, V2_53	get v2
000026B6	E722 0000 0006		00000000	2291+	VL	V2, 0(R2)	
000026BC	E612 C619 F05B			2292+	VPSOP	V1, V2, 159, 198, 1	test instruction
000026C2	E710 8F10 000E		00001110	2293+	VST	V1, V10UTPUT	save result
000026C8	B98D 0020			2294+	EPSW	R2, R0	exptract psw
000026CC	5020 8EF4		000010F4	2295+	ST	R2, CCPSW	to save CC
000026D0	07FB			2296+	BR	R11	return
000026D4				2297+RE53	DC	0F	
000026D4				2298+	DROP	R5	
000026D4	00000000 00000000			2299	DC	XL16' 00000000000000000000000000000000D'	V1
000026DC	00000000 0000000D						
000026E4	00000000 00000000			2300	DC	XL16' 00000000000000000000000000000000C'	V2
000026EC	00000000 0000000C						
				2301			
				2302 * V1: zero V2: negative PC=' 0' NZ=' - ' V1_sign=C CC=0			
				2303	VRI_G	VPSOP, 159, 132, 1, 0	nz=0 pc=0
000026F8				2304+	DS	0FD	
000026F8		000026F8		2305+	USING	*, R5	base for test data and test routine
000026F8	00002718			2306+T54	DC	A(X54)	address of test routine
000026FC	0036			2307+	DC	H' 54'	test number
000026FE	00			2308+	DC	X' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000026FF	9F			2309+	DC	HL1' 159'	i3
00002700	84			2310+	DC	HL1' 132'	i4
00002701	01			2311+	DC	HL1' 1'	m5
00002702	00			2312+	DC	HL1' 0'	cc
00002703	07			2313+	DC	HL1' 7'	cc failed mask
00002704	0000274C			2314+V2_54	DC	A(RE54+16)	address of v2: 16-byte packed decimal
00002708	E5D7E2D6 D7404040			2315+	DC	CL8' VPSOP'	instruction name
00002710	00000010			2316+	DC	A(16)	result length
00002714	0000273C			2317+REA54	DC	A(RE54)	result address
				2318+*			INSTRUCTION UNDER TEST ROUTINE
00002718				2319+X54	DS	0F	
00002718	E320 500C 0014		00002704	2320+	LGF	R2, V2_54	get v2
0000271E	E722 0000 0006		00000000	2321+	VL	V2, 0(R2)	
00002724	E612 8419 F05B			2322+	VPSOP	V1, V2, 159, 132, 1	test instruction
0000272A	E710 8F10 000E		00001110	2323+	VST	V1, V10UTPUT	save result
00002730	B98D 0020			2324+	EPSW	R2, R0	exptract psw
00002734	5020 8EF4		000010F4	2325+	ST	R2, CCPSW	to save CC
00002738	07FB			2326+	BR	R11	return
0000273C				2327+RE54	DC	0F	
0000273C				2328+	DROP	R5	
0000273C	00000000 00000000			2329	DC	XL16' 00000000000000000000000000000000C'	V1
00002744	00000000 0000000C						
0000274C	00000000 00000000			2330	DC	XL16' 00000000000000000000000000000000D'	V2
00002754	00000000 0000000D						
				2331			
				2332	VRI_G	VPSOP, 159, 196, 1, 0	nz=1 pc=0
00002760				2333+	DS	0FD	
00002760		00002760		2334+	USING	*, R5	base for test data and test routine
00002760	00002780			2335+T55	DC	A(X55)	address of test routine
00002764	0037			2336+	DC	H' 55'	test number
00002766	00			2337+	DC	X' 00'	
00002767	9F			2338+	DC	HL1' 159'	i3
00002768	C4			2339+	DC	HL1' 196'	i4
00002769	01			2340+	DC	HL1' 1'	m5
0000276A	00			2341+	DC	HL1' 0'	cc
0000276B	07			2342+	DC	HL1' 7'	cc failed mask
0000276C	000027B4			2343+V2_55	DC	A(RE55+16)	address of v2: 16-byte packed decimal
00002770	E5D7E2D6 D7404040			2344+	DC	CL8' VPSOP'	instruction name
00002778	00000010			2345+	DC	A(16)	result length
0000277C	000027A4			2346+REA55	DC	A(RE55)	result address
				2347+*			INSTRUCTION UNDER TEST ROUTINE
00002780				2348+X55	DS	0F	
00002780	E320 500C 0014		0000276C	2349+	LGF	R2, V2_55	get v2
00002786	E722 0000 0006		00000000	2350+	VL	V2, 0(R2)	
0000278C	E612 C419 F05B			2351+	VPSOP	V1, V2, 159, 196, 1	test instruction
00002792	E710 8F10 000E		00001110	2352+	VST	V1, V10UTPUT	save result
00002798	B98D 0020			2353+	EPSW	R2, R0	exptract psw
0000279C	5020 8EF4		000010F4	2354+	ST	R2, CCPSW	to save CC
000027A0	07FB			2355+	BR	R11	return
000027A4				2356+RE55	DC	0F	
000027A4				2357+	DROP	R5	
000027A4	00000000 00000000			2358	DC	XL16' 00000000000000000000000000000000C'	V1
000027AC	00000000 0000000C						
000027B4	00000000 00000000			2359	DC	XL16' 00000000000000000000000000000000B'	V2
000027BC	00000000 0000000B						
				2360			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				2361 * V1: zero V2: negative PC='1' NZ='-' V1_sign=F CC=0	
				2362 VRI_G VPSOP, 159, 134, 1, 0 nz=0 pc=1	
000027C8				2363+ DS OFD	
000027C8		000027C8		2364+ USING *, R5	base for test data and test routine
000027C8	000027E8			2365+T56 DC A(X56)	address of test routine
000027CC	0038			2366+ DC H' 56'	test number
000027CE	00			2367+ DC X' 00'	
000027CF	9F			2368+ DC HL1' 159'	i3
000027D0	86			2369+ DC HL1' 134'	i4
000027D1	01			2370+ DC HL1' 1'	m5
000027D2	00			2371+ DC HL1' 0'	cc
000027D3	07			2372+ DC HL1' 7'	cc failed mask
000027D4	0000281C			2373+V2_56 DC A(RE56+16)	address of v2: 16-byte packed decimal
000027D8	E5D7E2D6 D7404040			2374+ DC CL8' VPSOP'	instruction name
000027E0	00000010			2375+ DC A(16)	result length
000027E4	0000280C			2376+REA56 DC A(RE56)	result address
				2377+*	INSTRUCTION UNDER TEST ROUTINE
000027E8				2378+X56 DS OF	
000027E8	E320 500C 0014		000027D4	2379+ LGF R2, V2_56	get v2
000027EE	E722 0000 0006		00000000	2380+ VL V2, 0(R2)	
000027F4	E612 8619 F05B			2381+ VPSOP V1, V2, 159, 134, 1	test instruction
000027FA	E710 8F10 000E		00001110	2382+ VST V1, V10UTPUT	save result
00002800	B98D 0020			2383+ EPSW R2, R0	exptract psw
00002804	5020 8EF4		000010F4	2384+ ST R2, CCPSW	to save CC
00002808	07FB			2385+ BR R11	return
0000280C				2386+RE56 DC OF	
0000280C				2387+ DROP R5	
0000280C	00000000 00000000			2388 DC XL16' 00000000000000000000000000000000F'	V1
00002814	00000000 0000000F				
0000281C	00000000 00000000			2389 DC XL16' 00000000000000000000000000000000D'	V2
00002824	00000000 0000000D				
				2390	
				2391 VRI_G VPSOP, 159, 198, 1, 0 nz=1 pc=1	
00002830				2392+ DS OFD	
00002830		00002830		2393+ USING *, R5	base for test data and test routine
00002830	00002850			2394+T57 DC A(X57)	address of test routine
00002834	0039			2395+ DC H' 57'	test number
00002836	00			2396+ DC X' 00'	
00002837	9F			2397+ DC HL1' 159'	i3
00002838	C6			2398+ DC HL1' 198'	i4
00002839	01			2399+ DC HL1' 1'	m5
0000283A	00			2400+ DC HL1' 0'	cc
0000283B	07			2401+ DC HL1' 7'	cc failed mask
0000283C	00002884			2402+V2_57 DC A(RE57+16)	address of v2: 16-byte packed decimal
00002840	E5D7E2D6 D7404040			2403+ DC CL8' VPSOP'	instruction name
00002848	00000010			2404+ DC A(16)	result length
0000284C	00002874			2405+REA57 DC A(RE57)	result address
				2406+*	INSTRUCTION UNDER TEST ROUTINE
00002850				2407+X57 DS OF	
00002850	E320 500C 0014		0000283C	2408+ LGF R2, V2_57	get v2
00002856	E722 0000 0006		00000000	2409+ VL V2, 0(R2)	
0000285C	E612 C619 F05B			2410+ VPSOP V1, V2, 159, 198, 1	test instruction
00002862	E710 8F10 000E		00001110	2411+ VST V1, V10UTPUT	save result
00002868	B98D 0020			2412+ EPSW R2, R0	exptract psw
0000286C	5020 8EF4		000010F4	2413+ ST R2, CCPSW	to save CC
00002870	07FB			2414+ BR R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002874				2415+RE57	DC	0F
00002874				2416+	DROP	R5
00002874	00000000 00000000			2417	DC	XL16' 00000000000000000000000000000000F' V1
0000287C	00000000 0000000F					
00002884	00000000 00000000			2418	DC	XL16' 00000000000000000000000000000000B' V2
0000288C	00000000 0000000B					
				2419		
				2420 *		
				2421 * SC=10 (force positive): nv=1 to avoid data exceptions		
				2422 *		
				2423		
				2424 * V1: nonzero V2: ----- PC=' 0' NZ=' â€‘' V1_sign=C CC=2		
				2425 * V2: positive		
				2426 VRI_G VPSOP, 159, 136, 1, 2 nz=0 pc=0		
00002898				2427+	DS	0FD
00002898		00002898		2428+	USING	*, R5
00002898	000028B8			2429+T58	DC	A(X58)
0000289C	003A			2430+	DC	H' 58'
0000289E	00			2431+	DC	X' 00'
0000289F	9F			2432+	DC	HL1' 159'
000028A0	88			2433+	DC	HL1' 136'
000028A1	01			2434+	DC	HL1' 1'
000028A2	02			2435+	DC	HL1' 2'
000028A3	0D			2436+	DC	HL1' 13'
000028A4	000028EC			2437+V2_58	DC	A(RE58+16)
000028A8	E5D7E2D6 D7404040			2438+	DC	CL8' VPSOP'
000028B0	00000010			2439+	DC	A(16)
000028B4	000028DC			2440+REA58	DC	A(RE58)
				2441+*		INSTRUCTION UNDER TEST ROUTINE
000028B8				2442+X58	DS	0F
000028B8	E320 500C 0014		000028A4	2443+	LGF	R2, V2_58
000028BE	E722 0000 0006		00000000	2444+	VL	V2, 0(R2)
000028C4	E612 8819 F05B			2445+	VPSOP	V1, V2, 159, 136, 1
000028CA	E710 8F10 000E		00001110	2446+	VST	V1, V10UTPUT
000028D0	B98D 0020			2447+	EPSW	R2, R0
000028D4	5020 8EF4		000010F4	2448+	ST	R2, CCPSW
000028D8	07FB			2449+	BR	R11
000028DC				2450+RE58	DC	0F
000028DC				2451+	DROP	R5
000028DC	00000000 00000000			2452	DC	XL16' 000000000000000000000000220000000C' V1
000028E4	00000022 0000000C					
000028EC	00000000 00000000			2453	DC	XL16' 000000000000000000000000220000000A' V2
000028F4	00000022 0000000A					
				2454		
				2455	VRI_G	VPSOP, 159, 200, 1, 2
00002900				2456+	DS	0FD
00002900		00002900		2457+	USING	*, R5
00002900	00002920			2458+T59	DC	A(X59)
00002904	003B			2459+	DC	H' 59'
00002906	00			2460+	DC	X' 00'
00002907	9F			2461+	DC	HL1' 159'
00002908	C8			2462+	DC	HL1' 200'
00002909	01			2463+	DC	HL1' 1'
0000290A	02			2464+	DC	HL1' 2'
0000290B	0D			2465+	DC	HL1' 13'
0000290C	00002954			2466+V2_59	DC	A(RE59+16)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002910	E5D7E2D6 D7404040			2467+	DC	CL8' VPSOP'	instruction name
00002918	00000010			2468+	DC	A(16)	result length
0000291C	00002944			2469+REA59	DC	A(RE59)	result address
				2470+*			INSTRUCTION UNDER TEST ROUTINE
00002920				2471+X59	DS	0F	
00002920	E320 500C 0014		0000290C	2472+	LGF	R2, V2_59	get v2
00002926	E722 0000 0006		00000000	2473+	VL	V2, 0(R2)	
0000292C	E612 C819 F05B			2474+	VPSOP	V1, V2, 159, 200, 1	test instruction
00002932	E710 8F10 000E		00001110	2475+	VST	V1, V10UTPUT	save result
00002938	B98D 0020			2476+	EPSW	R2, R0	exptract psw
0000293C	5020 8EF4		000010F4	2477+	ST	R2, CCPSW	to save CC
00002940	07FB			2478+	BR	R11	return
00002944				2479+RE59	DC	0F	
00002944				2480+	DROP	R5	
00002944	00000000 00000000			2481	DC	XL16' 000000000000000000000000220000000C'	V1
0000294C	00000022 0000000C						
00002954	00000000 00000000			2482	DC	XL16' 000000000000000000000000220000000A'	V2
0000295C	00000022 0000000A						
				2483 * V2: negative			
				2484	VRI_G	VPSOP, 159, 136, 1, 2	nz=0 pc=0
00002968				2485+	DS	0FD	
00002968		00002968		2486+	USING	*, R5	base for test data and test routine
00002968	00002988			2487+T60	DC	A(X60)	address of test routine
0000296C	003C			2488+	DC	H' 60'	test number
0000296E	00			2489+	DC	X' 00'	
0000296F	9F			2490+	DC	HL1' 159'	i3
00002970	88			2491+	DC	HL1' 136'	i4
00002971	01			2492+	DC	HL1' 1'	m5
00002972	02			2493+	DC	HL1' 2'	cc
00002973	0D			2494+	DC	HL1' 13'	cc failed mask
00002974	000029BC			2495+V2_60	DC	A(RE60+16)	address of v2: 16-byte packed decimal
00002978	E5D7E2D6 D7404040			2496+	DC	CL8' VPSOP'	instruction name
00002980	00000010			2497+	DC	A(16)	result length
00002984	000029AC			2498+REA60	DC	A(RE60)	result address
				2499+*			INSTRUCTION UNDER TEST ROUTINE
00002988				2500+X60	DS	0F	
00002988	E320 500C 0014		00002974	2501+	LGF	R2, V2_60	get v2
0000298E	E722 0000 0006		00000000	2502+	VL	V2, 0(R2)	
00002994	E612 8819 F05B			2503+	VPSOP	V1, V2, 159, 136, 1	test instruction
0000299A	E710 8F10 000E		00001110	2504+	VST	V1, V10UTPUT	save result
000029A0	B98D 0020			2505+	EPSW	R2, R0	exptract psw
000029A4	5020 8EF4		000010F4	2506+	ST	R2, CCPSW	to save CC
000029A8	07FB			2507+	BR	R11	return
000029AC				2508+RE60	DC	0F	
000029AC				2509+	DROP	R5	
000029AC	00000000 00000000			2510	DC	XL16' 000000000000000000000000220000000C'	V1
000029B4	00000022 0000000C						
000029BC	00000000 00000000			2511	DC	XL16' 000000000000000000000000220000000D'	V2
000029C4	00000022 0000000D						
				2512			
				2513	VRI_G	VPSOP, 159, 200, 1, 2	nz=1 pc=0
000029D0				2514+	DS	0FD	
000029D0		000029D0		2515+	USING	*, R5	base for test data and test routine
000029D0	000029F0			2516+T61	DC	A(X61)	address of test routine
000029D4	003D			2517+	DC	H' 61'	test number
000029D6	00			2518+	DC	X' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002A94	00000022 0000000A			2572			
				2573	VRI_G	VPSOP, 159, 202, 1, 2	nz=1 pc=1
00002AA0				2574+	DS	OFD	
00002AA0		00002AA0		2575+	USING	*, R5	base for test data and test routine
00002AA0	00002AC0			2576+T63	DC	A(X63)	address of test routine
00002AA4	003F			2577+	DC	H' 63'	test number
00002AA6	00			2578+	DC	X' 00'	
00002AA7	9F			2579+	DC	HL1' 159'	i3
00002AA8	CA			2580+	DC	HL1' 202'	i4
00002AA9	01			2581+	DC	HL1' 1'	m5
00002AAA	02			2582+	DC	HL1' 2'	cc
00002AAB	0D			2583+	DC	HL1' 13'	cc failed mask
00002AAC	00002AF4			2584+V2_63	DC	A(RE63+16)	address of v2: 16-byte packed decimal
00002AB0	E5D7E2D6 D7404040			2585+	DC	CL8' VPSOP'	instruction name
00002AB8	00000010			2586+	DC	A(16)	result length
00002ABC	00002AE4			2587+REA63	DC	A(RE63)	result address
				2588+*			INSTRUCTION UNDER TEST ROUTINE
00002AC0				2589+X63	DS	OF	
00002AC0	E320 500C 0014		00002AAC	2590+	LGF	R2, V2_63	get v2
00002AC6	E722 0000 0006		00000000	2591+	VL	V2, 0(R2)	
00002ACC	E612 CA19 F05B			2592+	VPSOP	V1, V2, 159, 202, 1	test instruction
00002AD2	E710 8F10 000E		00001110	2593+	VST	V1, V10UTPUT	save result
00002AD8	B98D 0020			2594+	EPSW	R2, R0	exptract psw
00002ADC	5020 8EF4		000010F4	2595+	ST	R2, CCPSW	to save CC
00002AE0	07FB			2596+	BR	R11	return
00002AE4				2597+RE63	DC	OF	
00002AE4				2598+	DROP	R5	
00002AE4	00000000 00000000			2599	DC	XL16' 000000000000000000000000220000000F'	V1
00002AEC	00000022 0000000F						
00002AF4	00000000 00000000			2600	DC	XL16' 000000000000000000000000220000000A'	V2
00002AFC	00000022 0000000A						
				2601 * V2: negative			
				2602	VRI_G	VPSOP, 159, 138, 1, 2	nz=0 pc=1
00002B08				2603+	DS	OFD	
00002B08		00002B08		2604+	USING	*, R5	base for test data and test routine
00002B08	00002B28			2605+T64	DC	A(X64)	address of test routine
00002B0C	0040			2606+	DC	H' 64'	test number
00002B0E	00			2607+	DC	X' 00'	
00002B0F	9F			2608+	DC	HL1' 159'	i3
00002B10	8A			2609+	DC	HL1' 138'	i4
00002B11	01			2610+	DC	HL1' 1'	m5
00002B12	02			2611+	DC	HL1' 2'	cc
00002B13	0D			2612+	DC	HL1' 13'	cc failed mask
00002B14	00002B5C			2613+V2_64	DC	A(RE64+16)	address of v2: 16-byte packed decimal
00002B18	E5D7E2D6 D7404040			2614+	DC	CL8' VPSOP'	instruction name
00002B20	00000010			2615+	DC	A(16)	result length
00002B24	00002B4C			2616+REA64	DC	A(RE64)	result address
				2617+*			INSTRUCTION UNDER TEST ROUTINE
00002B28				2618+X64	DS	OF	
00002B28	E320 500C 0014		00002B14	2619+	LGF	R2, V2_64	get v2
00002B2E	E722 0000 0006		00000000	2620+	VL	V2, 0(R2)	
00002B34	E612 8A19 F05B			2621+	VPSOP	V1, V2, 159, 138, 1	test instruction
00002B3A	E710 8F10 000E		00001110	2622+	VST	V1, V10UTPUT	save result
00002B40	B98D 0020			2623+	EPSW	R2, R0	exptract psw
00002B44	5020 8EF4		000010F4	2624+	ST	R2, CCPSW	to save CC

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00002B48	07FB			2625+	BR	R11	return	
00002B4C				2626+RE64	DC	0F		
00002B4C				2627+	DROP	R5		
00002B4C	00000000 00000000			2628	DC	XL16' 000000000000000000000000220000000F'	V1	
00002B54	00000022 0000000F							
00002B5C	00000000 00000000			2629	DC	XL16' 000000000000000000000000220000000D'	V2	
00002B64	00000022 0000000D							
				2630				
00002B70				2631	VRI_G	VPSOP, 159, 202, 1, 2	nz=1 pc=1	
00002B70		00002B70		2632+	DS	0FD		
00002B70	00002B90			2633+	USING	*, R5	base for test data and test routine	
00002B74	0041			2634+T65	DC	A(X65)	address of test routine	
00002B76	00			2635+	DC	H' 65'	test number	
00002B76	00			2636+	DC	X' 00'		
00002B77	9F			2637+	DC	HL1' 159'	i3	
00002B78	CA			2638+	DC	HL1' 202'	i4	
00002B79	01			2639+	DC	HL1' 1'	m5	
00002B7A	02			2640+	DC	HL1' 2'	cc	
00002B7B	0D			2641+	DC	HL1' 13'	cc failed mask	
00002B7C	00002BC4			2642+V2_65	DC	A(RE65+16)	address of v2: 16-byte packed decimal	
00002B80	E5D7E2D6 D7404040			2643+	DC	CL8' VPSOP'	instruction name	
00002B88	00000010			2644+	DC	A(16)	result length	
00002B8C	00002BB4			2645+REA65	DC	A(RE65)	result address	
				2646+*			INSTRUCTION UNDER TEST ROUTINE	
00002B90				2647+X65	DS	0F		
00002B90	E320 500C 0014		00002B7C	2648+	LGF	R2, V2_65	get v2	
00002B96	E722 0000 0006		00000000	2649+	VL	V2, 0(R2)		
00002B9C	E612 CA19 F05B			2650+	VPSOP	V1, V2, 159, 202, 1	test instruction	
00002BA2	E710 8F10 000E		00001110	2651+	VST	V1, V10UTPUT	save result	
00002BA8	B98D 0020			2652+	EPSW	R2, R0	exptract psw	
00002BAC	5020 8EF4		000010F4	2653+	ST	R2, CCPSW	to save CC	
00002BB0	07FB			2654+	BR	R11	return	
00002BB4				2655+RE65	DC	0F		
00002BB4				2656+	DROP	R5		
00002BB4	00000000 00000000			2657	DC	XL16' 000000000000000000000000220000000F'	V1	
00002BBC	00000022 0000000F							
00002BC4	00000000 00000000			2658	DC	XL16' 000000000000000000000000220000000B'	V2	
00002BCC	00000022 0000000B							
				2659				
				2660	* V1: zero V2: - - - - - PC=' 0' NZ=' â€‘' V1_sign=C CC=0			
				2661	* V2: positive			
				2662	VRI_G	VPSOP, 159, 136, 1, 0	nz=0 pc=0	
00002BD8				2663+	DS	0FD		
00002BD8		00002BD8		2664+	USING	*, R5	base for test data and test routine	
00002BD8	00002BF8			2665+T66	DC	A(X66)	address of test routine	
00002BDC	0042			2666+	DC	H' 66'	test number	
00002BDE	00			2667+	DC	X' 00'		
00002BDF	9F			2668+	DC	HL1' 159'	i3	
00002BE0	88			2669+	DC	HL1' 136'	i4	
00002BE1	01			2670+	DC	HL1' 1'	m5	
00002BE2	00			2671+	DC	HL1' 0'	cc	
00002BE3	07			2672+	DC	HL1' 7'	cc failed mask	
00002BE4	00002C2C			2673+V2_66	DC	A(RE66+16)	address of v2: 16-byte packed decimal	
00002BE8	E5D7E2D6 D7404040			2674+	DC	CL8' VPSOP'	instruction name	
00002BF0	00000010			2675+	DC	A(16)	result length	
00002BF4	00002C1C			2676+REA66	DC	A(RE66)	result address	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				2677+*	INSTRUCTION UNDER TEST ROUTINE		
00002BF8				2678+X66	DS	0F	
00002BF8	E320 500C 0014		00002BE4	2679+	LGF	R2, V2_66	get v2
00002BFE	E722 0000 0006		00000000	2680+	VL	V2, 0(R2)	
00002C04	E612 8819 F05B			2681+	VPSOP	V1, V2, 159, 136, 1	test instruction
00002C0A	E710 8F10 000E		00001110	2682+	VST	V1, V10UTPUT	save result
00002C10	B98D 0020			2683+	EPSW	R2, R0	exptract psw
00002C14	5020 8EF4		000010F4	2684+	ST	R2, CCPSW	to save CC
00002C18	07FB			2685+	BR	R11	return
00002C1C				2686+RE66	DC	0F	
00002C1C				2687+	DROP	R5	
00002C1C	00000000 00000000			2688	DC	XL16' 00000000000000000000000000000000C'	V1
00002C24	00000000 0000000C						
00002C2C	00000000 00000000			2689	DC	XL16' 00000000000000000000000000000000A'	V2
00002C34	00000000 0000000A						
				2690			
00002C40				2691	VRI_G	VPSOP, 159, 200, 1, 0	nz=1 pc=0
00002C40		00002C40		2692+	DS	0FD	
00002C40	00002C60			2693+	USING	*, R5	base for test data and test routine
00002C44	0043			2694+T67	DC	A(X67)	address of test routine
00002C46	00			2695+	DC	H' 67'	test number
00002C47	9F			2696+	DC	X' 00'	
00002C48	C8			2697+	DC	HL1' 159'	i3
00002C48	C8			2698+	DC	HL1' 200'	i4
00002C49	01			2699+	DC	HL1' 1'	m5
00002C4A	00			2700+	DC	HL1' 0'	cc
00002C4B	07			2701+	DC	HL1' 7'	cc failed mask
00002C4C	00002C94			2702+V2_67	DC	A(RE67+16)	address of v2: 16-byte packed decimal
00002C50	E5D7E2D6 D7404040			2703+	DC	CL8' VPSOP'	instruction name
00002C58	00000010			2704+	DC	A(16)	result length
00002C5C	00002C84			2705+REA67	DC	A(RE67)	result address
				2706+*	INSTRUCTION UNDER TEST ROUTINE		
00002C60				2707+X67	DS	0F	
00002C60	E320 500C 0014		00002C4C	2708+	LGF	R2, V2_67	get v2
00002C66	E722 0000 0006		00000000	2709+	VL	V2, 0(R2)	
00002C6C	E612 C819 F05B			2710+	VPSOP	V1, V2, 159, 200, 1	test instruction
00002C72	E710 8F10 000E		00001110	2711+	VST	V1, V10UTPUT	save result
00002C78	B98D 0020			2712+	EPSW	R2, R0	exptract psw
00002C7C	5020 8EF4		000010F4	2713+	ST	R2, CCPSW	to save CC
00002C80	07FB			2714+	BR	R11	return
00002C84				2715+RE67	DC	0F	
00002C84				2716+	DROP	R5	
00002C84	00000000 00000000			2717	DC	XL16' 00000000000000000000000000000000C'	V1
00002C8C	00000000 0000000C						
00002C94	00000000 00000000			2718	DC	XL16' 00000000000000000000000000000000A'	V2
00002C9C	00000000 0000000A						
				2719 * V2: negative			
00002CA8				2720	VRI_G	VPSOP, 159, 136, 1, 0	nz=0 pc=0
00002CA8		00002CA8		2721+	DS	0FD	
00002CA8	00002CC8			2722+	USING	*, R5	base for test data and test routine
00002CAC	0044			2723+T68	DC	A(X68)	address of test routine
00002CAE	00			2724+	DC	H' 68'	test number
00002CAF	9F			2725+	DC	X' 00'	
00002CB0	88			2726+	DC	HL1' 159'	i3
00002CB1	01			2727+	DC	HL1' 136'	i4
				2728+	DC	HL1' 1'	m5

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002CB2	00			2729+	DC	HL1' 0'	cc
00002CB3	07			2730+	DC	HL1' 7'	cc failed mask
00002CB4	00002CFC			2731+V2_68	DC	A(RE68+16)	address of v2: 16-byte packed decimal
00002CB8	E5D7E2D6 D7404040			2732+	DC	CL8' VPSOP'	instruction name
00002CC0	00000010			2733+	DC	A(16)	result length
00002CC4	00002CEC			2734+REA68	DC	A(RE68)	result address
				2735+*			INSTRUCTION UNDER TEST ROUTINE
00002CC8				2736+X68	DS	0F	
00002CC8	E320 500C 0014		00002CB4	2737+	LGF	R2, V2_68	get v2
00002CCE	E722 0000 0006		00000000	2738+	VL	V2, 0(R2)	
00002CD4	E612 8819 F05B			2739+	VPSOP	V1, V2, 159, 136, 1	test instruction
00002CDA	E710 8F10 000E		00001110	2740+	VST	V1, V10UTPUT	save result
00002CE0	B98D 0020			2741+	EPSW	R2, R0	exptract psw
00002CE4	5020 8EF4		000010F4	2742+	ST	R2, CCPSW	to save CC
00002CE8	07FB			2743+	BR	R11	return
00002CEC				2744+RE68	DC	0F	
00002CEC				2745+	DROP	R5	
00002CEC	00000000 00000000			2746	DC	XL16' 00000000000000000000000000000000C'	V1
00002CF4	00000000 0000000C						
00002CFC	00000000 00000000			2747	DC	XL16' 00000000000000000000000000000000D'	V2
00002D04	00000000 0000000D						
				2748			
				2749	VRI_G	VPSOP, 159, 200, 1, 0	nz=1 pc=0
00002D10				2750+	DS	0FD	
00002D10		00002D10		2751+	USING	*, R5	base for test data and test routine
00002D10	00002D30			2752+T69	DC	A(X69)	address of test routine
00002D14	0045			2753+	DC	H' 69'	test number
00002D16	00			2754+	DC	X' 00'	
00002D17	9F			2755+	DC	HL1' 159'	i3
00002D18	C8			2756+	DC	HL1' 200'	i4
00002D19	01			2757+	DC	HL1' 1'	m5
00002D1A	00			2758+	DC	HL1' 0'	cc
00002D1B	07			2759+	DC	HL1' 7'	cc failed mask
00002D1C	00002D64			2760+V2_69	DC	A(RE69+16)	address of v2: 16-byte packed decimal
00002D20	E5D7E2D6 D7404040			2761+	DC	CL8' VPSOP'	instruction name
00002D28	00000010			2762+	DC	A(16)	result length
00002D2C	00002D54			2763+REA69	DC	A(RE69)	result address
				2764+*			INSTRUCTION UNDER TEST ROUTINE
00002D30				2765+X69	DS	0F	
00002D30	E320 500C 0014		00002D1C	2766+	LGF	R2, V2_69	get v2
00002D36	E722 0000 0006		00000000	2767+	VL	V2, 0(R2)	
00002D3C	E612 C819 F05B			2768+	VPSOP	V1, V2, 159, 200, 1	test instruction
00002D42	E710 8F10 000E		00001110	2769+	VST	V1, V10UTPUT	save result
00002D48	B98D 0020			2770+	EPSW	R2, R0	exptract psw
00002D4C	5020 8EF4		000010F4	2771+	ST	R2, CCPSW	to save CC
00002D50	07FB			2772+	BR	R11	return
00002D54				2773+RE69	DC	0F	
00002D54				2774+	DROP	R5	
00002D54	00000000 00000000			2775	DC	XL16' 00000000000000000000000000000000C'	V1
00002D5C	00000000 0000000C						
00002D64	00000000 00000000			2776	DC	XL16' 00000000000000000000000000000000B'	V2
00002D6C	00000000 0000000B						
				2777			
				2778 *	V1: zero	V2: - - - - -	PC=' 1' NZ=' â€‘' V1_sign=F CC=0
				2779 *	V2: positive		
				2780	VRI_G	VPSOP, 159, 138, 1, 0	nz=0 pc=1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002D78				2781+	DS	OFD	
00002D78		00002D78		2782+	USING	*, R5	base for test data and test routine
00002D78	00002D98			2783+T70	DC	A(X70)	address of test routine
00002D7C	0046			2784+	DC	H' 70'	test number
00002D7E	00			2785+	DC	X' 00'	
00002D7F	9F			2786+	DC	HL1' 159'	i3
00002D80	8A			2787+	DC	HL1' 138'	i4
00002D81	01			2788+	DC	HL1' 1'	m5
00002D82	00			2789+	DC	HL1' 0'	cc
00002D83	07			2790+	DC	HL1' 7'	cc failed mask
00002D84	00002DCC			2791+V2_70	DC	A(RE70+16)	address of v2: 16-byte packed decimal
00002D88	E5D7E2D6 D7404040			2792+	DC	CL8' VPSOP'	instruction name
00002D90	00000010			2793+	DC	A(16)	result length
00002D94	00002DBC			2794+REA70	DC	A(RE70)	result address
				2795+*			INSTRUCTION UNDER TEST ROUTINE
00002D98				2796+X70	DS	OF	
00002D98	E320 500C 0014		00002D84	2797+	LGF	R2, V2_70	get v2
00002D9E	E722 0000 0006		00000000	2798+	VL	V2, 0(R2)	
00002DA4	E612 8A19 F05B			2799+	VPSOP	V1, V2, 159, 138, 1	test instruction
00002DAA	E710 8F10 000E		00001110	2800+	VST	V1, V10UTPUT	save result
00002DB0	B98D 0020			2801+	EPSW	R2, R0	exptract psw
00002DB4	5020 8EF4		000010F4	2802+	ST	R2, CCPSW	to save CC
00002DB8	07FB			2803+	BR	R11	return
00002DBC				2804+RE70	DC	OF	
00002DBC				2805+	DROP	R5	
00002DBC	00000000 00000000			2806	DC	XL16' 00000000000000000000000000000000F'	V1
00002DC4	00000000 0000000F						
00002DCC	00000000 00000000			2807	DC	XL16' 00000000000000000000000000000000A'	V2
00002DD4	00000000 0000000A						
				2808			
				2809	VRI_G	VPSOP, 159, 202, 1, 0	nz=1 pc=1
00002DE0				2810+	DS	OFD	
00002DE0		00002DE0		2811+	USING	*, R5	base for test data and test routine
00002DE0	00002E00			2812+T71	DC	A(X71)	address of test routine
00002DE4	0047			2813+	DC	H' 71'	test number
00002DE6	00			2814+	DC	X' 00'	
00002DE7	9F			2815+	DC	HL1' 159'	i3
00002DE8	CA			2816+	DC	HL1' 202'	i4
00002DE9	01			2817+	DC	HL1' 1'	m5
00002DEA	00			2818+	DC	HL1' 0'	cc
00002DEB	07			2819+	DC	HL1' 7'	cc failed mask
00002DEC	00002E34			2820+V2_71	DC	A(RE71+16)	address of v2: 16-byte packed decimal
00002DF0	E5D7E2D6 D7404040			2821+	DC	CL8' VPSOP'	instruction name
00002DF8	00000010			2822+	DC	A(16)	result length
00002DFC	00002E24			2823+REA71	DC	A(RE71)	result address
				2824+*			INSTRUCTION UNDER TEST ROUTINE
00002E00				2825+X71	DS	OF	
00002E00	E320 500C 0014		00002DEC	2826+	LGF	R2, V2_71	get v2
00002E06	E722 0000 0006		00000000	2827+	VL	V2, 0(R2)	
00002E0C	E612 CA19 F05B			2828+	VPSOP	V1, V2, 159, 202, 1	test instruction
00002E12	E710 8F10 000E		00001110	2829+	VST	V1, V10UTPUT	save result
00002E18	B98D 0020			2830+	EPSW	R2, R0	exptract psw
00002E1C	5020 8EF4		000010F4	2831+	ST	R2, CCPSW	to save CC
00002E20	07FB			2832+	BR	R11	return
00002E24				2833+RE71	DC	OF	
00002E24				2834+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00002E24	00000000 00000000			2835	DC	XL16' 00000000000000000000000000000000F'	V1	
00002E2C	00000000 0000000F							
00002E34	00000000 00000000			2836	DC	XL16' 00000000000000000000000000000000A'	V2	
00002E3C	00000000 0000000A							
				2837 * V2: negative				
00002E48				2838	VRI_G	VPSOP, 159, 138, 1, 0	nz=0 pc=1	
00002E48		00002E48		2839+	DS	OFD		
00002E48	00002E68			2840+	USING	*, R5	base for test data and test routine	
00002E4C	0048			2841+T72	DC	A(X72)	address of test routine	
00002E4E	00			2842+	DC	H' 72'	test number	
00002E4F	9F			2843+	DC	X' 00'		
00002E50	8A			2844+	DC	HL1' 159'	i3	
00002E51	01			2845+	DC	HL1' 138'	i4	
00002E52	00			2846+	DC	HL1' 1'	m5	
00002E53	07			2847+	DC	HL1' 0'	cc	
00002E54	00002E9C			2848+	DC	HL1' 7'	cc failed mask	
00002E58	E5D7E2D6 D7404040			2849+V2_72	DC	A(RE72+16)	address of v2: 16-byte packed decimal	
00002E60	00000010			2850+	DC	CL8' VPSOP'	instruction name	
00002E64	00002E8C			2851+	DC	A(16)	result length	
				2852+REA72	DC	A(RE72)	result address	
				2853+*			INSTRUCTION UNDER TEST ROUTINE	
00002E68				2854+X72	DS	OF		
00002E68	E320 500C 0014		00002E54	2855+	LGF	R2, V2_72	get v2	
00002E6E	E722 0000 0006		00000000	2856+	VL	V2, 0(R2)		
00002E74	E612 8A19 F05B			2857+	VPSOP	V1, V2, 159, 138, 1	test instruction	
00002E7A	E710 8F10 000E		00001110	2858+	VST	V1, V10UTPUT	save result	
00002E80	B98D 0020			2859+	EPSW	R2, R0	exptract psw	
00002E84	5020 8EF4		000010F4	2860+	ST	R2, CCPSW	to save CC	
00002E88	07FB			2861+	BR	R11	return	
00002E8C				2862+RE72	DC	OF		
00002E8C				2863+	DROP	R5		
00002E8C	00000000 00000000			2864	DC	XL16' 00000000000000000000000000000000F'	V1	
00002E94	00000000 0000000F							
00002E9C	00000000 00000000			2865	DC	XL16' 00000000000000000000000000000000D'	V2	
00002EA4	00000000 0000000D							
				2866				
00002EB0				2867	VRI_G	VPSOP, 159, 202, 1, 0	nz=1 pc=1	
00002EB0		00002EB0		2868+	DS	OFD		
00002EB0	00002ED0			2869+	USING	*, R5	base for test data and test routine	
00002EB4	0049			2870+T73	DC	A(X73)	address of test routine	
00002EB6	00			2871+	DC	H' 73'	test number	
00002EB7	9F			2872+	DC	X' 00'		
00002EB8	CA			2873+	DC	HL1' 159'	i3	
00002EB9	01			2874+	DC	HL1' 202'	i4	
00002EBA	00			2875+	DC	HL1' 1'	m5	
00002EBB	07			2876+	DC	HL1' 0'	cc	
00002EBC	00002F04			2877+	DC	HL1' 7'	cc failed mask	
00002EC0	E5D7E2D6 D7404040			2878+V2_73	DC	A(RE73+16)	address of v2: 16-byte packed decimal	
00002EC8	00000010			2879+	DC	CL8' VPSOP'	instruction name	
00002ECC	00002EF4			2880+	DC	A(16)	result length	
				2881+REA73	DC	A(RE73)	result address	
				2882+*			INSTRUCTION UNDER TEST ROUTINE	
00002ED0				2883+X73	DS	OF		
00002ED0	E320 500C 0014		00002EBC	2884+	LGF	R2, V2_73	get v2	
00002ED6	E722 0000 0006		00000000	2885+	VL	V2, 0(R2)		
00002EDC	E612 CA19 F05B			2886+	VPSOP	V1, V2, 159, 202, 1	test instruction	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00002EE2	E710 8F10 000E		00001110	2887+	VST	V1, V10OUTPUT	save result	
00002EE8	B98D 0020			2888+	EPSW	R2, R0	exptract psw	
00002EEC	5020 8EF4		000010F4	2889+	ST	R2, CCPSW	to save CC	
00002EF0	07FB			2890+	BR	R11	return	
00002EF4				2891+RE73	DC	0F		
00002EF4				2892+	DROP	R5		
00002EF4	00000000 00000000			2893	DC	XL16' 00000000000000000000000000000000F'	V1	
00002EFC	00000000 0000000F							
00002F04	00000000 00000000			2894	DC	XL16' 00000000000000000000000000000000B'	V2	
00002F0C	00000000 0000000B							
				2895				
				2896 *				
				2897 * SC=11 (force negative): nv=1 to avoid data exceptions				
				2898 *				
				2899				
				2900 * V1: nonzero V2: - - - - - PC=' - ' NZ=' â€‘' V1_sign=D CC=1				
				2901 * V2: positive PC=0				
				2902	VRI_G	VPSOP, 159, 140, 1, 1	nz=0 pc=0	
00002F18				2903+	DS	0FD		
00002F18		00002F18		2904+	USING	*, R5	base for test data and test routine	
00002F18	00002F38			2905+T74	DC	A(X74)	address of test routine	
00002F1C	004A			2906+	DC	H' 74'	test number	
00002F1E	00			2907+	DC	X' 00'		
00002F1F	9F			2908+	DC	HL1' 159'	i3	
00002F20	8C			2909+	DC	HL1' 140'	i4	
00002F21	01			2910+	DC	HL1' 1'	m5	
00002F22	01			2911+	DC	HL1' 1'	cc	
00002F23	0B			2912+	DC	HL1' 11'	cc failed mask	
00002F24	00002F6C			2913+V2_74	DC	A(RE74+16)	address of v2: 16-byte packed decimal	
00002F28	E5D7E2D6 D7404040			2914+	DC	CL8' VPSOP'	instruction name	
00002F30	00000010			2915+	DC	A(16)	result length	
00002F34	00002F5C			2916+REA74	DC	A(RE74)	result address	
				2917+*			INSTRUCTION UNDER TEST ROUTINE	
00002F38				2918+X74	DS	0F		
00002F38	E320 500C 0014		00002F24	2919+	LGF	R2, V2_74	get v2	
00002F3E	E722 0000 0006		00000000	2920+	VL	V2, 0(R2)		
00002F44	E612 8C19 F05B			2921+	VPSOP	V1, V2, 159, 140, 1	test instruction	
00002F4A	E710 8F10 000E		00001110	2922+	VST	V1, V10OUTPUT	save result	
00002F50	B98D 0020			2923+	EPSW	R2, R0	exptract psw	
00002F54	5020 8EF4		000010F4	2924+	ST	R2, CCPSW	to save CC	
00002F58	07FB			2925+	BR	R11	return	
00002F5C				2926+RE74	DC	0F		
00002F5C				2927+	DROP	R5		
00002F5C	00000000 00000000			2928	DC	XL16' 000000000000000000000000220000000D'	V1	
00002F64	00000022 0000000D							
00002F6C	00000000 00000000			2929	DC	XL16' 000000000000000000000000220000000A'	V2	
00002F74	00000022 0000000A							
				2930				
00002F80				2931	VRI_G	VPSOP, 159, 204, 1, 1	nz=1 pc=0	
00002F80		00002F80		2932+	DS	0FD		
00002F80	00002FA0			2933+	USING	*, R5	base for test data and test routine	
00002F84	004B			2934+T75	DC	A(X75)	address of test routine	
00002F86	00			2935+	DC	H' 75'	test number	
00002F87	9F			2936+	DC	X' 00'		
00002F88	CC			2937+	DC	HL1' 159'	i3	
				2938+	DC	HL1' 204'	i4	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002F89	01			2939+	DC	HL1' 1'	m5
00002F8A	01			2940+	DC	HL1' 1'	cc
00002F8B	0B			2941+	DC	HL1' 11'	cc failed mask
00002F8C	00002FD4			2942+V2_75	DC	A(RE75+16)	address of v2: 16-byte packed decimal
00002F90	E5D7E2D6 D7404040			2943+	DC	CL8' VPSOP'	instruction name
00002F98	00000010			2944+	DC	A(16)	result length
00002F9C	00002FC4			2945+REA75	DC	A(RE75)	result address
				2946+*			INSTRUCTION UNDER TEST ROUTINE
00002FA0				2947+X75	DS	0F	
00002FA0	E320 500C 0014		00002F8C	2948+	LGF	R2, V2_75	get v2
00002FA6	E722 0000 0006		00000000	2949+	VL	V2, 0(R2)	
00002FAC	E612 CC19 F05B			2950+	VPSOP	V1, V2, 159, 204, 1	test instruction
00002FB2	E710 8F10 000E		00001110	2951+	VST	V1, V10OUTPUT	save result
00002FB8	B98D 0020			2952+	EPSW	R2, R0	exptract psw
00002FBC	5020 8EF4		000010F4	2953+	ST	R2, CCPSW	to save CC
00002FC0	07FB			2954+	BR	R11	return
00002FC4				2955+RE75	DC	0F	
00002FC4				2956+	DROP	R5	
00002FC4	00000000 00000000			2957	DC	XL16' 000000000000000000000000220000000D'	V1
00002FCC	00000022 0000000D						
00002FD4	00000000 00000000			2958	DC	XL16' 000000000000000000000000220000000A'	V2
00002FDC	00000022 0000000A						
				2959 * V2: negative	PC=0		
00002FE8				2960	VRI_G	VPSOP, 159, 140, 1, 1	nz=0 pc=0
00002FE8		00002FE8		2961+	DS	0FD	
00002FE8	00003008			2962+	USING	*, R5	base for test data and test routine
00002FEC	004C			2963+T76	DC	A(X76)	address of test routine
00002FEE	00			2964+	DC	H' 76'	test number
00002FEF	9F			2965+	DC	X' 00'	
00002FF0	8C			2966+	DC	HL1' 159'	i3
00002FF1	01			2967+	DC	HL1' 140'	i4
00002FF2	01			2968+	DC	HL1' 1'	m5
00002FF3	0B			2969+	DC	HL1' 1'	cc
00002FF4	0000303C			2970+	DC	HL1' 11'	cc failed mask
00002FF8	E5D7E2D6 D7404040			2971+V2_76	DC	A(RE76+16)	address of v2: 16-byte packed decimal
00003000	00000010			2972+	DC	CL8' VPSOP'	instruction name
00003004	0000302C			2973+	DC	A(16)	result length
				2974+REA76	DC	A(RE76)	result address
				2975+*			INSTRUCTION UNDER TEST ROUTINE
00003008				2976+X76	DS	0F	
00003008	E320 500C 0014		00002FF4	2977+	LGF	R2, V2_76	get v2
0000300E	E722 0000 0006		00000000	2978+	VL	V2, 0(R2)	
00003014	E612 8C19 F05B			2979+	VPSOP	V1, V2, 159, 140, 1	test instruction
0000301A	E710 8F10 000E		00001110	2980+	VST	V1, V10OUTPUT	save result
00003020	B98D 0020			2981+	EPSW	R2, R0	exptract psw
00003024	5020 8EF4		000010F4	2982+	ST	R2, CCPSW	to save CC
00003028	07FB			2983+	BR	R11	return
0000302C				2984+RE76	DC	0F	
0000302C				2985+	DROP	R5	
0000302C	00000000 00000000			2986	DC	XL16' 000000000000000000000000220000000D'	V1
00003034	00000022 0000000D						
0000303C	00000000 00000000			2987	DC	XL16' 000000000000000000000000220000000D'	V2
00003044	00000022 0000000D						
				2988			
				2989	VRI_G	VPSOP, 159, 204, 1, 1	nz=1 pc=0
00003050				2990+	DS	0FD	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003104	00000022 0000000D						
0000310C	00000000 00000000			3045	DC	XL16' 000000000000000000000000220000000A'	V2
00003114	00000022 0000000A						
				3046			
				3047	VRI_G	VPSOP, 159, 206, 1, 1	nz=1 pc=1
00003120				3048+	DS	OFD	
00003120		00003120		3049+	USING	*, R5	base for test data and test routine
00003120	00003140			3050+T79	DC	A(X79)	address of test routine
00003124	004F			3051+	DC	H' 79'	test number
00003126	00			3052+	DC	X' 00'	
00003127	9F			3053+	DC	HL1' 159'	i3
00003128	CE			3054+	DC	HL1' 206'	i4
00003129	01			3055+	DC	HL1' 1'	m5
0000312A	01			3056+	DC	HL1' 1'	cc
0000312B	0B			3057+	DC	HL1' 11'	cc failed mask
0000312C	00003174			3058+V2_79	DC	A(RE79+16)	address of v2: 16-byte packed decimal
00003130	E5D7E2D6 D7404040			3059+	DC	CL8' VPSOP'	instruction name
00003138	00000010			3060+	DC	A(16)	result length
0000313C	00003164			3061+REA79	DC	A(RE79)	result address
				3062+*			INSTRUCTION UNDER TEST ROUTINE
00003140				3063+X79	DS	OF	
00003140	E320 500C 0014		0000312C	3064+	LGF	R2, V2_79	get v2
00003146	E722 0000 0006		00000000	3065+	VL	V2, 0(R2)	
0000314C	E612 CE19 F05B			3066+	VPSOP	V1, V2, 159, 206, 1	test instruction
00003152	E710 8F10 000E		00001110	3067+	VST	V1, V10OUTPUT	save result
00003158	B98D 0020			3068+	EPSW	R2, R0	exptract psw
0000315C	5020 8EF4		000010F4	3069+	ST	R2, CCPSW	to save CC
00003160	07FB			3070+	BR	R11	return
00003164				3071+RE79	DC	OF	
00003164				3072+	DROP	R5	
00003164	00000000 00000000			3073	DC	XL16' 000000000000000000000000220000000D'	V1
0000316C	00000022 0000000D						
00003174	00000000 00000000			3074	DC	XL16' 000000000000000000000000220000000A'	V2
0000317C	00000022 0000000A						
				3075 * V2: negative	PC=1		
				3076	VRI_G	VPSOP, 159, 142, 1, 1	nz=0 pc=1
00003188				3077+	DS	OFD	
00003188		00003188		3078+	USING	*, R5	base for test data and test routine
00003188	000031A8			3079+T80	DC	A(X80)	address of test routine
0000318C	0050			3080+	DC	H' 80'	test number
0000318E	00			3081+	DC	X' 00'	
0000318F	9F			3082+	DC	HL1' 159'	i3
00003190	8E			3083+	DC	HL1' 142'	i4
00003191	01			3084+	DC	HL1' 1'	m5
00003192	01			3085+	DC	HL1' 1'	cc
00003193	0B			3086+	DC	HL1' 11'	cc failed mask
00003194	000031DC			3087+V2_80	DC	A(RE80+16)	address of v2: 16-byte packed decimal
00003198	E5D7E2D6 D7404040			3088+	DC	CL8' VPSOP'	instruction name
000031A0	00000010			3089+	DC	A(16)	result length
000031A4	000031CC			3090+REA80	DC	A(RE80)	result address
				3091+*			INSTRUCTION UNDER TEST ROUTINE
000031A8				3092+X80	DS	OF	
000031A8	E320 500C 0014		00003194	3093+	LGF	R2, V2_80	get v2
000031AE	E722 0000 0006		00000000	3094+	VL	V2, 0(R2)	
000031B4	E612 8E19 F05B			3095+	VPSOP	V1, V2, 159, 142, 1	test instruction
000031BA	E710 8F10 000E		00001110	3096+	VST	V1, V10OUTPUT	save result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000031C0	B98D 0020			3097+	EPSW	R2, R0	extract psw
000031C4	5020 8EF4		000010F4	3098+	ST	R2, CCPSW	to save CC
000031C8	07FB			3099+	BR	R11	return
000031CC				3100+RE80	DC	0F	
000031CC				3101+	DROP	R5	
000031CC	00000000 00000000			3102	DC	XL16' 000000000000000000000000220000000D'	V1
000031D4	00000022 0000000D						
000031DC	00000000 00000000			3103	DC	XL16' 000000000000000000000000220000000D'	V2
000031E4	00000022 0000000D						
				3104			
				3105	VRI_G	VPSOP, 159, 206, 1, 1	nz=1 pc=1
000031F0				3106+	DS	0FD	
000031F0		000031F0		3107+	USING	*, R5	base for test data and test routine
000031F0	00003210			3108+T81	DC	A(X81)	address of test routine
000031F4	0051			3109+	DC	H' 81'	test number
000031F6	00			3110+	DC	X' 00'	
000031F7	9F			3111+	DC	HL1' 159'	i3
000031F8	CE			3112+	DC	HL1' 206'	i4
000031F9	01			3113+	DC	HL1' 1'	m5
000031FA	01			3114+	DC	HL1' 1'	cc
000031FB	0B			3115+	DC	HL1' 11'	cc failed mask
000031FC	00003244			3116+V2_81	DC	A(RE81+16)	address of v2: 16-byte packed decimal
00003200	E5D7E2D6 D7404040			3117+	DC	CL8' VPSOP'	instruction name
00003208	00000010			3118+	DC	A(16)	result length
0000320C	00003234			3119+REA81	DC	A(RE81)	result address
				3120+*			INSTRUCTION UNDER TEST ROUTINE
00003210				3121+X81	DS	0F	
00003210	E320 500C 0014		000031FC	3122+	LGF	R2, V2_81	get v2
00003216	E722 0000 0006		00000000	3123+	VL	V2, 0(R2)	
0000321C	E612 CE19 F05B			3124+	VPSOP	V1, V2, 159, 206, 1	test instruction
00003222	E710 8F10 000E		00001110	3125+	VST	V1, V10UTPUT	save result
00003228	B98D 0020			3126+	EPSW	R2, R0	extract psw
0000322C	5020 8EF4		000010F4	3127+	ST	R2, CCPSW	to save CC
00003230	07FB			3128+	BR	R11	return
00003234				3129+RE81	DC	0F	
00003234				3130+	DROP	R5	
00003234	00000000 00000000			3131	DC	XL16' 000000000000000000000000220000000D'	V1
0000323C	00000022 0000000D						
00003244	00000000 00000000			3132	DC	XL16' 000000000000000000000000220000000B'	V2
0000324C	00000022 0000000B						
				3133			
				3134 * V1: zero		V2: - - - - - PC=' 0' NZ=' 0'	V1_sign=C CC=0
				3135 * V2: positive			
				3136	VRI_G	VPSOP, 159, 140, 1, 0	nz=0 pc=0
00003258				3137+	DS	0FD	
00003258		00003258		3138+	USING	*, R5	base for test data and test routine
00003258	00003278			3139+T82	DC	A(X82)	address of test routine
0000325C	0052			3140+	DC	H' 82'	test number
0000325E	00			3141+	DC	X' 00'	
0000325F	9F			3142+	DC	HL1' 159'	i3
00003260	8C			3143+	DC	HL1' 140'	i4
00003261	01			3144+	DC	HL1' 1'	m5
00003262	00			3145+	DC	HL1' 0'	cc
00003263	07			3146+	DC	HL1' 7'	cc failed mask
00003264	000032AC			3147+V2_82	DC	A(RE82+16)	address of v2: 16-byte packed decimal
00003268	E5D7E2D6 D7404040			3148+	DC	CL8' VPSOP'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003270	00000010			3149+	DC	A(16)	result length
00003274	0000329C			3150+REA82	DC	A(RE82)	result address
				3151+*			INSTRUCTION UNDER TEST ROUTINE
00003278				3152+X82	DS	0F	
00003278	E320 500C 0014		00003264	3153+	LGF	R2, V2_82	get v2
0000327E	E722 0000 0006		00000000	3154+	VL	V2, 0(R2)	
00003284	E612 8C19 F05B			3155+	VPSOP	V1, V2, 159, 140, 1	test instruction
0000328A	E710 8F10 000E		00001110	3156+	VST	V1, V10UTPUT	save result
00003290	B98D 0020			3157+	EPSW	R2, R0	exptract psw
00003294	5020 8EF4		000010F4	3158+	ST	R2, CCPSW	to save CC
00003298	07FB			3159+	BR	R11	return
0000329C				3160+RE82	DC	0F	
0000329C				3161+	DROP	R5	
0000329C	00000000 00000000			3162	DC	XL16' 00000000000000000000000000000000C'	V1
000032A4	00000000 0000000C						
000032AC	00000000 00000000			3163	DC	XL16' 00000000000000000000000000000000A'	V2
000032B4	00000000 0000000A						
				3164 * V2: negative			
000032C0				3165	VRI_G	VPSOP, 159, 140, 1, 0	nz=0 pc=0
000032C0		000032C0		3166+	DS	0FD	
000032C0	000032E0			3167+	USING	*, R5	base for test data and test routine
000032C4	0053			3168+T83	DC	A(X83)	address of test routine
000032C6	00			3169+	DC	H' 83'	test number
000032C7	9F			3170+	DC	X' 00'	
000032C8	8C			3171+	DC	HL1' 159'	i3
000032C9	01			3172+	DC	HL1' 140'	i4
000032CA	00			3173+	DC	HL1' 1'	m5
000032CB	07			3174+	DC	HL1' 0'	cc
000032CB	07			3175+	DC	HL1' 7'	cc failed mask
000032CC	00003314			3176+V2_83	DC	A(RE83+16)	address of v2: 16-byte packed decimal
000032D0	E5D7E2D6 D7404040			3177+	DC	CL8' VPSOP'	instruction name
000032D8	00000010			3178+	DC	A(16)	result length
000032DC	00003304			3179+REA83	DC	A(RE83)	result address
				3180+*			INSTRUCTION UNDER TEST ROUTINE
000032E0				3181+X83	DS	0F	
000032E0	E320 500C 0014		000032CC	3182+	LGF	R2, V2_83	get v2
000032E6	E722 0000 0006		00000000	3183+	VL	V2, 0(R2)	
000032EC	E612 8C19 F05B			3184+	VPSOP	V1, V2, 159, 140, 1	test instruction
000032F2	E710 8F10 000E		00001110	3185+	VST	V1, V10UTPUT	save result
000032F8	B98D 0020			3186+	EPSW	R2, R0	exptract psw
000032FC	5020 8EF4		000010F4	3187+	ST	R2, CCPSW	to save CC
00003300	07FB			3188+	BR	R11	return
00003304				3189+RE83	DC	0F	
00003304				3190+	DROP	R5	
00003304	00000000 00000000			3191	DC	XL16' 00000000000000000000000000000000C'	V1
0000330C	00000000 0000000C						
00003314	00000000 00000000			3192	DC	XL16' 00000000000000000000000000000000D'	V2
0000331C	00000000 0000000D						
				3193			
				3194 * V1: zero V2: - - - - - PC=' 1' NZ=' 0' V1_sign=F CC=0			
				3195 * V2: positive			
00003328				3196	VRI_G	VPSOP, 159, 142, 1, 0	nz=0 pc=1
00003328		00003328		3197+	DS	0FD	
00003328	00003348			3198+	USING	*, R5	base for test data and test routine
0000332C	0054			3199+T84	DC	A(X84)	address of test routine
				3200+	DC	H' 84'	test number

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000332E	00			3201+	DC	X' 00'	
0000332F	9F			3202+	DC	HL1' 159'	i3
00003330	8E			3203+	DC	HL1' 142'	i4
00003331	01			3204+	DC	HL1' 1'	m5
00003332	00			3205+	DC	HL1' 0'	cc
00003333	07			3206+	DC	HL1' 7'	cc failed mask
00003334	0000337C			3207+V2_84	DC	A(RE84+16)	address of v2: 16-byte packed decimal
00003338	E5D7E2D6 D7404040			3208+	DC	CL8' VPSOP'	instruction name
00003340	00000010			3209+	DC	A(16)	result length
00003344	0000336C			3210+REA84	DC	A(RE84)	result address
				3211+*			INSTRUCTION UNDER TEST ROUTINE
00003348				3212+X84	DS	0F	
00003348	E320 500C 0014		00003334	3213+	LGF	R2, V2_84	get v2
0000334E	E722 0000 0006		00000000	3214+	VL	V2, 0(R2)	
00003354	E612 8E19 F05B			3215+	VPSOP	V1, V2, 159, 142, 1	test instruction
0000335A	E710 8F10 000E		00001110	3216+	VST	V1, V10OUTPUT	save result
00003360	B98D 0020			3217+	EPSW	R2, R0	exptract psw
00003364	5020 8EF4		000010F4	3218+	ST	R2, CCPSW	to save CC
00003368	07FB			3219+	BR	R11	return
0000336C				3220+RE84	DC	0F	
0000336C				3221+	DROP	R5	
0000336C	00000000 00000000			3222	DC	XL16' 00000000000000000000000000000000F'	V1
00003374	00000000 0000000F						
0000337C	00000000 00000000			3223	DC	XL16' 00000000000000000000000000000000A'	V2
00003384	00000000 0000000A						
				3224 * V2: negative			
				3225	VRI_G	VPSOP, 159, 142, 1, 0	nz=0 pc=1
00003390				3226+	DS	0FD	
00003390		00003390		3227+	USING	*, R5	base for test data and test routine
00003390	000033B0			3228+T85	DC	A(X85)	address of test routine
00003394	0055			3229+	DC	H' 85'	test number
00003396	00			3230+	DC	X' 00'	
00003397	9F			3231+	DC	HL1' 159'	i3
00003398	8E			3232+	DC	HL1' 142'	i4
00003399	01			3233+	DC	HL1' 1'	m5
0000339A	00			3234+	DC	HL1' 0'	cc
0000339B	07			3235+	DC	HL1' 7'	cc failed mask
0000339C	000033E4			3236+V2_85	DC	A(RE85+16)	address of v2: 16-byte packed decimal
000033A0	E5D7E2D6 D7404040			3237+	DC	CL8' VPSOP'	instruction name
000033A8	00000010			3238+	DC	A(16)	result length
000033AC	000033D4			3239+REA85	DC	A(RE85)	result address
				3240+*			INSTRUCTION UNDER TEST ROUTINE
000033B0				3241+X85	DS	0F	
000033B0	E320 500C 0014		0000339C	3242+	LGF	R2, V2_85	get v2
000033B6	E722 0000 0006		00000000	3243+	VL	V2, 0(R2)	
000033BC	E612 8E19 F05B			3244+	VPSOP	V1, V2, 159, 142, 1	test instruction
000033C2	E710 8F10 000E		00001110	3245+	VST	V1, V10OUTPUT	save result
000033C8	B98D 0020			3246+	EPSW	R2, R0	exptract psw
000033CC	5020 8EF4		000010F4	3247+	ST	R2, CCPSW	to save CC
000033D0	07FB			3248+	BR	R11	return
000033D4				3249+RE85	DC	0F	
000033D4				3250+	DROP	R5	
000033D4	00000000 00000000			3251	DC	XL16' 00000000000000000000000000000000F'	V1
000033DC	00000000 0000000F						
000033E4	00000000 00000000			3252	DC	XL16' 00000000000000000000000000000000D'	V2
000033EC	00000000 0000000D						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				3253	
				3254 * V1: zero V2: - - - - - PC=' - ' NZ=' 1' V1_sign=d CC=0	
				3255 * V2: positive	
				3256 VRI_G VPSOP, 159, 204, 1, 0 nz=1 pc=0	
000033F8				3257+ DS OFD	
000033F8		000033F8		3258+ USING *, R5	base for test data and test routine
000033F8	00003418			3259+T86 DC A(X86)	address of test routine
000033FC	0056			3260+ DC H' 86'	test number
000033FE	00			3261+ DC X' 00'	
000033FF	9F			3262+ DC HL1' 159'	i3
00003400	CC			3263+ DC HL1' 204'	i4
00003401	01			3264+ DC HL1' 1'	m5
00003402	00			3265+ DC HL1' 0'	cc
00003403	07			3266+ DC HL1' 7'	cc failed mask
00003404	0000344C			3267+V2_86 DC A(RE86+16)	address of v2: 16-byte packed decimal
00003408	E5D7E2D6 D7404040			3268+ DC CL8' VPSOP'	instruction name
00003410	00000010			3269+ DC A(16)	result length
00003414	0000343C			3270+REA86 DC A(RE86)	result address
				3271+*	INSTRUCTION UNDER TEST ROUTINE
00003418				3272+X86 DS OF	
00003418	E320 500C 0014		00003404	3273+ LGF R2, V2_86	get v2
0000341E	E722 0000 0006		00000000	3274+ VL V2, 0(R2)	
00003424	E612 CC19 F05B			3275+ VPSOP V1, V2, 159, 204, 1	test instruction
0000342A	E710 8F10 000E		00001110	3276+ VST V1, V10UTPUT	save result
00003430	B98D 0020			3277+ EPSW R2, R0	exptract psw
00003434	5020 8EF4		000010F4	3278+ ST R2, CCPSW	to save CC
00003438	07FB			3279+ BR R11	return
0000343C				3280+RE86 DC OF	
0000343C				3281+ DROP R5	
0000343C	00000000 00000000			3282 DC XL16' 00000000000000000000000000000000D'	V1
00003444	00000000 0000000D				
0000344C	00000000 00000000			3283 DC XL16' 00000000000000000000000000000000A'	V2
00003454	00000000 0000000A				
				3284 * V2: negative	
				3285 VRI_G VPSOP, 159, 204, 1, 0 nz=1 pc=0	
00003460				3286+ DS OFD	
00003460		00003460		3287+ USING *, R5	base for test data and test routine
00003460	00003480			3288+T87 DC A(X87)	address of test routine
00003464	0057			3289+ DC H' 87'	test number
00003466	00			3290+ DC X' 00'	
00003467	9F			3291+ DC HL1' 159'	i3
00003468	CC			3292+ DC HL1' 204'	i4
00003469	01			3293+ DC HL1' 1'	m5
0000346A	00			3294+ DC HL1' 0'	cc
0000346B	07			3295+ DC HL1' 7'	cc failed mask
0000346C	000034B4			3296+V2_87 DC A(RE87+16)	address of v2: 16-byte packed decimal
00003470	E5D7E2D6 D7404040			3297+ DC CL8' VPSOP'	instruction name
00003478	00000010			3298+ DC A(16)	result length
0000347C	000034A4			3299+REA87 DC A(RE87)	result address
				3300+*	INSTRUCTION UNDER TEST ROUTINE
00003480				3301+X87 DS OF	
00003480	E320 500C 0014		0000346C	3302+ LGF R2, V2_87	get v2
00003486	E722 0000 0006		00000000	3303+ VL V2, 0(R2)	
0000348C	E612 CC19 F05B			3304+ VPSOP V1, V2, 159, 204, 1	test instruction
00003492	E710 8F10 000E		00001110	3305+ VST V1, V10UTPUT	save result
00003498	B98D 0020			3306+ EPSW R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000349C	5020 8EF4		000010F4	3307+	ST	R2, CCPSW	to save CC	
000034A0	07FB			3308+	BR	R11	return	
000034A4				3309+RE87	DC	0F		
000034A4				3310+	DROP	R5		
000034A4	00000000 00000000			3311	DC	XL16' 0000000000000000000000000000000D'	V1	
000034AC	00000000 0000000D							
000034B4	00000000 00000000		3312	DC	XL16' 000000000000000000000000000000B'	V2		
000034BC	00000000 0000000B							
			3313					
			3314 * V2: positive					
			3315	VRI_G	VPSOP, 159, 206, 1, 0	nz=1 pc=1		
000034C8			3316+	DS	0FD			
000034C8		000034C8	3317+	USING	*, R5	base for test data and test routine		
000034C8	000034E8		3318+T88	DC	A(X88)	address of test routine		
000034CC	0058		3319+	DC	H' 88'	test number		
000034CE	00		3320+	DC	X' 00'			
000034CF	9F		3321+	DC	HL1' 159'	i3		
000034D0	CE		3322+	DC	HL1' 206'	i4		
000034D1	01		3323+	DC	HL1' 1'	m5		
000034D2	00		3324+	DC	HL1' 0'	cc		
000034D3	07		3325+	DC	HL1' 7'	cc failed mask		
000034D4	0000351C		3326+V2_88	DC	A(RE88+16)	address of v2: 16-byte packed decimal		
000034D8	E5D7E2D6 D7404040		3327+	DC	CL8' VPSOP'	instruction name		
000034E0	00000010		3328+	DC	A(16)	result length		
000034E4	0000350C		3329+REA88	DC	A(RE88)	result address		
			3330+*			INSTRUCTION UNDER TEST ROUTINE		
000034E8			3331+X88	DS	0F			
000034E8	E320 500C 0014		3332+	LGF	R2, V2_88	get v2		
000034EE	E722 0000 0006	000034D4	3333+	VL	V2, 0(R2)			
000034F4	E612 CE19 F05B		3334+	VPSOP	V1, V2, 159, 206, 1	test instruction		
000034FA	E710 8F10 000E	00001110	3335+	VST	V1, V10UTPUT	save result		
00003500	B98D 0020		3336+	EPSW	R2, R0	exptract psw		
00003504	5020 8EF4	000010F4	3337+	ST	R2, CCPSW	to save CC		
00003508	07FB		3338+	BR	R11	return		
0000350C			3339+RE88	DC	0F			
0000350C			3340+	DROP	R5			
0000350C	00000000 00000000		3341	DC	XL16' 000000000000000000000000000000D'	V1		
00003514	00000000 0000000D							
0000351C	00000000 00000000		3342	DC	XL16' 000000000000000000000000000000A'	V2		
00003524	00000000 0000000A							
			3343 * V2: negative					
			3344	VRI_G	VPSOP, 159, 206, 1, 0	nz=1 pc=1		
00003530			3345+	DS	0FD			
00003530		00003530	3346+	USING	*, R5	base for test data and test routine		
00003530	00003550		3347+T89	DC	A(X89)	address of test routine		
00003534	0059		3348+	DC	H' 89'	test number		
00003536	00		3349+	DC	X' 00'			
00003537	9F		3350+	DC	HL1' 159'	i3		
00003538	CE		3351+	DC	HL1' 206'	i4		
00003539	01		3352+	DC	HL1' 1'	m5		
0000353A	00		3353+	DC	HL1' 0'	cc		
0000353B	07		3354+	DC	HL1' 7'	cc failed mask		
0000353C	00003584		3355+V2_89	DC	A(RE89+16)	address of v2: 16-byte packed decimal		
00003540	E5D7E2D6 D7404040		3356+	DC	CL8' VPSOP'	instruction name		
00003548	00000010		3357+	DC	A(16)	result length		
0000354C	00003574		3358+REA89	DC	A(RE89)	result address		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				3359+*	INSTRUCTION UNDER TEST ROUTINE		
00003550				3360+X89	DS	0F	
00003550	E320 500C 0014		0000353C	3361+	LGF	R2, V2_89	get v2
00003556	E722 0000 0006		00000000	3362+	VL	V2, 0(R2)	
0000355C	E612 CE19 F05B			3363+	VPSOP	V1, V2, 159, 206, 1	test instruction
00003562	E710 8F10 000E		00001110	3364+	VST	V1, V10UTPUT	save result
00003568	B98D 0020			3365+	EPSW	R2, R0	exptract psw
0000356C	5020 8EF4		000010F4	3366+	ST	R2, CCPSW	to save CC
00003570	07FB			3367+	BR	R11	return
00003574				3368+RE89	DC	0F	
00003574				3369+	DROP	R5	
00003574	00000000 00000000			3370	DC	XL16' 00000000000000000000000000000000D'	V1
0000357C	00000000 0000000D						
00003584	00000000 00000000			3371	DC	XL16' 00000000000000000000000000000000B'	V2
0000358C	00000000 0000000B						
				3372			
				3373 *	-----		
				3374 *	SOME cc=3 (overflow) tests with rdc=4		
				3375 *	-----		
				3376 *	V1: zero V2: positive PC=' 0' NZ=' 0' V1_sign=C CC=0		
				3377	VRI_G	VPSOP, 132, 128, 1, 3	nz=0 pc=0
00003598				3378+	DS	0FD	
00003598		00003598		3379+	USING	*, R5	base for test data and test routine
00003598	000035B8			3380+T90	DC	A(X90)	address of test routine
0000359C	005A			3381+	DC	H' 90'	test number
0000359E	00			3382+	DC	X' 00'	
0000359F	84			3383+	DC	HL1' 132'	i3
000035A0	80			3384+	DC	HL1' 128'	i4
000035A1	01			3385+	DC	HL1' 1'	m5
000035A2	03			3386+	DC	HL1' 3'	cc
000035A3	0E			3387+	DC	HL1' 14'	cc failed mask
000035A4	000035EC			3388+V2_90	DC	A(RE90+16)	address of v2: 16-byte packed decimal
000035A8	E5D7E2D6 D7404040			3389+	DC	CL8' VPSOP'	instruction name
000035B0	00000010			3390+	DC	A(16)	result length
000035B4	000035DC			3391+REA90	DC	A(RE90)	result address
				3392+*	INSTRUCTION UNDER TEST ROUTINE		
000035B8				3393+X90	DS	0F	
000035B8	E320 500C 0014		000035A4	3394+	LGF	R2, V2_90	get v2
000035BE	E722 0000 0006		00000000	3395+	VL	V2, 0(R2)	
000035C4	E612 8018 405B			3396+	VPSOP	V1, V2, 132, 128, 1	test instruction
000035CA	E710 8F10 000E		00001110	3397+	VST	V1, V10UTPUT	save result
000035D0	B98D 0020			3398+	EPSW	R2, R0	exptract psw
000035D4	5020 8EF4		000010F4	3399+	ST	R2, CCPSW	to save CC
000035D8	07FB			3400+	BR	R11	return
000035DC				3401+RE90	DC	0F	
000035DC				3402+	DROP	R5	
000035DC	00000000 00000000			3403	DC	XL16' 00000000000000000000000000000000C'	V1
000035E4	00000000 0000000C						
000035EC	00000000 00009990			3404	DC	XL16' 00000000000099900000000000000000F'	V2
000035F4	00000000 0000000F						
				3405			
				3406 *	SC=01 (complement): nv=1 to avoid data exceptions		
				3407 *	V1: zero V2: positive PC=' 0' NZ=' 0' V1_sign=C CC=0		
				3408	VRI_G	VPSOP, 132, 132, 1, 3	nz=0 pc=0
00003600				3409+	DS	0FD	
00003600		00003600		3410+	USING	*, R5	base for test data and test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00003600	00003620			3411+T91	DC	A(X91)
00003604	005B			3412+	DC	H' 91'
00003606	00			3413+	DC	X' 00'
00003607	84			3414+	DC	HL1' 132'
00003608	84			3415+	DC	HL1' 132'
00003609	01			3416+	DC	HL1' 1'
0000360A	03			3417+	DC	HL1' 3'
0000360B	0E			3418+	DC	HL1' 14'
0000360C	00003654			3419+V2_91	DC	A(RE91+16)
00003610	E5D7E2D6 D7404040			3420+	DC	CL8' VPSOP'
00003618	00000010			3421+	DC	A(16)
0000361C	00003644			3422+REA91	DC	A(RE91)
				3423+*		INSTRUCTION UNDER TEST ROUTINE
00003620				3424+X91	DS	0F
00003620	E320 500C 0014		0000360C	3425+	LGF	R2, V2_91
00003626	E722 0000 0006		00000000	3426+	VL	V2, 0(R2)
0000362C	E612 8418 405B			3427+	VPSOP	V1, V2, 132, 132, 1
00003632	E710 8F10 000E		00001110	3428+	VST	V1, V10UTPUT
00003638	B98D 0020			3429+	EPSW	R2, R0
0000363C	5020 8EF4		000010F4	3430+	ST	R2, CCPSW
00003640	07FB			3431+	BR	R11
00003644				3432+RE91	DC	0F
00003644				3433+	DROP	R5
00003644	00000000 00000000			3434	DC	XL16' 00000000000000000000000000000000C' V1
0000364C	00000000 0000000C					
00003654	00000000 00009990			3435	DC	XL16' 00000000000009990000000000000000A' V2
0000365C	00000000 0000000A					
				3436		
				3437 *	SC=10 (force positive): nv=1 to avoid data exceptions	
				3438 *	V1: zero V2: ----- PC=' 0' NZ=' â€‘' V1_sign=C CC=0	
				3439 *	V2: positive	
				3440	VRI_G	VPSOP, 132, 136, 1, 3 nz=0 pc=0
00003668				3441+	DS	0FD
00003668		00003668		3442+	USING	*, R5
00003668	00003688			3443+T92	DC	A(X92)
0000366C	005C			3444+	DC	H' 92'
0000366E	00			3445+	DC	X' 00'
0000366F	84			3446+	DC	HL1' 132'
00003670	88			3447+	DC	HL1' 136'
00003671	01			3448+	DC	HL1' 1'
00003672	03			3449+	DC	HL1' 3'
00003673	0E			3450+	DC	HL1' 14'
00003674	000036BC			3451+V2_92	DC	A(RE92+16)
00003678	E5D7E2D6 D7404040			3452+	DC	CL8' VPSOP'
00003680	00000010			3453+	DC	A(16)
00003684	000036AC			3454+REA92	DC	A(RE92)
				3455+*		INSTRUCTION UNDER TEST ROUTINE
00003688				3456+X92	DS	0F
00003688	E320 500C 0014		00003674	3457+	LGF	R2, V2_92
0000368E	E722 0000 0006		00000000	3458+	VL	V2, 0(R2)
00003694	E612 8818 405B			3459+	VPSOP	V1, V2, 132, 136, 1
0000369A	E710 8F10 000E		00001110	3460+	VST	V1, V10UTPUT
000036A0	B98D 0020			3461+	EPSW	R2, R0
000036A4	5020 8EF4		000010F4	3462+	ST	R2, CCPSW
000036A8	07FB			3463+	BR	R11
000036AC				3464+RE92	DC	0F

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000036AC				3465+	DROP R5	
000036AC	00000000 00000000			3466	DC	XL16' 00000000000000000000000000000000C' V1
000036B4	00000000 0000000C					
000036BC	00000000 00000999			3467	DC	XL16' 0000000000000999000000000000000A' V2
000036C4	00000000 0000000A					
				3468		
				3469	* SC=11 (force negative): nv=1 to avoid data exceptions	
				3470	* V1: zero V2: ----- PC=' 0' NZ=' 0' V1_sign=C CC=0	
				3471	* V2: positive	
				3472	VRI_G VPSOP, 132, 140, 1, 3 nz=0 pc=0	
000036D0				3473+	DS	OFD
000036D0		000036D0		3474+	USING	*, R5 base for test data and test routine
000036D0	000036F0			3475+T93	DC	A(X93) address of test routine
000036D4	005D			3476+	DC	H' 93' test number
000036D6	00			3477+	DC	X' 00'
000036D7	84			3478+	DC	HL1' 132' i3
000036D8	8C			3479+	DC	HL1' 140' i4
000036D9	01			3480+	DC	HL1' 1' m5
000036DA	03			3481+	DC	HL1' 3' cc
000036DB	0E			3482+	DC	HL1' 14' cc failed mask
000036DC	00003724			3483+V2_93	DC	A(RE93+16) address of v2: 16-byte packed decimal
000036E0	E5D7E2D6 D7404040			3484+	DC	CL8' VPSOP' instruction name
000036E8	00000010			3485+	DC	A(16) result length
000036EC	00003714			3486+REA93	DC	A(RE93) result address
				3487+*		INSTRUCTION UNDER TEST ROUTINE
000036F0				3488+X93	DS	OF
000036F0	E320 500C 0014		000036DC	3489+	LGF	R2, V2_93 get v2
000036F6	E722 0000 0006		00000000	3490+	VL	V2, 0(R2)
000036FC	E612 8C18 405B			3491+	VPSOP	V1, V2, 132, 140, 1 test instruction
00003702	E710 8F10 000E		00001110	3492+	VST	V1, V10UTPUT save result
00003708	B98D 0020			3493+	EPSW	R2, R0 exptract psw
0000370C	5020 8EF4		000010F4	3494+	ST	R2, CCPSW to save CC
00003710	07FB			3495+	BR	R11 return
00003714				3496+RE93	DC	OF
00003714				3497+	DROP	R5
00003714	00000000 00000000			3498	DC	XL16' 00000000000000000000000000000000C' V1
0000371C	00000000 0000000C					
00003724	00000000 00000000			3499	DC	XL16' 0000000000000000099900000000000A' V2
0000372C	99900000 0000000A					
				3500		
				3501	* -----	
				3502	* SOME cc=3 (overflow) tests with rdc=7	
				3503	* -----	
				3504	* SC=00 (maintain): nv=1 to avoid data exceptions	
				3505	* V1: nonzero V2: positive PC=' 0' NZ=' â€‘' V1_sign=C CC=2	
				3506	VRI_G VPSOP, 135, 128, 1, 3 nz=0	
00003738				3507+	DS	OFD
00003738		00003738		3508+	USING	*, R5 base for test data and test routine
00003738	00003758			3509+T94	DC	A(X94) address of test routine
0000373C	005E			3510+	DC	H' 94' test number
0000373E	00			3511+	DC	X' 00'
0000373F	87			3512+	DC	HL1' 135' i3
00003740	80			3513+	DC	HL1' 128' i4
00003741	01			3514+	DC	HL1' 1' m5
00003742	03			3515+	DC	HL1' 3' cc
00003743	0E			3516+	DC	HL1' 14' cc failed mask

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003744	0000378C			3517+V2_94	DC	A(RE94+16)	address of v2: 16-byte packed decimal
00003748	E5D7E2D6 D7404040			3518+	DC	CL8' VPSOP'	instruction name
00003750	00000010			3519+	DC	A(16)	result length
00003754	0000377C			3520+REA94	DC	A(RE94)	result address
				3521+*			INSTRUCTION UNDER TEST ROUTINE
00003758				3522+X94	DS	0F	
00003758	E320 500C 0014		00003744	3523+	LGF	R2, V2_94	get v2
0000375E	E722 0000 0006		00000000	3524+	VL	V2, 0(R2)	
00003764	E612 8018 705B			3525+	VPSOP	V1, V2, 135, 128, 1	test instruction
0000376A	E710 8F10 000E		00001110	3526+	VST	V1, V10UTPUT	save result
00003770	B98D 0020			3527+	EPSW	R2, R0	exptract psw
00003774	5020 8EF4		000010F4	3528+	ST	R2, CCPSW	to save CC
00003778	07FB			3529+	BR	R11	return
0000377C				3530+RE94	DC	0F	
0000377C				3531+	DROP	R5	
0000377C	00000000 00000000			3532	DC	XL16' 00000000000000000000000002000000C'	V1
00003784	00000000 2000000C						
0000378C	00000000 00000000			3533	DC	XL16' 000000000000000000000000222000000F'	V2
00003794	00000022 2000000F						
				3534			
				3535	* SC=01 (complement): nv=1 to avoid data exceptions		
				3536	* V1: nonzero V2: positive PC='-' NZ='â€‘' V1_sign=D CC=1		
				3537	VRI_G VPSOP, 135, 132, 1, 3 nz=0 pc=0		
000037A0				3538+	DS	0FD	
000037A0		000037A0		3539+	USING	*, R5	base for test data and test routine
000037A0	000037C0			3540+T95	DC	A(X95)	address of test routine
000037A4	005F			3541+	DC	H' 95'	test number
000037A6	00			3542+	DC	X' 00'	
000037A7	87			3543+	DC	HL1' 135'	i3
000037A8	84			3544+	DC	HL1' 132'	i4
000037A9	01			3545+	DC	HL1' 1'	m5
000037AA	03			3546+	DC	HL1' 3'	cc
000037AB	0E			3547+	DC	HL1' 14'	cc failed mask
000037AC	000037F4			3548+V2_95	DC	A(RE95+16)	address of v2: 16-byte packed decimal
000037B0	E5D7E2D6 D7404040			3549+	DC	CL8' VPSOP'	instruction name
000037B8	00000010			3550+	DC	A(16)	result length
000037BC	000037E4			3551+REA95	DC	A(RE95)	result address
				3552+*			INSTRUCTION UNDER TEST ROUTINE
000037C0				3553+X95	DS	0F	
000037C0	E320 500C 0014		000037AC	3554+	LGF	R2, V2_95	get v2
000037C6	E722 0000 0006		00000000	3555+	VL	V2, 0(R2)	
000037CC	E612 8418 705B			3556+	VPSOP	V1, V2, 135, 132, 1	test instruction
000037D2	E710 8F10 000E		00001110	3557+	VST	V1, V10UTPUT	save result
000037D8	B98D 0020			3558+	EPSW	R2, R0	exptract psw
000037DC	5020 8EF4		000010F4	3559+	ST	R2, CCPSW	to save CC
000037E0	07FB			3560+	BR	R11	return
000037E4				3561+RE95	DC	0F	
000037E4				3562+	DROP	R5	
000037E4	00000000 00000000			3563	DC	XL16' 0000000000000000000000002000000D'	V1
000037EC	00000000 2000000D						
000037F4	00000000 00000000			3564	DC	XL16' 000000000000000000000000222000000C'	V2
000037FC	00000022 2000000C						
				3565			
				3566	* SC=10 (force positive): nv=1 to avoid data exceptions		
				3567	* V1: nonzero V2: - - - - - PC='0' NZ='â€‘' V1_sign=C CC=2		
				3568	* V2: positive		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				3569	VRI_G VPSOP, 135, 136, 1, 3	nz=0 pc=0
00003808				3570+	DS OFD	
00003808		00003808		3571+	USING *, R5	base for test data and test routine
00003808	00003828			3572+T96	DC A(X96)	address of test routine
0000380C	0060			3573+	DC H' 96'	test number
0000380E	00			3574+	DC X' 00'	
0000380F	87			3575+	DC HL1' 135'	i3
00003810	88			3576+	DC HL1' 136'	i4
00003811	01			3577+	DC HL1' 1'	m5
00003812	03			3578+	DC HL1' 3'	cc
00003813	0E			3579+	DC HL1' 14'	cc failed mask
00003814	0000385C			3580+V2_96	DC A(RE96+16)	address of v2: 16-byte packed decimal
00003818	E5D7E2D6 D7404040			3581+	DC CL8' VPSOP'	instruction name
00003820	00000010			3582+	DC A(16)	result length
00003824	0000384C			3583+REA96	DC A(RE96)	result address
				3584+*		INSTRUCTION UNDER TEST ROUTINE
00003828				3585+X96	DS OF	
00003828	E320 500C 0014		00003814	3586+	LGF R2, V2_96	get v2
0000382E	E722 0000 0006		00000000	3587+	VL V2, 0(R2)	
00003834	E612 8818 705B			3588+	VPSOP V1, V2, 135, 136, 1	test instruction
0000383A	E710 8F10 000E		00001110	3589+	VST V1, V10UTPUT	save result
00003840	B98D 0020			3590+	EPSW R2, R0	exptract psw
00003844	5020 8EF4		000010F4	3591+	ST R2, CCPSW	to save CC
00003848	07FB			3592+	BR R11	return
0000384C				3593+RE96	DC OF	
0000384C				3594+	DROP R5	
0000384C	00000000 00000000			3595	DC XL16' 00000000000000000000000002000000C'	V1
00003854	00000000 2000000C					
0000385C	00000000 00000000			3596	DC XL16' 000000000000000000000000222000000A'	V2
00003864	00000022 2000000A					
				3597		
				3598 *	SC=11 (force negative): nv=1 to avoid data exceptions	
				3599 *	V1: nonzero V2: - - - - - PC= ' - ' NZ= ' â€‘ ' V1_sign=D CC=1	
				3600 *	V2: positive PC=0	
				3601	VRI_G VPSOP, 135, 140, 1, 3	nz=0 pc=0
00003870				3602+	DS OFD	
00003870		00003870		3603+	USING *, R5	base for test data and test routine
00003870	00003890			3604+T97	DC A(X97)	address of test routine
00003874	0061			3605+	DC H' 97'	test number
00003876	00			3606+	DC X' 00'	
00003877	87			3607+	DC HL1' 135'	i3
00003878	8C			3608+	DC HL1' 140'	i4
00003879	01			3609+	DC HL1' 1'	m5
0000387A	03			3610+	DC HL1' 3'	cc
0000387B	0E			3611+	DC HL1' 14'	cc failed mask
0000387C	000038C4			3612+V2_97	DC A(RE97+16)	address of v2: 16-byte packed decimal
00003880	E5D7E2D6 D7404040			3613+	DC CL8' VPSOP'	instruction name
00003888	00000010			3614+	DC A(16)	result length
0000388C	000038B4			3615+REA97	DC A(RE97)	result address
				3616+*		INSTRUCTION UNDER TEST ROUTINE
00003890				3617+X97	DS OF	
00003890	E320 500C 0014		0000387C	3618+	LGF R2, V2_97	get v2
00003896	E722 0000 0006		00000000	3619+	VL V2, 0(R2)	
0000389C	E612 8C18 705B			3620+	VPSOP V1, V2, 135, 140, 1	test instruction
000038A2	E710 8F10 000E		00001110	3621+	VST V1, V10UTPUT	save result
000038A8	B98D 0020			3622+	EPSW R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000038AC	5020 8EF4		000010F4	3623+	ST	R2, CCPSW	to save CC		
000038B0	07FB			3624+	BR	R11	return		
000038B4				3625+RE97	DC	0F			
000038B4				3626+	DROP	R5			
000038B4	00000000	00000000		3627	DC	XL16' 00000000000000000000000002000000D'		V1	
000038BC	00000000	2000000D							
000038C4	00000000	00000000		3628	DC	XL16' 000000000000000000000000222000000A'		V2	
000038CC	00000022	2000000A							
				3629					
				3630	*+++++				
				3631	*test				
				3632					
000038D4	00000000			3633	DC	F' 0'	END OF TABLE		
000038D8	00000000			3634	DC	F' 0'			
				3635	*				
				3636	* table of pointers to individual load test				
				3637	*				
000038DC				3638	E6TESTS	DS	0F		
				3639		PTTABLE			
000038DC				3640+TTABLE	DS	0F			
000038DC	00001170			3641+	DC	A(T1)	address	of	test
000038E0	000011D8			3642+	DC	A(T2)	address	of	test
000038E4	00001240			3643+	DC	A(T3)	address	of	test
000038E8	000012A8			3644+	DC	A(T4)	address	of	test
000038EC	00001310			3645+	DC	A(T5)	address	of	test
000038F0	00001378			3646+	DC	A(T6)	address	of	test
000038F4	000013E0			3647+	DC	A(T7)	address	of	test
000038F8	00001448			3648+	DC	A(T8)	address	of	test
000038FC	000014B0			3649+	DC	A(T9)	address	of	test
00003900	00001518			3650+	DC	A(T10)	address	of	test
00003904	00001580			3651+	DC	A(T11)	address	of	test
00003908	000015E8			3652+	DC	A(T12)	address	of	test
0000390C	00001650			3653+	DC	A(T13)	address	of	test
00003910	000016B8			3654+	DC	A(T14)	address	of	test
00003914	00001720			3655+	DC	A(T15)	address	of	test
00003918	00001788			3656+	DC	A(T16)	address	of	test
0000391C	000017F0			3657+	DC	A(T17)	address	of	test
00003920	00001858			3658+	DC	A(T18)	address	of	test
00003924	000018C0			3659+	DC	A(T19)	address	of	test
00003928	00001928			3660+	DC	A(T20)	address	of	test
0000392C	00001990			3661+	DC	A(T21)	address	of	test
00003930	000019F8			3662+	DC	A(T22)	address	of	test
00003934	00001A60			3663+	DC	A(T23)	address	of	test
00003938	00001AC8			3664+	DC	A(T24)	address	of	test
0000393C	00001B30			3665+	DC	A(T25)	address	of	test
00003940	00001B98			3666+	DC	A(T26)	address	of	test
00003944	00001C00			3667+	DC	A(T27)	address	of	test
00003948	00001C68			3668+	DC	A(T28)	address	of	test
0000394C	00001CD0			3669+	DC	A(T29)	address	of	test
00003950	00001D38			3670+	DC	A(T30)	address	of	test
00003954	00001DA0			3671+	DC	A(T31)	address	of	test
00003958	00001E08			3672+	DC	A(T32)	address	of	test
0000395C	00001E70			3673+	DC	A(T33)	address	of	test
00003960	00001ED8			3674+	DC	A(T34)	address	of	test
00003964	00001F40			3675+	DC	A(T35)	address	of	test
00003968	00001FA8			3676+	DC	A(T36)	address	of	test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000396C	00002010			3677+	DC	A(T37)	address of test
00003970	00002078			3678+	DC	A(T38)	address of test
00003974	000020E0			3679+	DC	A(T39)	address of test
00003978	00002148			3680+	DC	A(T40)	address of test
0000397C	000021B0			3681+	DC	A(T41)	address of test
00003980	00002218			3682+	DC	A(T42)	address of test
00003984	00002280			3683+	DC	A(T43)	address of test
00003988	000022E8			3684+	DC	A(T44)	address of test
0000398C	00002350			3685+	DC	A(T45)	address of test
00003990	000023B8			3686+	DC	A(T46)	address of test
00003994	00002420			3687+	DC	A(T47)	address of test
00003998	00002488			3688+	DC	A(T48)	address of test
0000399C	000024F0			3689+	DC	A(T49)	address of test
000039A0	00002558			3690+	DC	A(T50)	address of test
000039A4	000025C0			3691+	DC	A(T51)	address of test
000039A8	00002628			3692+	DC	A(T52)	address of test
000039AC	00002690			3693+	DC	A(T53)	address of test
000039B0	000026F8			3694+	DC	A(T54)	address of test
000039B4	00002760			3695+	DC	A(T55)	address of test
000039B8	000027C8			3696+	DC	A(T56)	address of test
000039BC	00002830			3697+	DC	A(T57)	address of test
000039C0	00002898			3698+	DC	A(T58)	address of test
000039C4	00002900			3699+	DC	A(T59)	address of test
000039C8	00002968			3700+	DC	A(T60)	address of test
000039CC	000029D0			3701+	DC	A(T61)	address of test
000039D0	00002A38			3702+	DC	A(T62)	address of test
000039D4	00002AA0			3703+	DC	A(T63)	address of test
000039D8	00002B08			3704+	DC	A(T64)	address of test
000039DC	00002B70			3705+	DC	A(T65)	address of test
000039E0	00002BD8			3706+	DC	A(T66)	address of test
000039E4	00002C40			3707+	DC	A(T67)	address of test
000039E8	00002CA8			3708+	DC	A(T68)	address of test
000039EC	00002D10			3709+	DC	A(T69)	address of test
000039F0	00002D78			3710+	DC	A(T70)	address of test
000039F4	00002DE0			3711+	DC	A(T71)	address of test
000039F8	00002E48			3712+	DC	A(T72)	address of test
000039FC	00002EB0			3713+	DC	A(T73)	address of test
00003A00	00002F18			3714+	DC	A(T74)	address of test
00003A04	00002F80			3715+	DC	A(T75)	address of test
00003A08	00002FE8			3716+	DC	A(T76)	address of test
00003A0C	00003050			3717+	DC	A(T77)	address of test
00003A10	000030B8			3718+	DC	A(T78)	address of test
00003A14	00003120			3719+	DC	A(T79)	address of test
00003A18	00003188			3720+	DC	A(T80)	address of test
00003A1C	000031F0			3721+	DC	A(T81)	address of test
00003A20	00003258			3722+	DC	A(T82)	address of test
00003A24	000032C0			3723+	DC	A(T83)	address of test
00003A28	00003328			3724+	DC	A(T84)	address of test
00003A2C	00003390			3725+	DC	A(T85)	address of test
00003A30	000033F8			3726+	DC	A(T86)	address of test
00003A34	00003460			3727+	DC	A(T87)	address of test
00003A38	000034C8			3728+	DC	A(T88)	address of test
00003A3C	00003530			3729+	DC	A(T89)	address of test
00003A40	00003598			3730+	DC	A(T90)	address of test
00003A44	00003600			3731+	DC	A(T91)	address of test
00003A48	00003668			3732+	DC	A(T92)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				3745 *****	
				3746 * Register equates	
				3747 *****	
		00000000	00000001	3749 R0	EQU 0
		00000001	00000001	3750 R1	EQU 1
		00000002	00000001	3751 R2	EQU 2
		00000003	00000001	3752 R3	EQU 3
		00000004	00000001	3753 R4	EQU 4
		00000005	00000001	3754 R5	EQU 5
		00000006	00000001	3755 R6	EQU 6
		00000007	00000001	3756 R7	EQU 7
		00000008	00000001	3757 R8	EQU 8
		00000009	00000001	3758 R9	EQU 9
		0000000A	00000001	3759 R10	EQU 10
		0000000B	00000001	3760 R11	EQU 11
		0000000C	00000001	3761 R12	EQU 12
		0000000D	00000001	3762 R13	EQU 13
		0000000E	00000001	3763 R14	EQU 14
		0000000F	00000001	3764 R15	EQU 15
				3766 *****	
				3767 * Register equates	
				3768 *****	
		00000000	00000001	3770 V0	EQU 0
		00000001	00000001	3771 V1	EQU 1
		00000002	00000001	3772 V2	EQU 2
		00000003	00000001	3773 V3	EQU 3
		00000004	00000001	3774 V4	EQU 4
		00000005	00000001	3775 V5	EQU 5
		00000006	00000001	3776 V6	EQU 6
		00000007	00000001	3777 V7	EQU 7
		00000008	00000001	3778 V8	EQU 8
		00000009	00000001	3779 V9	EQU 9
		0000000A	00000001	3780 V10	EQU 10
		0000000B	00000001	3781 V11	EQU 11
		0000000C	00000001	3782 V12	EQU 12
		0000000D	00000001	3783 V13	EQU 13
		0000000E	00000001	3784 V14	EQU 14
		0000000F	00000001	3785 V15	EQU 15
		00000010	00000001	3786 V16	EQU 16
		00000011	00000001	3787 V17	EQU 17
		00000012	00000001	3788 V18	EQU 18
		00000013	00000001	3789 V19	EQU 19
		00000014	00000001	3790 V20	EQU 20
		00000015	00000001	3791 V21	EQU 21

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES												
PRTLNG	U	00000059	1	472	318												
PRTM5	C	0000105E	2	470	316												
PRTNAME	C	00001033	8	462	295												
PRTNUM	C	00001018	3	460	293												
R0	U	00000000	1	3749	112	163	166	186	188	189	190	195	212	216	217	277	318
					326	327	353	355	371	374	376	378	380	395	707	736	765
					794	823	852	881	910	939	968	997	1032	1061	1090	1119	1148
					1177	1256	1285	1315	1344	1374	1403	1432	1461	1491	1520	1549	1578
					1608	1637	1667	1696	1726	1756	1786	1815	1845	1874	1903	1932	1966
					1995	2024	2053	2083	2112	2142	2171	2205	2235	2265	2294	2324	2353
					2383	2412	2447	2476	2505	2534	2565	2594	2623	2652	2683	2712	2741
					2770	2801	2830	2859	2888	2923	2952	2981	3010	3039	3068	3097	3126
					3157	3186	3217	3246	3277	3306	3336	3365	3398	3429	3461	3493	3527
					3558	3590	3622										
R1	U	00000001	1	3750	196	223	224	225	228	229	241	242	243	248	249	250	251
					278	319	336	337	385	399							
R10	U	0000000A	1	3759	151	160	161										
R11	U	0000000B	1	3760	220	221	709	738	767	796	825	854	883	912	941	970	999
					1034	1063	1092	1121	1150	1179	1258	1287	1317	1346	1376	1405	1434
					1463	1493	1522	1551	1580	1610	1639	1669	1698	1728	1758	1788	1817
					1847	1876	1905	1934	1968	1997	2026	2055	2085	2114	2144	2173	2207
					2237	2267	2296	2326	2355	2385	2414	2449	2478	2507	2536	2567	2596
					2625	2654	2685	2714	2743	2772	2803	2832	2861	2890	2925	2954	2983
					3012	3041	3070	3099	3128	3159	3188	3219	3248	3279	3308	3338	3367
					3400	3431	3463	3495	3529	3560	3592	3624					
R12	U	0000000C	1	3761	205	208	232	329									
R13	U	0000000D	1	3762													
R14	U	0000000E	1	3763													
R15	U	0000000F	1	3764	279	320	348	358	359								
R2	U	00000002	1	3751	197	255	256	263	264	265	270	271	272	289	290	297	298
					299	304	305	306	311	312	313	353	354	355	372	374	380
					381	382	384	390	395	396	703	704	707	708	732	733	736
					737	761	762	765	766	790	791	794	795	819	820	823	824
					848	849	852	853	877	878	881	882	906	907	910	911	935
					936	939	940	964	965	968	969	993	994	997	998	1028	1029
					1032	1033	1057	1058	1061	1062	1086	1087	1090	1091	1115	1116	1119
					1120	1144	1145	1148	1149	1173	1174	1177	1178	1252	1253	1256	1257
					1281	1282	1285	1286	1311	1312	1315	1316	1340	1341	1344	1345	1370
					1371	1374	1375	1399	1400	1403	1404	1428	1429	1432	1433	1457	1458
					1461	1462	1487	1488	1491	1492	1516	1517	1520	1521	1545	1546	1549
					1550	1574	1575	1578	1579	1604	1605	1608	1609	1633	1634	1637	1638
					1663	1664	1667	1668	1692	1693	1696	1697	1722	1723	1726	1727	1752
					1753	1756	1757	1782	1783	1786	1787	1811	1812	1815	1816	1841	1842
					1845	1846	1870	1871	1874	1875	1899	1900	1903	1904	1928	1929	1932
					1933	1962	1963	1966	1967	1991	1992	1995	1996	2020	2021	2024	2025
					2049	2050	2053	2054	2079	2080	2083	2084	2108	2109	2112	2113	2138
					2139	2142	2143	2167	2168	2171	2172	2201	2202	2205	2206	2231	2232
					2235	2236	2261	2262	2265	2266	2290	2291	2294	2295	2320	2321	2324
					2325	2349	2350	2353	2354	2379	2380	2383	2384	2408	2409	2412	2413
					2443	2444	2447	2448	2472	2473	2476	2477	2501	2502	2505	2506	2530
					2531	2534	2535	2561	2562	2565	2566	2590	2591	2594	2595	2619	2620
					2623	2624	2648	2649	2652	2653	2679	2680	2683	2684	2708	2709	2712
					2713	2737	2738	2741	2742	2766	2767	2770	2771	2797	2798	2801	2802
					2826	2827	2830	2831	2855	2856	2859	2860	2884	2885	2888	2889	2919
					2920	2923	2924	2948	2949	2952	2953	2977	2978	2981	2982	3006	3007
					3010	3011	3035	3036	3039	3040	3064	3065	3068	3069	3093	3094	3097

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE35	F	00001F84	4	1759	1746 1749
RE36	F	00001FEC	4	1789	1776 1779
RE37	F	00002054	4	1818	1805 1808
RE38	F	000020BC	4	1848	1835 1838
RE39	F	00002124	4	1877	1864 1867
RE4	F	000012EC	4	797	784 787
RE40	F	0000218C	4	1906	1893 1896
RE41	F	000021F4	4	1935	1922 1925
RE42	F	0000225C	4	1969	1956 1959
RE43	F	000022C4	4	1998	1985 1988
RE44	F	0000232C	4	2027	2014 2017
RE45	F	00002394	4	2056	2043 2046
RE46	F	000023FC	4	2086	2073 2076
RE47	F	00002464	4	2115	2102 2105
RE48	F	000024CC	4	2145	2132 2135
RE49	F	00002534	4	2174	2161 2164
RE5	F	00001354	4	826	813 816
RE50	F	0000259C	4	2208	2195 2198
RE51	F	00002604	4	2238	2225 2228
RE52	F	0000266C	4	2268	2255 2258
RE53	F	000026D4	4	2297	2284 2287
RE54	F	0000273C	4	2327	2314 2317
RE55	F	000027A4	4	2356	2343 2346
RE56	F	0000280C	4	2386	2373 2376
RE57	F	00002874	4	2415	2402 2405
RE58	F	000028DC	4	2450	2437 2440
RE59	F	00002944	4	2479	2466 2469
RE6	F	000013BC	4	855	842 845
RE60	F	000029AC	4	2508	2495 2498
RE61	F	00002A14	4	2537	2524 2527
RE62	F	00002A7C	4	2568	2555 2558
RE63	F	00002AE4	4	2597	2584 2587
RE64	F	00002B4C	4	2626	2613 2616
RE65	F	00002BB4	4	2655	2642 2645
RE66	F	00002C1C	4	2686	2673 2676
RE67	F	00002C84	4	2715	2702 2705
RE68	F	00002CEC	4	2744	2731 2734
RE69	F	00002D54	4	2773	2760 2763
RE7	F	00001424	4	884	871 874
RE70	F	00002DBC	4	2804	2791 2794
RE71	F	00002E24	4	2833	2820 2823
RE72	F	00002E8C	4	2862	2849 2852
RE73	F	00002EF4	4	2891	2878 2881
RE74	F	00002F5C	4	2926	2913 2916
RE75	F	00002FC4	4	2955	2942 2945
RE76	F	0000302C	4	2984	2971 2974
RE77	F	00003094	4	3013	3000 3003
RE78	F	000030FC	4	3042	3029 3032
RE79	F	00003164	4	3071	3058 3061
RE8	F	0000148C	4	913	900 903
RE80	F	000031CC	4	3100	3087 3090
RE81	F	00003234	4	3129	3116 3119
RE82	F	0000329C	4	3160	3147 3150
RE83	F	00003304	4	3189	3176 3179
RE84	F	0000336C	4	3220	3207 3210
RE85	F	000033D4	4	3249	3236 3239

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
RE86	F	0000343C	4	3280	3267	3270
RE87	F	000034A4	4	3309	3296	3299
RE88	F	0000350C	4	3339	3326	3329
RE89	F	00003574	4	3368	3355	3358
RE9	F	000014F4	4	942	929	932
RE90	F	000035DC	4	3401	3388	3391
RE91	F	00003644	4	3432	3419	3422
RE92	F	000036AC	4	3464	3451	3454
RE93	F	00003714	4	3496	3483	3486
RE94	F	0000377C	4	3530	3517	3520
RE95	F	000037E4	4	3561	3548	3551
RE96	F	0000384C	4	3593	3580	3583
RE97	F	000038B4	4	3625	3612	3615
REA1	A	0000118C	4	700		
REA10	A	00001534	4	961		
REA11	A	0000159C	4	990		
REA12	A	00001604	4	1025		
REA13	A	0000166C	4	1054		
REA14	A	000016D4	4	1083		
REA15	A	0000173C	4	1112		
REA16	A	000017A4	4	1141		
REA17	A	0000180C	4	1170		
REA18	A	00001874	4	1249		
REA19	A	000018DC	4	1278		
REA2	A	000011F4	4	729		
REA20	A	00001944	4	1308		
REA21	A	000019AC	4	1337		
REA22	A	00001A14	4	1367		
REA23	A	00001A7C	4	1396		
REA24	A	00001AE4	4	1425		
REA25	A	00001B4C	4	1454		
REA26	A	00001BB4	4	1484		
REA27	A	00001C1C	4	1513		
REA28	A	00001C84	4	1542		
REA29	A	00001CEC	4	1571		
REA3	A	0000125C	4	758		
REA30	A	00001D54	4	1601		
REA31	A	00001DBC	4	1630		
REA32	A	00001E24	4	1660		
REA33	A	00001E8C	4	1689		
REA34	A	00001EF4	4	1719		
REA35	A	00001F5C	4	1749		
REA36	A	00001FC4	4	1779		
REA37	A	0000202C	4	1808		
REA38	A	00002094	4	1838		
REA39	A	000020FC	4	1867		
REA4	A	000012C4	4	787		
REA40	A	00002164	4	1896		
REA41	A	000021CC	4	1925		
REA42	A	00002234	4	1959		
REA43	A	0000229C	4	1988		
REA44	A	00002304	4	2017		
REA45	A	0000236C	4	2046		
REA46	A	000023D4	4	2076		
REA47	A	0000243C	4	2105		
REA48	A	000024A4	4	2135		

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA49	A	0000250C	4	2164	
REA5	A	0000132C	4	816	
REA50	A	00002574	4	2198	
REA51	A	000025DC	4	2228	
REA52	A	00002644	4	2258	
REA53	A	000026AC	4	2287	
REA54	A	00002714	4	2317	
REA55	A	0000277C	4	2346	
REA56	A	000027E4	4	2376	
REA57	A	0000284C	4	2405	
REA58	A	000028B4	4	2440	
REA59	A	0000291C	4	2469	
REA6	A	00001394	4	845	
REA60	A	00002984	4	2498	
REA61	A	000029EC	4	2527	
REA62	A	00002A54	4	2558	
REA63	A	00002ABC	4	2587	
REA64	A	00002B24	4	2616	
REA65	A	00002B8C	4	2645	
REA66	A	00002BF4	4	2676	
REA67	A	00002C5C	4	2705	
REA68	A	00002CC4	4	2734	
REA69	A	00002D2C	4	2763	
REA7	A	000013FC	4	874	
REA70	A	00002D94	4	2794	
REA71	A	00002DFC	4	2823	
REA72	A	00002E64	4	2852	
REA73	A	00002ECC	4	2881	
REA74	A	00002F34	4	2916	
REA75	A	00002F9C	4	2945	
REA76	A	00003004	4	2974	
REA77	A	0000306C	4	3003	
REA78	A	000030D4	4	3032	
REA79	A	0000313C	4	3061	
REA8	A	00001464	4	903	
REA80	A	000031A4	4	3090	
REA81	A	0000320C	4	3119	
REA82	A	00003274	4	3150	
REA83	A	000032DC	4	3179	
REA84	A	00003344	4	3210	
REA85	A	000033AC	4	3239	
REA86	A	00003414	4	3270	
REA87	A	0000347C	4	3299	
REA88	A	000034E4	4	3329	
REA89	A	0000354C	4	3358	
REA9	A	000014CC	4	932	
REA90	A	000035B4	4	3391	
REA91	A	0000361C	4	3422	
REA92	A	00003684	4	3454	
REA93	A	000036EC	4	3486	
REA94	A	00003754	4	3520	
REA95	A	000037BC	4	3551	
REA96	A	00003824	4	3583	
REA97	A	0000388C	4	3615	
READDR	A	0000001C	4	539	228
REG2LOW	U	000000DD	1	440	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
REG2PATT	U	AABBCCDD	1	439		
RELEN	A	00000018	4	538		
RPTDWSAV	D	00000488	8	364	353	355
RPTERROR	I	0000045C	4	348	279	320
RPTSAVE	F	0000047C	4	361	348	358
RPTSVR5	F	00000480	4	362	349	357
SKL0001	U	00000054	1	179	195	
SKT0001	C	0000022A	26	176	179	196
SVOLDPSW	U	00000140	0	114		
T1	A	00001170	4	689	3641	
T10	A	00001518	4	950	3650	
T11	A	00001580	4	979	3651	
T12	A	000015E8	4	1014	3652	
T13	A	00001650	4	1043	3653	
T14	A	000016B8	4	1072	3654	
T15	A	00001720	4	1101	3655	
T16	A	00001788	4	1130	3656	
T17	A	000017F0	4	1159	3657	
T18	A	00001858	4	1238	3658	
T19	A	000018C0	4	1267	3659	
T2	A	000011D8	4	718	3642	
T20	A	00001928	4	1297	3660	
T21	A	00001990	4	1326	3661	
T22	A	000019F8	4	1356	3662	
T23	A	00001A60	4	1385	3663	
T24	A	00001AC8	4	1414	3664	
T25	A	00001B30	4	1443	3665	
T26	A	00001B98	4	1473	3666	
T27	A	00001C00	4	1502	3667	
T28	A	00001C68	4	1531	3668	
T29	A	00001CD0	4	1560	3669	
T3	A	00001240	4	747	3643	
T30	A	00001D38	4	1590	3670	
T31	A	00001DA0	4	1619	3671	
T32	A	00001E08	4	1649	3672	
T33	A	00001E70	4	1678	3673	
T34	A	00001ED8	4	1708	3674	
T35	A	00001F40	4	1738	3675	
T36	A	00001FA8	4	1768	3676	
T37	A	00002010	4	1797	3677	
T38	A	00002078	4	1827	3678	
T39	A	000020E0	4	1856	3679	
T4	A	000012A8	4	776	3644	
T40	A	00002148	4	1885	3680	
T41	A	000021B0	4	1914	3681	
T42	A	00002218	4	1948	3682	
T43	A	00002280	4	1977	3683	
T44	A	000022E8	4	2006	3684	
T45	A	00002350	4	2035	3685	
T46	A	000023B8	4	2065	3686	
T47	A	00002420	4	2094	3687	
T48	A	00002488	4	2124	3688	
T49	A	000024F0	4	2153	3689	
T5	A	00001310	4	805	3645	
T50	A	00002558	4	2187	3690	
T51	A	000025C0	4	2217	3691	

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SYMBOL		TYPE	VALUE	LENGTH	DEFN	REFERENCES			
T52		A	00002628	4	2247	3692			
T53		A	00002690	4	2276	3693			
T54		A	000026F8	4	2306	3694			
T55		A	00002760	4	2335	3695			
T56		A	000027C8	4	2365	3696			
T57		A	00002830	4	2394	3697			
T58		A	00002898	4	2429	3698			
T59		A	00002900	4	2458	3699			
T6		A	00001378	4	834	3646			
T60		A	00002968	4	2487	3700			
T61		A	000029D0	4	2516	3701			
T62		A	00002A38	4	2547	3702			
T63		A	00002AA0	4	2576	3703			
T64		A	00002B08	4	2605	3704			
T65		A	00002B70	4	2634	3705			
T66		A	00002BD8	4	2665	3706			
T67		A	00002C40	4	2694	3707			
T68		A	00002CA8	4	2723	3708			
T69		A	00002D10	4	2752	3709			
T7		A	000013E0	4	863	3647			
T70		A	00002D78	4	2783	3710			
T71		A	00002DE0	4	2812	3711			
T72		A	00002E48	4	2841	3712			
T73		A	00002EB0	4	2870	3713			
T74		A	00002F18	4	2905	3714			
T75		A	00002F80	4	2934	3715			
T76		A	00002FE8	4	2963	3716			
T77		A	00003050	4	2992	3717			
T78		A	000030B8	4	3021	3718			
T79		A	00003120	4	3050	3719			
T8		A	00001448	4	892	3648			
T80		A	00003188	4	3079	3720			
T81		A	000031F0	4	3108	3721			
T82		A	00003258	4	3139	3722			
T83		A	000032C0	4	3168	3723			
T84		A	00003328	4	3199	3724			
T85		A	00003390	4	3228	3725			
T86		A	000033F8	4	3259	3726			
T87		A	00003460	4	3288	3727			
T88		A	000034C8	4	3318	3728			
T89		A	00003530	4	3347	3729			
T9		A	000014B0	4	921	3649			
T90		A	00003598	4	3380	3730			
T91		A	00003600	4	3411	3731			
T92		A	00003668	4	3443	3732			
T93		A	000036D0	4	3475	3733			
T94		A	00003738	4	3509	3734			
T95		A	000037A0	4	3540	3735			
T96		A	00003808	4	3572	3736			
T97		A	00003870	4	3604	3737			
TESTCC		I	00000324	4	235	225			
TESTING		F	00001004	4	451	217			
TESTREST		U	0000030C	1	227	244			
TNUM		H	00000004	2	526	255	289		
TSUB		A	00000000	4	525	220			
TTABLE		F	000038DC	4	3640				

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES												
V0	U	00000000	1	3770													
V1	U	00000001	1	3771	219	705	706	734	735	763	764	792	793	821	822	850	851
					879	880	908	909	937	938	966	967	995	996	1030	1031	1059
					1060	1088	1089	1117	1118	1146	1147	1175	1176	1254	1255	1283	1284
					1313	1314	1342	1343	1372	1373	1401	1402	1430	1431	1459	1460	1489
					1490	1518	1519	1547	1548	1576	1577	1606	1607	1635	1636	1665	1666
					1694	1695	1724	1725	1754	1755	1784	1785	1813	1814	1843	1844	1872
					1873	1901	1902	1930	1931	1964	1965	1993	1994	2022	2023	2051	2052
					2081	2082	2110	2111	2140	2141	2169	2170	2203	2204	2233	2234	2263
					2264	2292	2293	2322	2323	2351	2352	2381	2382	2410	2411	2445	2446
					2474	2475	2503	2504	2532	2533	2563	2564	2592	2593	2621	2622	2650
					2651	2681	2682	2710	2711	2739	2740	2768	2769	2799	2800	2828	2829
					2857	2858	2886	2887	2921	2922	2950	2951	2979	2980	3008	3009	3037
					3038	3066	3067	3095	3096	3124	3125	3155	3156	3184	3185	3215	3216
					3244	3245	3275	3276	3304	3305	3334	3335	3363	3364	3396	3397	3427
					3428	3459	3460	3491	3492	3525	3526	3556	3557	3588	3589	3620	3621
V10	U	0000000A	1	3780													
V11	U	0000000B	1	3781													
V12	U	0000000C	1	3782													
V13	U	0000000D	1	3783													
V14	U	0000000E	1	3784													
V15	U	0000000F	1	3785													
V16	U	00000010	1	3786													
V17	U	00000011	1	3787													
V18	U	00000012	1	3788													
V19	U	00000013	1	3789													
V1FUDGE	X	00001130	16	514	219												
V1INPUT	C	00001140	16	515													
V1OUTPUT	X	00001110	16	512	229	706	735	764	793	822	851	880	909	938	967	996	1031
					1060	1089	1118	1147	1176	1255	1284	1314	1343	1373	1402	1431	1460
					1490	1519	1548	1577	1607	1636	1666	1695	1725	1755	1785	1814	1844
					1873	1902	1931	1965	1994	2023	2052	2082	2111	2141	2170	2204	2234
					2264	2293	2323	2352	2382	2411	2446	2475	2504	2533	2564	2593	2622
					2651	2682	2711	2740	2769	2800	2829	2858	2887	2922	2951	2980	3009
					3038	3067	3096	3125	3156	3185	3216	3245	3276	3305	3335	3364	3397
					3428	3460	3492	3526	3557	3589	3621						
V2	U	00000002	1	3772	704	705	733	734	762	763	791	792	820	821	849	850	878
					879	907	908	936	937	965	966	994	995	1029	1030	1058	1059
					1087	1088	1116	1117	1145	1146	1174	1175	1253	1254	1282	1283	1312
					1313	1341	1342	1371	1372	1400	1401	1429	1430	1458	1459	1488	1489
					1517	1518	1546	1547	1575	1576	1605	1606	1634	1635	1664	1665	1693
					1694	1723	1724	1753	1754	1783	1784	1812	1813	1842	1843	1871	1872
					1900	1901	1929	1930	1963	1964	1992	1993	2021	2022	2050	2051	2080
					2081	2109	2110	2139	2140	2168	2169	2202	2203	2232	2233	2262	2263
					2291	2292	2321	2322	2350	2351	2380	2381	2409	2410	2444	2445	2473
					2474	2502	2503	2531	2532	2562	2563	2591	2592	2620	2621	2649	2650
					2680	2681	2709	2710	2738	2739	2767	2768	2798	2799	2827	2828	2856
					2857	2885	2886	2920	2921	2949	2950	2978	2979	3007	3008	3036	3037
					3065	3066	3094	3095	3123	3124	3154	3155	3183	3184	3214	3215	3243
					3244	3274	3275	3303	3304	3333	3334	3362	3363	3395	3396	3426	3427
					3458	3459	3490	3491	3524	3525	3555	3556	3587	3588	3619	3620	
V20	U	00000014	1	3790													
V21	U	00000015	1	3791													
V22	U	00000016	1	3792													
V23	U	00000017	1	3793													
V24	U	00000018	1	3794													

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V25	U	00000019	1	3795	
V26	U	0000001A	1	3796	
V27	U	0000001B	1	3797	
V28	U	0000001C	1	3798	
V29	U	0000001D	1	3799	
V2VALUE	A	0000000C	4	534	
V2_1	A	0000117C	4	697	703
V2_10	A	00001524	4	958	964
V2_11	A	0000158C	4	987	993
V2_12	A	000015F4	4	1022	1028
V2_13	A	0000165C	4	1051	1057
V2_14	A	000016C4	4	1080	1086
V2_15	A	0000172C	4	1109	1115
V2_16	A	00001794	4	1138	1144
V2_17	A	000017FC	4	1167	1173
V2_18	A	00001864	4	1246	1252
V2_19	A	000018CC	4	1275	1281
V2_2	A	000011E4	4	726	732
V2_20	A	00001934	4	1305	1311
V2_21	A	0000199C	4	1334	1340
V2_22	A	00001A04	4	1364	1370
V2_23	A	00001A6C	4	1393	1399
V2_24	A	00001AD4	4	1422	1428
V2_25	A	00001B3C	4	1451	1457
V2_26	A	00001BA4	4	1481	1487
V2_27	A	00001C0C	4	1510	1516
V2_28	A	00001C74	4	1539	1545
V2_29	A	00001CDC	4	1568	1574
V2_3	A	0000124C	4	755	761
V2_30	A	00001D44	4	1598	1604
V2_31	A	00001DAC	4	1627	1633
V2_32	A	00001E14	4	1657	1663
V2_33	A	00001E7C	4	1686	1692
V2_34	A	00001EE4	4	1716	1722
V2_35	A	00001F4C	4	1746	1752
V2_36	A	00001FB4	4	1776	1782
V2_37	A	0000201C	4	1805	1811
V2_38	A	00002084	4	1835	1841
V2_39	A	000020EC	4	1864	1870
V2_4	A	000012B4	4	784	790
V2_40	A	00002154	4	1893	1899
V2_41	A	000021BC	4	1922	1928
V2_42	A	00002224	4	1956	1962
V2_43	A	0000228C	4	1985	1991
V2_44	A	000022F4	4	2014	2020
V2_45	A	0000235C	4	2043	2049
V2_46	A	000023C4	4	2073	2079
V2_47	A	0000242C	4	2102	2108
V2_48	A	00002494	4	2132	2138
V2_49	A	000024FC	4	2161	2167
V2_5	A	0000131C	4	813	819
V2_50	A	00002564	4	2195	2201
V2_51	A	000025CC	4	2225	2231
V2_52	A	00002634	4	2255	2261
V2_53	A	0000269C	4	2284	2290
V2_54	A	00002704	4	2314	2320

ASMA Ver. 0.7.0		zvector- e6- 16- VSRP- VPSOP (Zvector E6 VRI- g)				18 Jun 2024 18:58:28		Page	90
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES				
V2_55	A	0000276C	4	2343	2349				
V2_56	A	000027D4	4	2373	2379				
V2_57	A	0000283C	4	2402	2408				
V2_58	A	000028A4	4	2437	2443				
V2_59	A	0000290C	4	2466	2472				
V2_6	A	00001384	4	842	848				
V2_60	A	00002974	4	2495	2501				
V2_61	A	000029DC	4	2524	2530				
V2_62	A	00002A44	4	2555	2561				
V2_63	A	00002AAC	4	2584	2590				
V2_64	A	00002B14	4	2613	2619				
V2_65	A	00002B7C	4	2642	2648				
V2_66	A	00002BE4	4	2673	2679				
V2_67	A	00002C4C	4	2702	2708				
V2_68	A	00002CB4	4	2731	2737				
V2_69	A	00002D1C	4	2760	2766				
V2_7	A	000013EC	4	871	877				
V2_70	A	00002D84	4	2791	2797				
V2_71	A	00002DEC	4	2820	2826				
V2_72	A	00002E54	4	2849	2855				
V2_73	A	00002EBC	4	2878	2884				
V2_74	A	00002F24	4	2913	2919				
V2_75	A	00002F8C	4	2942	2948				
V2_76	A	00002FF4	4	2971	2977				
V2_77	A	0000305C	4	3000	3006				
V2_78	A	000030C4	4	3029	3035				
V2_79	A	0000312C	4	3058	3064				
V2_8	A	00001454	4	900	906				
V2_80	A	00003194	4	3087	3093				
V2_81	A	000031FC	4	3116	3122				
V2_82	A	00003264	4	3147	3153				
V2_83	A	000032CC	4	3176	3182				
V2_84	A	00003334	4	3207	3213				
V2_85	A	0000339C	4	3236	3242				
V2_86	A	00003404	4	3267	3273				
V2_87	A	0000346C	4	3296	3302				
V2_88	A	000034D4	4	3326	3332				
V2_89	A	0000353C	4	3355	3361				
V2_9	A	000014BC	4	929	935				
V2_90	A	000035A4	4	3388	3394				
V2_91	A	0000360C	4	3419	3425				
V2_92	A	00003674	4	3451	3457				
V2_93	A	000036DC	4	3483	3489				
V2_94	A	00003744	4	3517	3523				
V2_95	A	000037AC	4	3548	3554				
V2_96	A	00003814	4	3580	3586				
V2_97	A	0000387C	4	3612	3618				
V3	U	00000003	1	3773					
V30	U	0000001E	1	3800					
V31	U	0000001F	1	3801					
V4	U	00000004	1	3774					
V5	U	00000005	1	3775					
V6	U	00000006	1	3776					
V7	U	00000007	1	3777					
V8	U	00000008	1	3778					
V9	U	00000009	1	3779					

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X0001	U	000002B0	1	185	173 186
X1	F	00001190	4	702	689
X10	F	00001538	4	963	950
X11	F	000015A0	4	992	979
X12	F	00001608	4	1027	1014
X13	F	00001670	4	1056	1043
X14	F	000016D8	4	1085	1072
X15	F	00001740	4	1114	1101
X16	F	000017A8	4	1143	1130
X17	F	00001810	4	1172	1159
X18	F	00001878	4	1251	1238
X19	F	000018E0	4	1280	1267
X2	F	000011F8	4	731	718
X20	F	00001948	4	1310	1297
X21	F	000019B0	4	1339	1326
X22	F	00001A18	4	1369	1356
X23	F	00001A80	4	1398	1385
X24	F	00001AE8	4	1427	1414
X25	F	00001B50	4	1456	1443
X26	F	00001BB8	4	1486	1473
X27	F	00001C20	4	1515	1502
X28	F	00001C88	4	1544	1531
X29	F	00001CF0	4	1573	1560
X3	F	00001260	4	760	747
X30	F	00001D58	4	1603	1590
X31	F	00001DC0	4	1632	1619
X32	F	00001E28	4	1662	1649
X33	F	00001E90	4	1691	1678
X34	F	00001EF8	4	1721	1708
X35	F	00001F60	4	1751	1738
X36	F	00001FC8	4	1781	1768
X37	F	00002030	4	1810	1797
X38	F	00002098	4	1840	1827
X39	F	00002100	4	1869	1856
X4	F	000012C8	4	789	776
X40	F	00002168	4	1898	1885
X41	F	000021D0	4	1927	1914
X42	F	00002238	4	1961	1948
X43	F	000022A0	4	1990	1977
X44	F	00002308	4	2019	2006
X45	F	00002370	4	2048	2035
X46	F	000023D8	4	2078	2065
X47	F	00002440	4	2107	2094
X48	F	000024A8	4	2137	2124
X49	F	00002510	4	2166	2153
X5	F	00001330	4	818	805
X50	F	00002578	4	2200	2187
X51	F	000025E0	4	2230	2217
X52	F	00002648	4	2260	2247
X53	F	000026B0	4	2289	2276
X54	F	00002718	4	2319	2306
X55	F	00002780	4	2348	2335
X56	F	000027E8	4	2378	2365
X57	F	00002850	4	2407	2394
X58	F	000028B8	4	2442	2429
X59	F	00002920	4	2471	2458

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES					
X6	F	00001398	4	847	834					
X60	F	00002988	4	2500	2487					
X61	F	000029F0	4	2529	2516					
X62	F	00002A58	4	2560	2547					
X63	F	00002AC0	4	2589	2576					
X64	F	00002B28	4	2618	2605					
X65	F	00002B90	4	2647	2634					
X66	F	00002BF8	4	2678	2665					
X67	F	00002C60	4	2707	2694					
X68	F	00002CC8	4	2736	2723					
X69	F	00002D30	4	2765	2752					
X7	F	00001400	4	876	863					
X70	F	00002D98	4	2796	2783					
X71	F	00002E00	4	2825	2812					
X72	F	00002E68	4	2854	2841					
X73	F	00002ED0	4	2883	2870					
X74	F	00002F38	4	2918	2905					
X75	F	00002FA0	4	2947	2934					
X76	F	00003008	4	2976	2963					
X77	F	00003070	4	3005	2992					
X78	F	000030D8	4	3034	3021					
X79	F	00003140	4	3063	3050					
X8	F	00001468	4	905	892					
X80	F	000031A8	4	3092	3079					
X81	F	00003210	4	3121	3108					
X82	F	00003278	4	3152	3139					
X83	F	000032E0	4	3181	3168					
X84	F	00003348	4	3212	3199					
X85	F	000033B0	4	3241	3228					
X86	F	00003418	4	3272	3259					
X87	F	00003480	4	3301	3288					
X88	F	000034E8	4	3331	3318					
X89	F	00003550	4	3360	3347					
X9	F	000014D0	4	934	921					
X90	F	000035B8	4	3393	3380					
X91	F	00003620	4	3424	3411					
X92	F	00003688	4	3456	3443					
X93	F	000036F0	4	3488	3475					
X94	F	00003758	4	3522	3509					
X95	F	000037C0	4	3553	3540					
X96	F	00003828	4	3585	3572					
X97	F	00003890	4	3617	3604					
XC0001	U	000002D8	1	199	191					
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=A(E6TESTS)	A	00000588	4	426	205					
=AL2(L' MSGMSG)	R	00000596	2	430	376					
=F' 1'	F	0000058C	4	427	243	326				
=F' 2'	F	00000584	4	425	190					
=H' 0'	H	00000594	2	429	371					
=XL4' 3'	X	00000590	4	428	250					

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	14960	0000- 3A6F	0000- 3A6F
Regi on		14960	0000- 3A6F	0000- 3A6F
CSECT	ZVE6TST	14960	0000- 3A6F	0000- 3A6F

STMT

FILE NAME

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1 /home/tn529/sharedvfp/tests/zvector-e6-16-VSRP-VPS0P.asm
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**** NO ERRORS FOUND ****